

# **Agilent N5416A USB 2.0 Compliance Test Option**

## **Notes on Electrical Testing**



**Agilent Technologies**

# Notices

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## USB Automated Testing—At A Glance

The Agilent N5416A USB 2.0 compliance test option helps you verify USB compliance to specifications using the Agilent 5485xA Series or DSO80000 Series Infiniium digital storage oscilloscope.

The USB 2.0 compliance test option runs under an automated test engine that.

- Lets you select individual or multiple tests to run.
- Lets you identify the device being tested and its configuration.
- Shows you how to make oscilloscope connections to the device under test.
- Automatically checks for proper oscilloscope configuration.
- Automatically sets up the oscilloscope for each test.
- Provides detailed information for each test that has been run and lets you specify the thresholds at which marginal or critical warnings appear.
- Creates a printable HTML report of the tests that have been run.

## In This Book

This manual contains notes on the electrical tests that are performed by the USB 2.0 compliance test option; it describes the equipment used, and it describes how the tests are performed.

- [Chapter 1](#), “Installing the USB 2.0 Compliance Test Option” shows how to install and license the automated test application software (if it was purchased separately).
- [Chapter 2](#), “Preparing to Take Measurements” describes the equipment required, how to set up the equipment, how to start the USB 2.0 Compliance Test Option, and how to run tests.
- [Chapter 3](#), “Device Hi-Speed Tests” describes the equipment used for each test setup.
- [Chapter 4](#), “Hub Hi-Speed Tests” describes the equipment used for each test setup.
- [Chapter 5](#), “Host Hi-Speed Electrical Tests” describes the equipment used for each test setup.
- [Chapter 6](#), “Troubleshooting Hi-Speed Test Failures” describes the Debug Mode options that can be used when troubleshooting hi-speed test failures.
- [Chapter 7](#), “Low and Full Speed Tests” describes the equipment used for each test setup.
- [Chapter 8](#), “On-The-Go Electrical Tests” describes the equipment used for the test setup.

### See Also

- The USB 2.0 Compliance Test Option’s online help, which describes:
  - Creating or opening a test project.
  - Selecting tests.
  - Configuring selected tests.
  - Connecting the oscilloscope to the DUT.
  - Running tests.
  - Viewing test results.
  - Viewing/printing the HTML test report.
  - Saving test projects.
- The USB 2.0 developers documents at the USB Implementers Forum web site, <http://www.usb.org/developers/docs>. This web page has test procedure documents for the E2683A USB 2.0 Compliance Test Option, which contain test records used for compliance test submission.

# Contents

USB Automated Testing—At A Glance 3

In This Book 4

## 1 Installing the USB 2.0 Compliance Test Option

Installing the Software 13

Installing the License Key 14

## 2 Preparing to Take Measurements

Required Equipment and Software 16

Setting Up the Equipment 19

Infiniium 5485xA Series or DS080000 Series Digital Sampling Oscilloscope 19

81130A Digital Signal Generator 20

Starting the USB 2.0 Compliance Test Option 21

Online Help Topics 22

Running Tests 23

## 3 Device Hi-Speed Tests

Device Hi-Speed Signal Quality Test 27

Equipment Used 27

Selecting the Tests 27

Configuring the Tests 28

Connecting the Equipment 28

Running the Tests 29

Test Instructions, Part 1 29

Test Instructions, Part 2 29

Viewing Test Results 31

Device Packet Parameters	32
Equipment Used	32
Selecting the Tests	32
Configuring the Tests	33
Connecting the Equipment	33
Running the Tests	34
Test Instructions, Part 1	34
Test Instructions, Part 2	35
Viewing Test Results	38
Device CHIRP Timing	39
Equipment Used	39
Selecting the Tests	39
Configuring the Tests	40
Connecting the Equipment	40
Running the Tests	41
Test Instructions	41
Viewing Test Results	41
Device Suspend/Resume/Reset Timing	42
Equipment Used	42
Selecting the Tests	42
Configuring the Tests	43
Connecting the Equipment	43
Running the Tests	44
Test Instructions	44
Viewing Test Results	49
Device Test J/K, SE0_NAK	50
Equipment Used	50
Selecting the Tests	50
Configuring the Tests	51
Connecting the Equipment	51
Running the Tests	52
Test Instructions	52
Viewing Test Results	55

Device Receiver Sensitivity	56
Equipment Used	56
Selecting the Tests	57
Configuring the Tests	57
Connecting the Equipment	58
Running the Tests	59
Test Instructions	59
Viewing Test Results	61

## 4 Hub Hi-Speed Tests

Hub Hi-Speed Signal Quality Test - Upstream Facing Ports	65
Equipment Used	65
Selecting the Tests	65
Configuring the Tests	66
Connecting the Equipment	66
Running the Tests	67
Test Instructions, Part 1	67
Test Instructions, Part 2	68
Viewing Test Results	68
Hub Hi-Speed Signal Quality Test - Downstream Facing Ports	69
Equipment Used	69
Selecting the Tests	69
Configuring the Tests	70
Connecting the Equipment	70
Running the Tests	71
Test Instructions	71
Viewing Test Results	72
Hub Jitter Test - Downstream Facing Ports	73
Equipment Used	73
Selecting the Tests	73
Configuring the Tests	74
Connecting the Equipment	74
Running the Tests	75
Test Instructions	75
Viewing Test Results	76

Hub Disconnect Detect	77
Equipment Used	77
Selecting the Tests	77
Configuring the Tests	78
Connecting the Equipment	78
Running the Tests	79
Test Instructions	79
Viewing Test Results	80
Hub Packet Parameters - Upstream Facing Port	81
Equipment Used	81
Selecting the Tests	81
Configuring the Tests	82
Connecting the Equipment	82
Running the Tests	83
Test Instructions, Part 1	83
Test Instructions, Part 2	84
Viewing Test Results	87
Hub Receiver Sensitivity - Upstream Facing Port	88
Equipment Used	88
Selecting the Tests	89
Configuring the Tests	89
Connecting the Equipment	93
Running the Tests	94
Test Instructions	94
Viewing Test Results	96
Hub Repeater Test - Downstream Facing Port	97
Equipment Used	97
Selecting the Tests	97
Configuring the Tests	98
Connecting the Equipment	98
Running the Tests	99
Test Instructions	99
Viewing Test Results	101



Hub Repeater Test - Upstream Facing Port	102
Equipment Used	102
Selecting the Tests	102
Configuring the Tests	103
Connecting the Equipment	103
Running the Tests	104
Test Instructions, Part 1	104
Test Instructions, Part 2	106
Viewing Test Results	107
Hub CHIRP Timing - Upstream Facing Port	108
Equipment Used	108
Selecting the Tests	108
Configuring the Tests	109
Connecting the Equipment	109
Running the Tests	110
Test Instructions	110
Viewing Test Results	110
Hub Suspend/Resume/Reset Timing - Upstream Facing Port	111
Equipment Used	111
Selecting the Tests	111
Configuring the Tests	112
Connecting the Equipment	112
Running the Tests	113
Test Instructions	113
Viewing Test Results	118
Hub Test J/K, SE0_NAK - Upstream Facing Port	119
Equipment Used	119
Selecting the Tests	119
Configuring the Tests	120
Connecting the Equipment	120
Running the Tests	120
Test Instructions	120
Viewing Test Results	123

Hub Test J/K, SE0_NAK - Downstream Facing Port	124
Equipment Used	124
Selecting the Tests	124
Configuring the Tests	125
Connecting the Equipment	125
Running the Tests	126
Test Instructions	126
Viewing Test Results	129

## 5 Host Hi-Speed Electrical Tests

Host Hi-Speed Signal Quality	133
Equipment Used	133
Selecting the Tests	133
Configuring the Tests	134
Connecting the Equipment	134
Running the Tests	134
Test Instructions, Part 1	134
Test Instructions, Part 2	135
Viewing Test Results	136
Host Controller Packet Parameters	137
Equipment Used	137
Selecting the Tests	137
Configuring the Tests	138
Connecting the Equipment	138
Running the Tests	139
Test Instructions, Part 1	139
Test Instructions, Part 2	140
Viewing Test Results	143
Host Disconnect Detect	144
Equipment Used	144
Selecting the Tests	144
Configuring the Tests	145
Connecting the Equipment	145
Running the Tests	146
Test Instructions	146
Viewing Test Results	147

Host CHIRP Timing	148
Equipment Used	148
Selecting the Tests	148
Configuring the Tests	149
Connecting the Equipment	149
Running the Tests	150
Test Instructions	150
Viewing Test Results	151
Host Suspend/Resume Timing	152
Equipment Used	152
Selecting the Tests	152
Configuring the Tests	153
Connecting the Equipment	153
Running the Tests	154
Test Instructions	154
Viewing Test Results	156
Host Test J/K, SE0_NAK	157
Equipment Used	157
Selecting the Tests	157
Configuring the Tests	158
Connecting the Equipment	158
Running the Tests	158
Test Instructions	158
Viewing Test Results	161

## 6 Troubleshooting Hi-Speed Test Failures

### 7 Low and Full Speed Tests

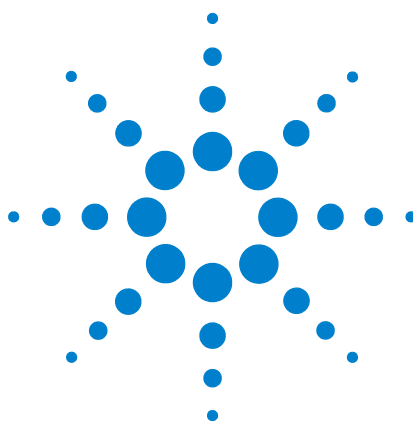
Droop/Drop Test	167
Host and Self-Powered Hubs	167
Bus-Powered Hubs	170
Inrush Current Test	174
Equipment Used	174
Selecting the Tests	174
Configuring the Tests	175
Connecting the Equipment	175
Running the Tests	176
Test Instructions, Part 1	176
Test Instructions, Part 2	176
Viewing Test Results	176

Signal Integrity Test	177
Host Downstream Signal Quality Test	177
Hub Downstream Signal Quality Test	182
Upstream Signal Quality Test	188
Back-Voltage Test	198
Equipment Used	198
Selecting the Tests	198
Configuring the Tests	198
Connecting the Equipment	198
Running the Tests	199
Test Instructions	199
Viewing Test Results	200

## 8 On-The-Go Electrical Tests

Equipment Used	202
Selecting the Tests	202
Configuring the Tests	203
Connecting the Equipment	203
Running the Tests	204
Viewing Test Results	204

## Index



# 1 Installing the USB 2.0 Compliance Test Option

Installing the Software 13

Installing the License Key 14

If you purchased the N5416A USB 2.0 Compliance Test Option separately, you need to install the software and license key.

## Installing the Software

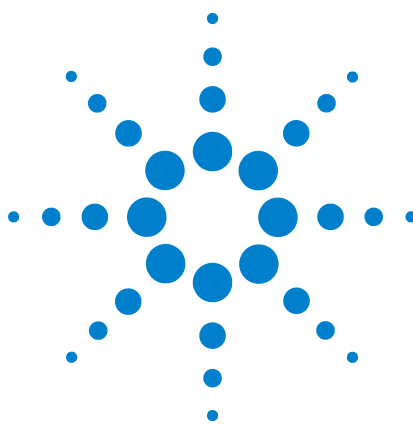
- 1 Make sure you have version A.03.90 or higher of the Infiniium oscilloscope software by choosing **Help>About Infiniium...** from the main menu.
- 2 Download the latest version of the N5416A USB 2.0 Compliance Test Option software to your oscilloscope:
  - a Go to: <http://www.agilent.com/find/scope-apps-sw>
  - b Click the N5416A USB 2.0 Compliance Test Option links.
- 3 Run the setup program, and follow the instructions.

Be sure to accept the installation of the .NET Framework software; it is required in order to run the USB 2.0 Compliance Test Option.



## Installing the License Key

- 1 Request a license code from Agilent by following the instructions on the Entitlement Certificate.  
  
You will need the oscilloscope's "Option ID Number", which you can find in the **Help>About Infiniium...** dialog.
- 2 After you receive your license code from Agilent, choose **Utilities>Install Option License...**
- 3 In the Install Option License dialog, enter your license code and click **Install License**.
- 4 Click **OK** in the dialog that tells you to restart the Infiniium oscilloscope application software to complete the license installation.
- 5 Click **Close** to close the Install Option License dialog.
- 6 Choose **File>Exit**.
- 7 Restart the Infiniium oscilloscope application software to complete the license installation.



## 2 Preparing to Take Measurements

Required Equipment and Software	16
Setting Up the Equipment	19
Starting the USB 2.0 Compliance Test Option	21
Running Tests	23

After you gather and set up the required equipment and software, you can start the USB 2.0 Compliance Test Option and begin performing the electrical compliance tests.



## Required Equipment and Software

**Table 1** Digital Storage Oscilloscope, Software, and Accessories

Equipment Required	Host Hi-Speed	Hub Hi-Speed	Device Hi-Speed	Low/Full Speed
Agilent 5485xA Series or DS080000 Series Infiniium oscilloscope.	1*,**	1*,**	1*,**	1***
Agilent N5416A USB Compliance Test Option.	1	1	1	1
Computer monitor (optional).	optional	optional	optional	optional
Agilent 1131A, 1133A, or 1134A InfiniiMax differential probe.	1	2	1	n/a
Agilent E2669A differential connectivity kit, OR E2678A socketed head.	1	2	1	n/a
Agilent header adapter (P/N 01131-68703), included with E2669A and E2678A purchased after October, 2003.	1	2	1	n/a
Agilent E2697A 1 Mohm adapter with passive probe, OR 1156A, 1157A, or 1158A active probe.	2	2	2	3***
Agilent E2697A high impedance converter, N2774A current probe, and N2775A power supply.	n/a	n/a	n/a	1***
*The oscilloscope's memory upgrade option is recommended (Option 001 when ordered with the oscilloscope, or after purchase: E2680A for the 5485xA Series oscilloscopes, or N5404A for the DS080000 Series oscilloscopes). This gives the automated test software more flexibility in making corner case measurements (and improves test performance).				
**The enhanced bandwidth software option is recommended for the Agilent 54855A oscilloscope (Option 008), and the noise reduction software option is recommended for the DS080000 Series oscilloscopes (Option 005 when ordered with the oscilloscope or N5403A after purchase). This reduces the bandwidth of the oscilloscope to just what is required by the USB-IF (2 GHz for USB 2.0), which can greatly reduce system measurement noise, allowing the maximum measurement margin.				
***For low/full speed testing, the Agilent 54831B/D or 54832B/D Infiniium oscilloscope with 1165A passive probes and 1147A current probe can be used instead.				

**Table 2** Digital Multimeter

Equipment Required	Host Hi-Speed	Hub Hi-Speed	Device Hi-Speed	Low/Full Speed
Agilent 33401A digital multimeter or equivalent.	1	1	1	1
Mini-clip DMM leads - one each of black and red color.	1	1	1	1



**Table 3** Digital Signal Generator

Equipment Required	Host Hi-Speed	Hub Hi-Speed	Device Hi-Speed	Low/Full Speed
Agilent 81130A Pulse/Pattern Generator with 2 channels of Agilent 81132A (660 MHz) option.	n/a	1	1	n/a
1 MB Memory card option for 81130A (option UFJ).	n/a	1	1	n/a
6dB attenuator (Agilent 8493C Option 006) – for scaling the DSG output voltages needed for receiver sensitivity test.	n/a	2	2	n/a
50-ohm coaxial cable with male SMA connectors at both ends (Agilent 8120-4948 or equivalent).	n/a	2	2	n/a
Agilent 82357A USB/GPIB interface	n/a	1	1	n/a

**Table 4** USB Electrical Test Fixtures

Equipment Required	Host Hi-Speed	Hub Hi-Speed	Device Hi-Speed	Low/Full Speed
Device Hi-Speed Signal Quality test fixture, Agilent P/N E2645-66501.	1	1	1	n/a
Host Hi-Speed Signal Quality test fixture, Agilent P/N E2645-66502.	1	1	n/a	n/a
Receiver Sensitivity test fixture, Agilent P/N E2645-66503.	n/a	1	1	n/a
Host Disconnect test fixture, Agilent P/N E2645-66506.	1	n/a	n/a	n/a
5V test fixture power supply, Agilent P/N 0950-2546.	1	1	1	n/a
SQiDD board, included in the USB test option.	n/a	n/a	n/a	1*
100 mA load board (see the schematic in <a href="#">Figure 4</a> on page 165)				1
500 mA load board (see the schematic in <a href="#">Figure 5</a> on page 165)				1

\*A second SQiDD board is recommended for droop/drop testing; additional SQiDD boards can be ordered as Agilent E2646A.

## 2 Preparing to Take Measurements

**Table 5** Miscellaneous Cables and Devices

Equipment Required	Host Hi-Speed	Hub Hi-Speed	Device Hi-Speed	Low/Full Speed
5 m USB cable (any listed on USB-IF web site).	1	1	1	as needed
1.5 m USB cable (any listed on USB-IF web site).	1	1	n/a	n/a
1 m USB cable (any listed on USB-IF web site).				as needed
Modular AC power cord.	2	2	2	
Hi-Speed USB Hub (any listed on USB-IF web site).	1	n/a	n/a	
Hi-Speed USB Device (any listed on USB-IF web site).	1	n/a	n/a	
USB self-powered hub (and power supply). These are the hubs used for compliance testing and are available from the USB-IF. For development testing, in most cases, a hub that has passed USB compliance testing can be used.	n/a	n/a	n/a	5

**Table 6** High-Speed Electrical Test Bed Computer

Equipment Required	Host Hi-Speed	Hub Hi-Speed	Device Hi-Speed	Low/Full Speed
High-Speed Electrical Test Bed Computer. This computer hosts a USB 2.0 compliance host controller for hi-speed hub or device electrical test, or serves as a test bed host for a USB 2.0 host controller under test. For instructions on configuring this computer, refer to the <i>High-Speed Electrical Test Toolkit Setup Instruction</i> document which comes with the High-Speed Electrical Test Tool Kit software.	1	1	1	1
High-Speed Electrical Test Tool Kit software (USBHSET)*, **.	1	1	1	1

\*You can get this software from the developers tools page at the USB Implementers Forum web site, <http://www.usb.org/developers/tools>.

\*\*Contains a proprietary EHCI driver stack. The Hi-speed Electrical Test Tool software requires the use of a proprietary EHCI driver stack. The use of this proprietary EHCI driver stack facilitates the electrical testing that requires direct control of the command registers of the USB EHCI host controllers. The end result much more robust test bed environment. Since the proprietary EHCI driver stack is designed for debug and test validation purposes, this driver stack does not support the normal functionality as found in the EHCI drivers from Microsoft (or the device vendor). An automatic driver stack switching function has been implemented into the Hi-speed Electrical Test Tool for easy switching between the proprietary EHCI driver stack and that from Microsoft. Upon invocation of the HS Electrical Test Tool software, the driver stack will automatically switch to the Intel proprietary EHCI driver stack. Upon exit of the HS Electrical Test Tool software, the driver stack will automatically switch to the Microsoft EHCI driver stack.

## Setting Up the Equipment

### Infiniium 5485xA Series or DS080000 Series Digital Sampling Oscilloscope

- 1 Connect keyboard and mouse to oscilloscope.
- 2 Connect optional computer monitor to the VGA connector on the rear nearest the right side of the instrument.
- 3 Attach the Agilent 113xA differential probe to Channel 1 of the oscilloscope.
  - a Attach the socketed probe head to the differential probe amp.
  - b Attach the header adapter to the socketed probe head (Figure 1).
  - c Handle the socketed probe head and header adapter carefully.
  - d For durability, epoxy can be used to strengthen the assembly. Only apply epoxy to back (noncomponent) side of probe head.



**Figure 1** Differential Probe Setup

- 4 Attach the E2697A adapters or 1156A probes to Channels 2 and 3.
  - a When using the E2697A adapter, connect the 10073C miniature passive probes to the E2697A adapter.

#### NOTE

These probe assignments will be used through out the entire test procedure.

- 5 Turn on the oscilloscope to allow 30 minutes of warm up time prior to use.
- 6 Configure the second monitor, if being used, while the oscilloscope is warming up.
- 7 If the ambient temperature has changed more than 5 degrees from the previous calibration, perform the calibration procedure built into the oscilloscope (in the [Calibration... ] section of [Utilities] pull down menu).

- 8 If the E2697A adapter is being used, compensate the passive probes (see probe instructions).
- 9 Calibrate all the probes.
  - a If you will be performing hub hi-speed tests, calibrate out the skew between the differential probes on channel 1 and channel 4 (refer to oscilloscope instructions).

### NOTE

In certain test situations, there may not be a ground connection between the DSO and the device under test. This may lead to the signal seen by the differential probe to be modulated up and down due to the mid-frequency switching power supply. Connecting the DSO ground to the DUT ground will be required to establish a common ground reference.

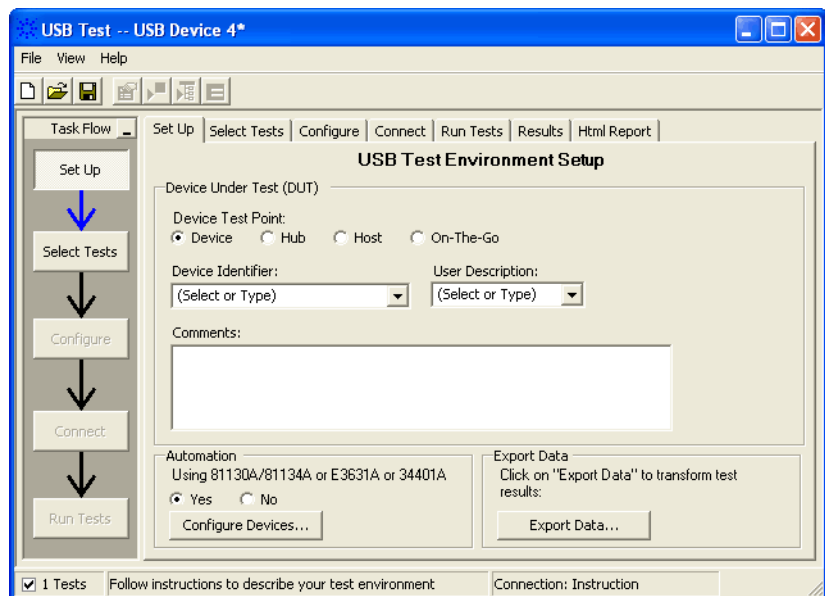
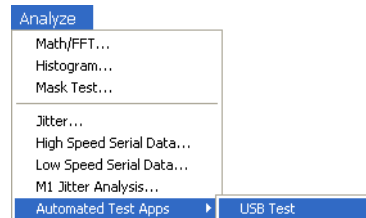
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### 81130A Digital Signal Generator

The digital signal generator is needed to perform hi-speed hub and device receiver sensitivity tests. For energy conservation, you may choose to turn on the digital signal generator about 15 minutes prior to performing these measurements.

## Starting the USB 2.0 Compliance Test Option

- 1 From the Infiniium oscilloscope's main menu, choose **Analyze>Automated Test Apps>USB Test**.



**Figure 2** The USB 2.0 Compliance Test Option

### NOTE

If “USB Test” does not appear in the Automated Test Apps menu, the USB 2.0 Compliance Test Option has not been installed (see [Chapter 1](#), “Installing the USB 2.0 Compliance Test Option”).

**Figure 2** shows the USB 2.0 Compliance Test Option main window. The task flow pane, and the tabs in the main pane, show the steps you take in running the automated tests:

Set Up	Lets you identify the test environment, including information about the device being tested and other test instruments that can be automatically configured.
--------	--

Select Tests	Lets you select the tests you want to run. The tests are organized hierarchically so you can select all tests in a group. After tests are run, status indicators show which tests have passed, failed, or not been run, and there are indicators for the test groups.
Configure	Lets you configure test parameters (like test type).
Connect	Shows you how to connect the oscilloscope to the device under test for the tests to be run.
Run Tests	Starts the automated tests. If the connections to the device under test need to be changed while multiple tests are running, the tests pause, show you how to change the connection, and wait for you to confirm that the connections have been changed before continuing.
Results	Contains more detailed information about the tests that have been run. You can change the thresholds at which marginal or critical warnings appear.
HTML Report	Shows a compliance test report that can be printed. You can choose between a verbose and compact report.

### Online Help Topics

For information on using the USB 2.0 Compliance Test Option, see its online help (which you can access by choosing Help>Contents... from the application's main menu).

The USB 2.0 Compliance Test Option's online help describes:

- Creating or opening a test project.
- Selecting tests.
- Configuring selected tests.
- Connecting the oscilloscope to the DUT.
- Running tests.
- Viewing test results.
  - To show reference images and flash mask hits.
  - To change margin thresholds.
- Viewing/printing the HTML test report.
- Saving test projects.

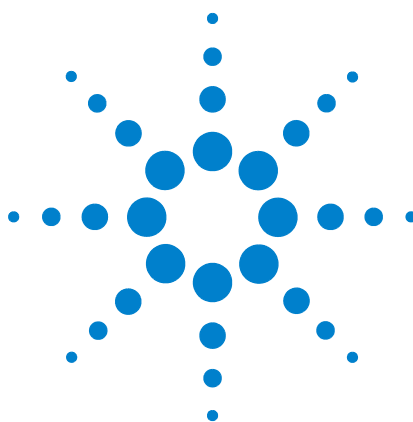
## Running Tests

To run USB electrical compliance tests:

- 1 Select the tests you want to run.
- 2 Change test configuration options if necessary.
- 3 Connect the oscilloscope to the device under test.
- 4 Run the tests.
- 5 View the detailed test results.
- 6 View/print the HTML test report.

## 2 Preparing to Take Measurements





## 3 Device Hi-Speed Tests

Device Hi-Speed Signal Quality Test	27
Device Packet Parameters	32
Device CHIRP Timing	39
Device Suspend/Resume/Reset Timing	42
Device Test J/K, SE0_NAK	50
Device Receiver Sensitivity	56

### NOTE

To give the automated test software more flexibility in making corner case measurements (and improve test performance), the oscilloscope's memory upgrade option is recommended (Option 001 when ordered with the oscilloscope, or after purchase: E2680A for the 5485xA Series oscilloscopes, or N5404A for the DSO80000 Series oscilloscopes).

Also, to reduce the bandwidth of the oscilloscope to just what is required by the USB-IF (2 GHz for USB 2.0)—this can greatly reduce system measurement noise, allowing the maximum measurement margin—the enhanced bandwidth software option is recommended for the Agilent 54855A oscilloscope (Option 008), and the noise reduction software option is recommended for the DSO80000 Series oscilloscopes (Option 005 when ordered with the oscilloscope or N5403A after purchase).

In addition to the hi-speed electrical tests described in this chapter, the device under test must also pass the following compliance tests applicable to hi-speed capable devices:

- Upstream full speed signal quality.
- Upstream low speed signal quality.
- Inrush current.
- Back-voltage.

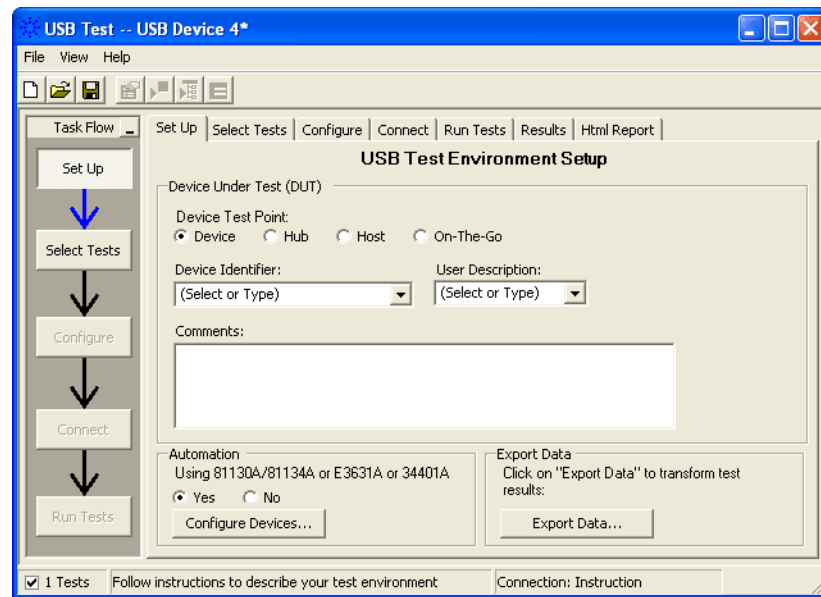
### Before Running These Tests

If you haven't already performed the initial equipment set up, see [“Setting Up the Equipment”](#) on page 19.



#### Selecting the Device Test Environment Setup

- 1 In the USB automated test application, select the **Device** test environment.



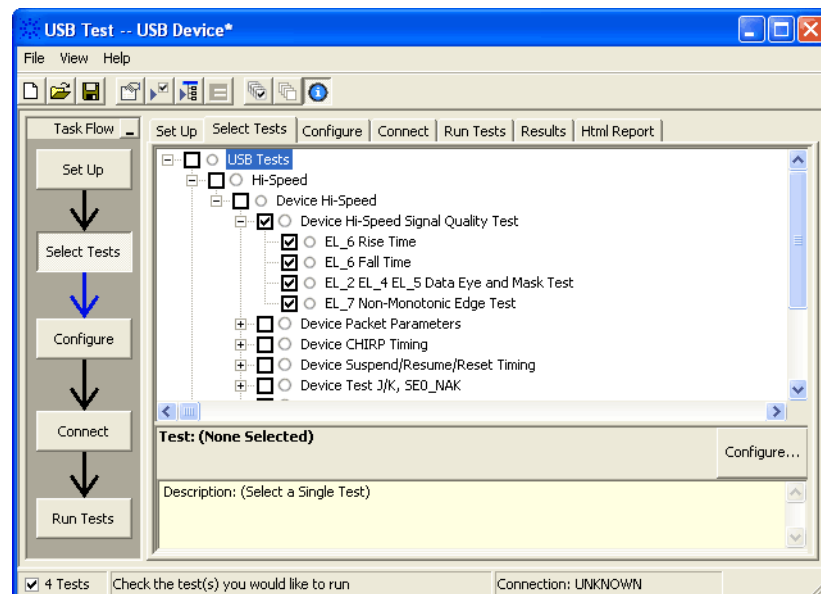
## Device Hi-Speed Signal Quality Test

### Equipment Used

**Table 7** Equipment Used in Device Hi-Speed Signal Quality Tests

Quantity	Item	Description/Model
1	Oscilloscope	Agilent 5485xA Series or DS080000 Series
1	Differential probe	Agilent 113xA with E2699A or E2678A
1	Header adapter	Agilent 01131-68703
1	Host test bed computer	Any computer with hi-speed USB ports
1	Device Hi-Speed Signal Quality test fixture and 4" USB cable	Agilent E2645-66501
1	5V power supply	Agilent 0950-2546 or equivalent
1	5 meter USB 2.0 hi-speed cable	Any listed on USB-IF web site

### Selecting the Tests

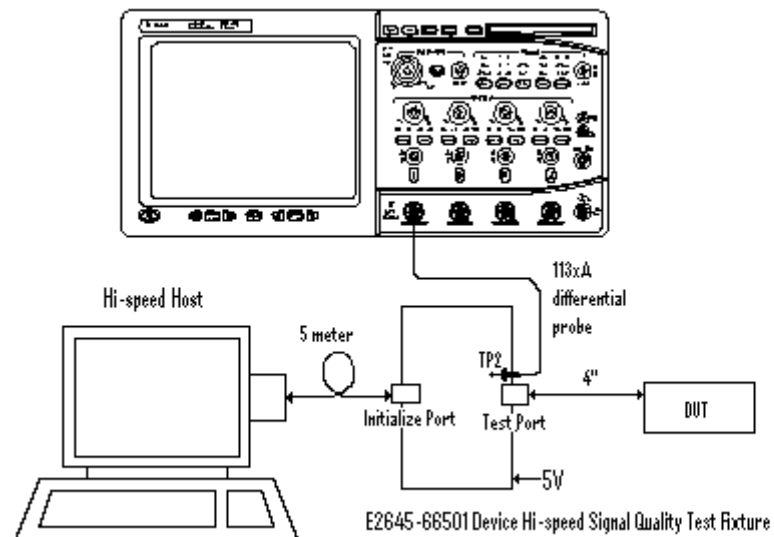


## Configuring the Tests

### Connecting the Equipment

The USB automated test application will prompt you to perform these connection steps:

- 1 Attach the 5V power supply to J5 of the E2645-66501 Device Hi-Speed signal quality test fixture. Verify the green Power LED (D1) is lit and the yellow Test LED (D2) is not lit.
- 2 Connect the [TEST PORT] of the Device Hi-speed Signal Quality test fixture into the upstream facing port of the device under test, using the 4" USB cable.
- 3 Connect the [INIT PORT] of the test fixture to a Hi-speed capable port of the Test Bed Computer, using the 5 meter USB cable.
- 4 Apply power to the device.
- 5 Attach the differential probe to TP2 of the test fixture, using the damped header adapter. Ensure the + polarity on the probe lines up with D+, which is the pin nearest the USB connector.



- 6 Check I have completed these instructions.

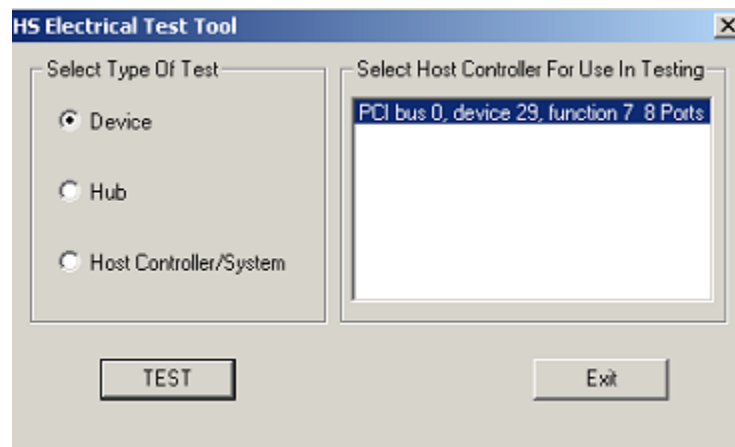
## Running the Tests

- 1 Click **Run Tests**.

### Test Instructions, Part 1

The USB automated test application will prompt you to perform these steps:

- 1 Invoke the HS Electrical Test Tool software on the Hi-Speed Electrical Test Bed computer.
- 2 Select Device and click the [TEST] button to enter the Device Test menu.



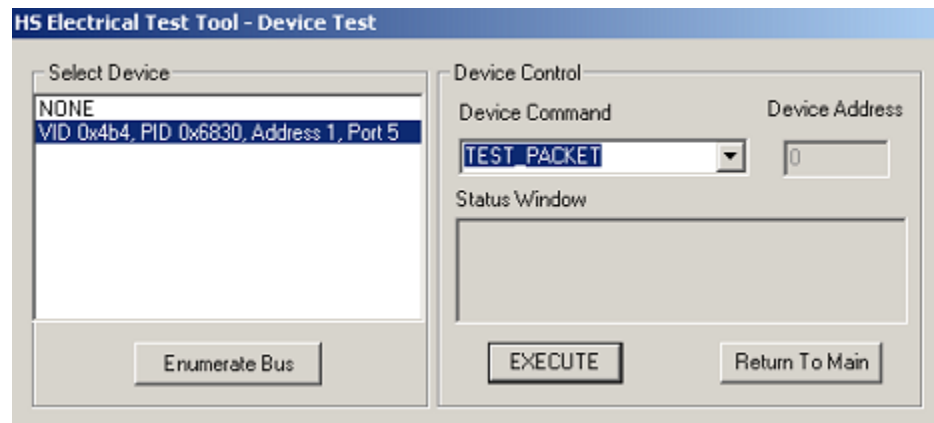
- 3 Click **OK** to close the Test Instructions dialog.

### Test Instructions, Part 2

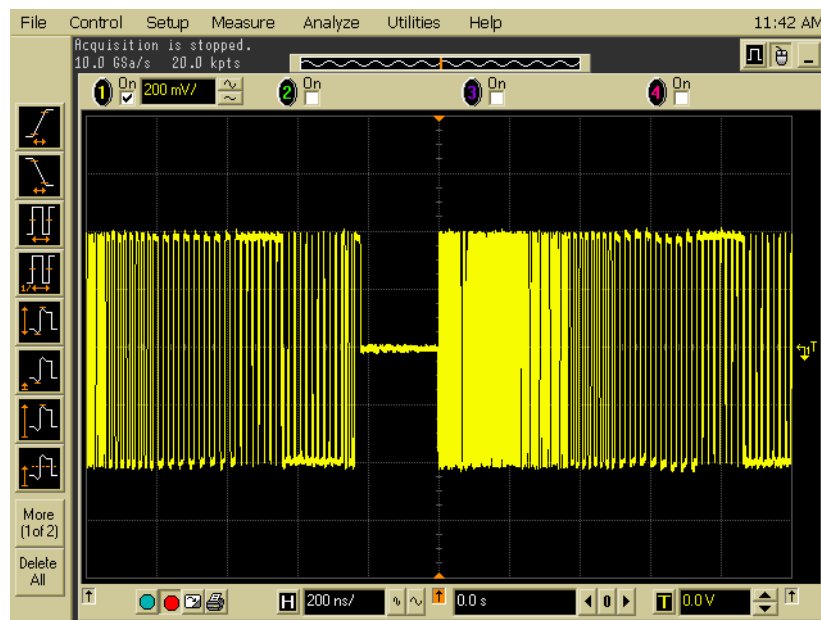
The USB automated test application will prompt you to perform these steps:

- 1 The device under test should be enumerated with the device's VID shown together with the root port in which it is connected.
- 2 Select **TEST\_PACKET** from the Device Command drop down menu and click [EXECUTE]. This forces the device under test to continuously transmit test packets.

### 3 Device Hi-Speed Tests



- 3 Place the Test Switch (S1) in the **TEST** position. Verify the yellow TEST LED is lit. You should see the transmitted test packet on the oscilloscope as below.



- 4 Click **OK** to close the Test Instructions dialog.

**EL\_6 Rise Time**

**EL\_6 Fall Time**

**EL\_2 EL\_4 EL\_5 Data Eye and Mask Test**

After viewing the test results, click **OK** to close the Test Instructions dialog.

## EL\_7 Non-Monotonic Edge Test

### Viewing Test Results

- 1 When the Testing Complete dialog appears, click **OK**.  
The Results tab shows the test results.

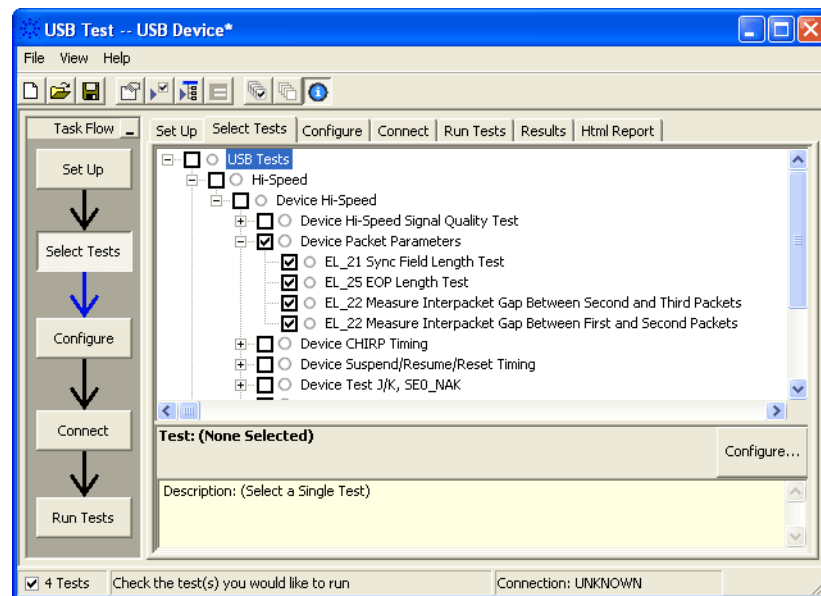
## Device Packet Parameters

### Equipment Used

**Table 8** Equipment Used in Device Packet Parameters Tests

Quantity	Item	Description/Model
1	Oscilloscope	Agilent 5485xA Series or DS080000 Series
1	Differential probe	Agilent 113xA with E2699A or E2678A
1	Header adapter	Agilent 01131-68703
1	Host test bed computer	Any computer with hi-speed USB ports
1	Device Hi-Speed Signal Quality test fixture and 4" USB cable	Agilent E2645-66501
1	5 meter USB 2.0 hi-speed cable	Any listed on USB-IF web site

### Selecting the Tests





## Configuring the Tests

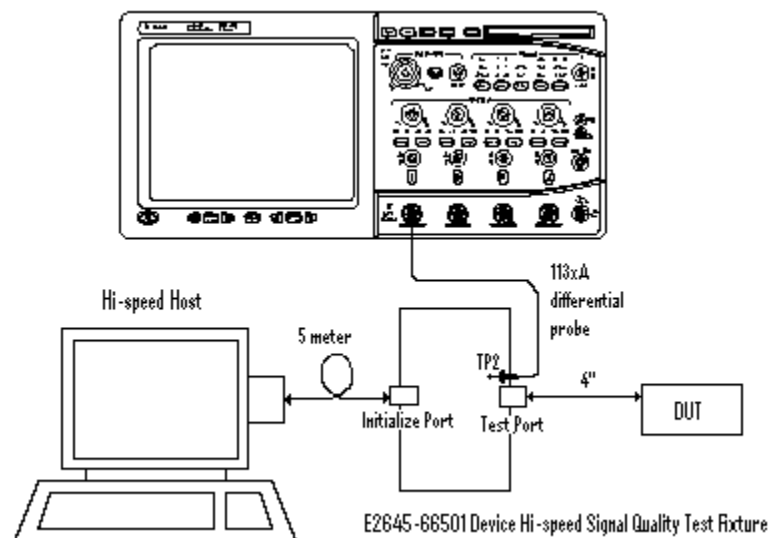
### Connecting the Equipment

The USB automated test application will prompt you to perform these connection steps:

- 1 Remove the 5V supply. Connect the E2645-66501 Device Hi-Speed Signal Quality test fixture ([INIT PORT]) into a high-speed capable port of the test bed, using the 5 meter USB cable.
- 2 Connect the test fixture [TEST PORT] into B receptacle of the upstream facing port under test of the device, using the 4" USB cable. Apply power to the device.
- 3 Ensure that the test switch on the test fixture is in the OFF position, and the test LED is not lit.
- 4 Attach the Agilent 113xA differential probe to TP2 of the test fixture, using a damped header adapter.

#### NOTE

Ensure the + polarity on the probe lines up with D+, which is the pin nearest the USB connector.



- 5 Check **I have completed these instructions.**

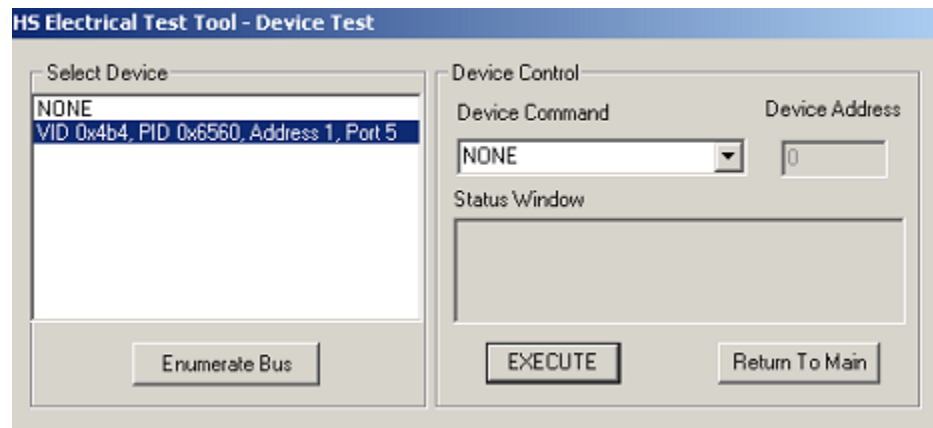
## Running the Tests

- 1 Click **Run Tests**.

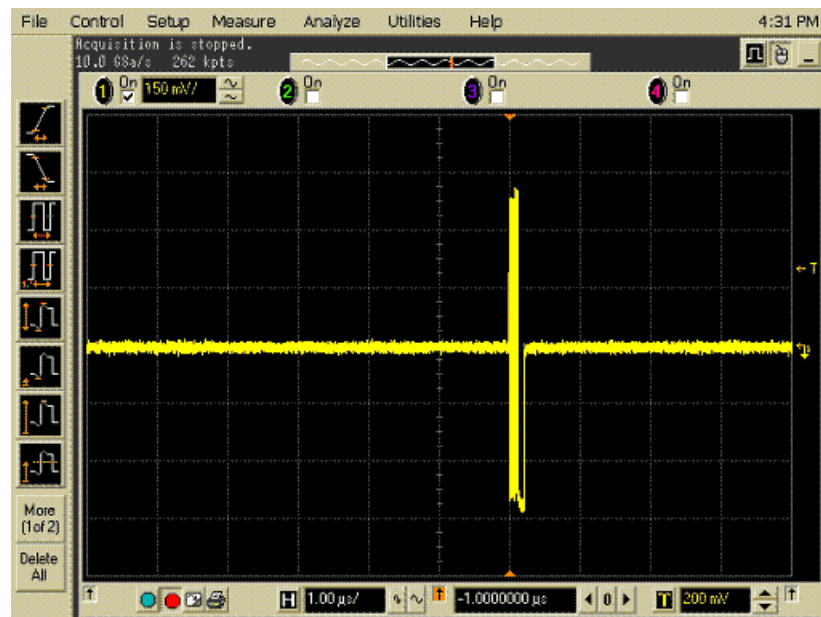
## Test Instructions, Part 1

The USB automated test application will prompt you to perform these steps:

- 1 Cycle the device power to restore the device to normal operation. On the Device Test Menu of the HS Electrical Tool, click **Enumerate Bus** once.



- 2 Using the oscilloscope, verify the SOFs (Start Of Frame) packets are being transmitted on the port under test. You may need to lower the trigger level to somewhat below 400 mV.

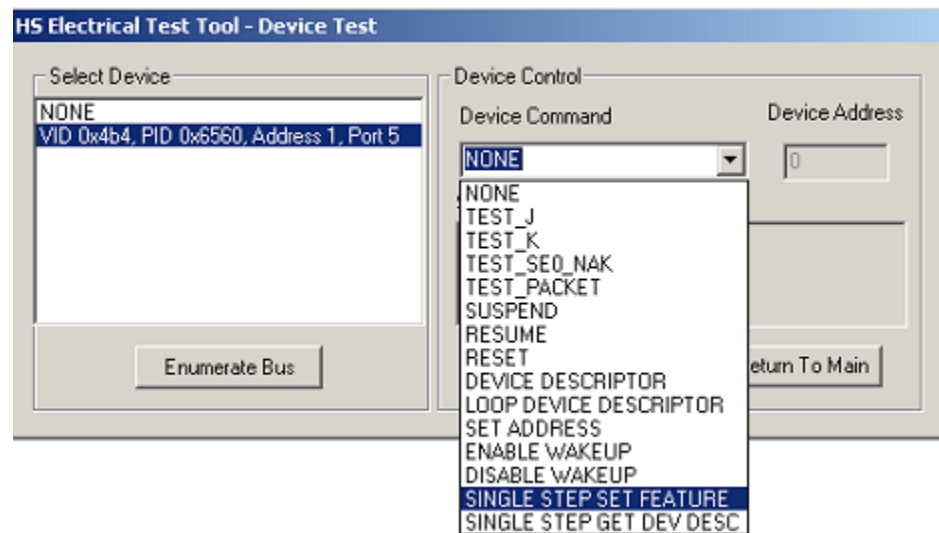


- 3 Click **OK** to close the Test Instructions dialog.

## Test Instructions, Part 2

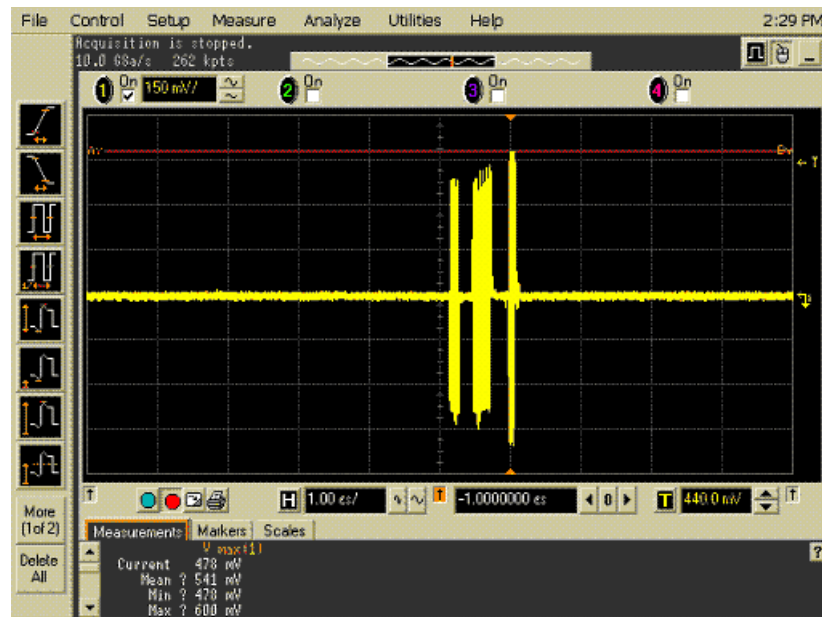
The USB automated test application will prompt you to perform these steps:

- 1 In the Device Test menu of the HS Electrical Test Tool, ensure that the hub under test is selected.
- 2 Select **SINGLE STEP SET FEATURE** from the Device Command window. Click **[EXECUTE]** once.



- 3 You should see the transmitted test packet on the oscilloscope as below.

### 3 Device Hi-Speed Tests

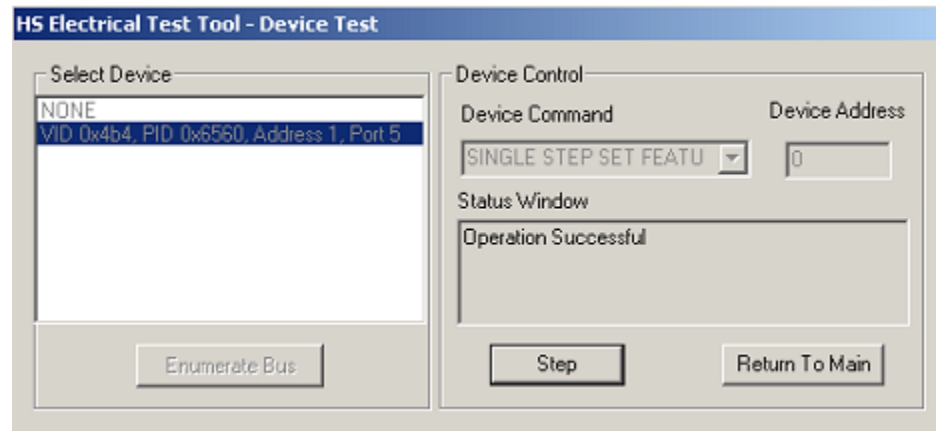


- 4 Click **OK** to close the Test Instructions dialog.

**EL\_21 Sync Field Length Test****EL\_25 EOP Length Test****EL\_22 Measure Interpacket Gap Between Second and Third Packets****EL\_22 Measure Interpacket Gap Between First and Second Packets**

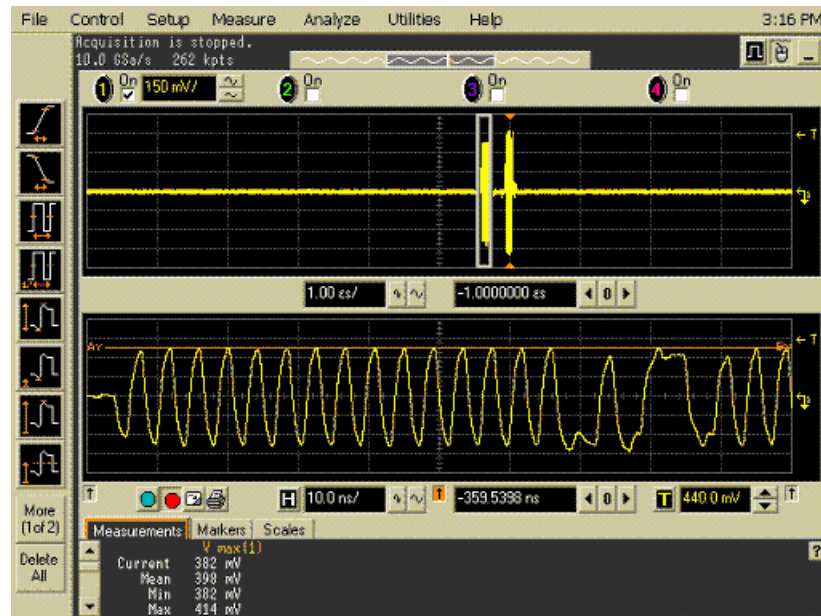
The USB automated test application will prompt you to perform these steps:

- 1 In the Device Test menu of the HS Electrical Test Tool, click **[STEP]** once again. This is the second step of the two-step Single Step Set Feature command.



- 2 You should see the transmitted test packet on the oscilloscope as below.

### 3 Device Hi-Speed Tests



- 3 Click **OK** to close the Test Instructions dialog.

### Viewing Test Results

- 1 When the Testing Complete dialog appears, click **OK**.

The Results tab shows the test results.

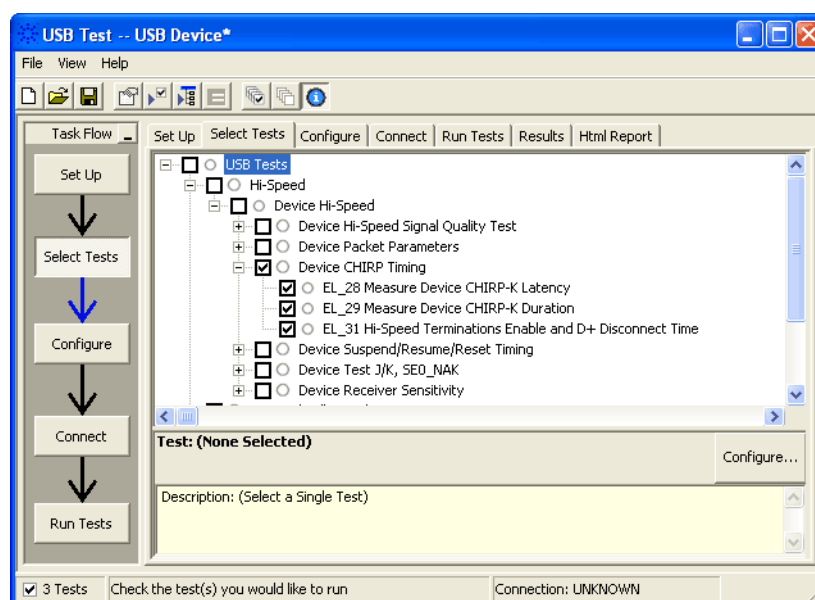
## Device CHIRP Timing

### Equipment Used

**Table 9** Equipment Used in Device CHIRP Timing Tests

Quantity	Item	Description/Model
1	Oscilloscope	Agilent 5485xA Series or DS080000 Series
2	Passive or active probes	Agilent E2697A with 10073C, or 1156A
1	Host test bed computer	Any computer with hi-speed USB ports
1	Device Hi-Speed Signal Quality test fixture and 4" USB cable	Agilent E2645-66501
1	5 meter USB 2.0 hi-speed cable	Any listed on USB-IF web site

### Selecting the Tests

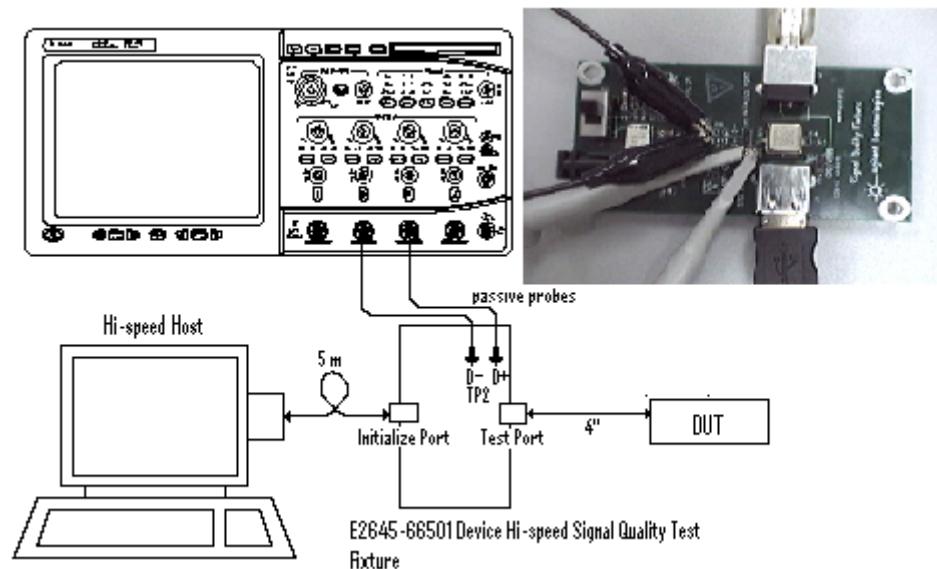


## Configuring the Tests

### Connecting the Equipment

The USB automated test application will prompt you to perform these connection steps:

- 1 Connect the E2697A with 10073C passive probe or the 1156A active probe on Channel 2 to the D- pin at TP2 of the E2645-66501 Device Hi-Speed Signal Quality test fixture.
- 2 Connect the E2697A with 10073C passive probe or the 1156A active probe on Channel 3 to the D+ pin at TP2. D+ on TP2 is the pin closest to the USB connector.
- 3 Connect both probe grounds to leads TP5.
- 4 Connect the [INIT PORT] of the test fixture into the HS host controller port, using the 5-meter USB cable.
- 5 Connect the [TEST PORT] on the fixture to the upstream port of the device under test.



- 6 Check I have completed these instructions.



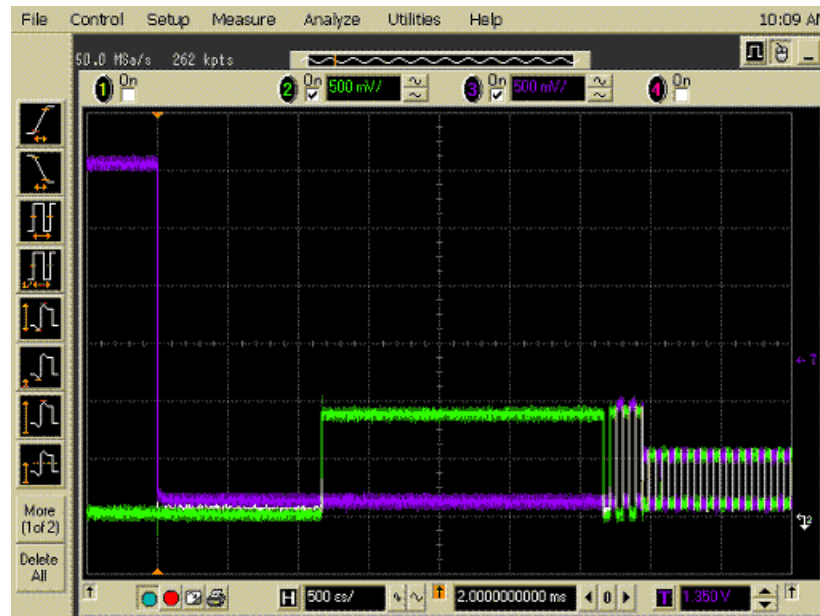
## Running the Tests

- 1 Click **Run Tests**.

## Test Instructions

The USB automated test application will prompt you to perform these steps:

- 1 On the HS Electrical Test Tool software, click [**Enumerate Bus**] once. You should capture the CHIRP handshake as in the below figure.



- 2 Click **OK** to close the Test Instructions dialog.

**EL\_28 Measure Device CHIRP-K Latency**

**EL\_29 Measure Device CHIRP-K Duration**

**EL\_31 Hi-Speed Terminations Enable and D+ Disconnect Time**

## Viewing Test Results

- 1 When the Testing Complete dialog appears, click **OK**.

The Results tab shows the test results.

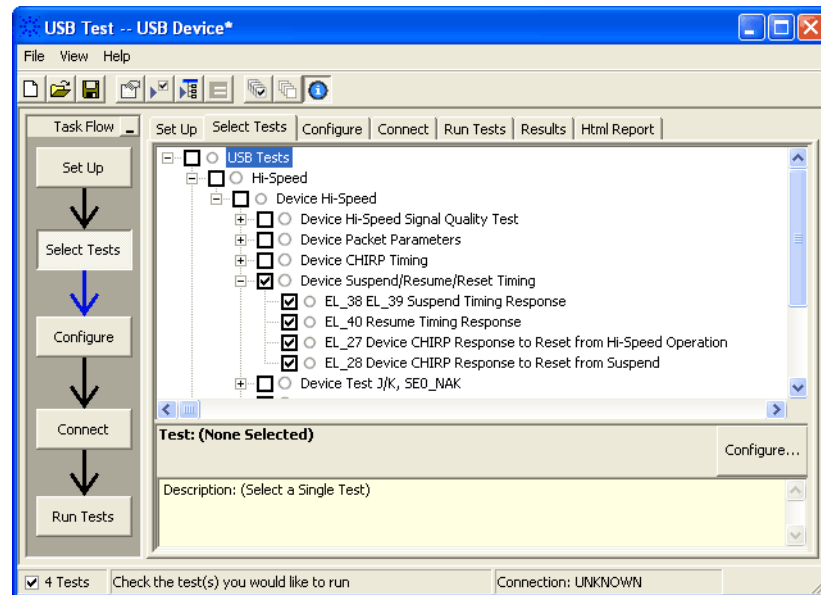
## Device Suspend/Resume/Reset Timing

### Equipment Used

**Table 10** Equipment Used in Device Suspend/Resume/Reset Timing Tests

Quantity	Item	Description/Model
1	Oscilloscope	Agilent 5485xA Series or DS080000 Series
2	Passive or active probes	Agilent E2697A with 10073C, or 1156A
1	Host test bed computer	Any computer with hi-speed USB ports
1	Device Hi-Speed Signal Quality test fixture and 4" USB cable	Agilent E2645-66501
1	5 meter USB 2.0 hi-speed cable	Any listed on USB-IF web site

### Selecting the Tests

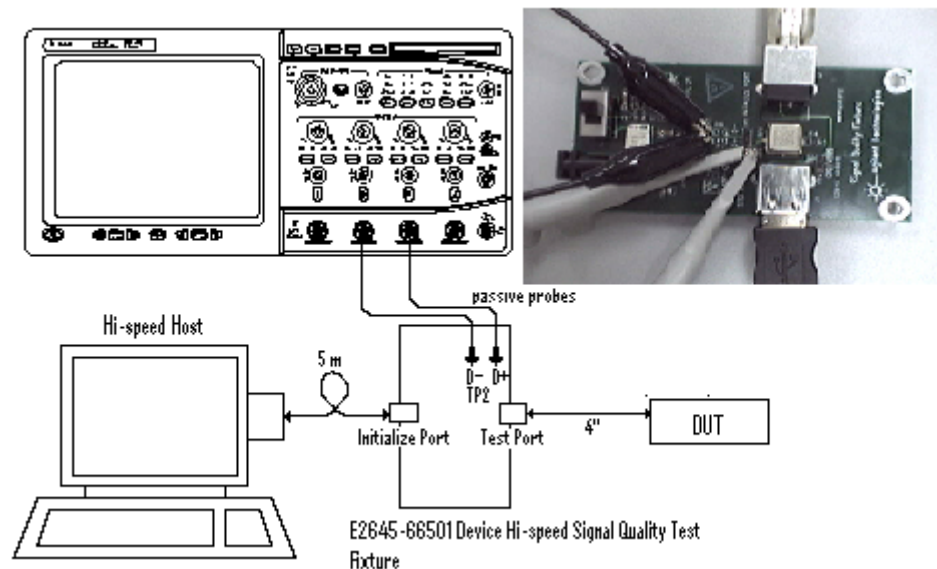


## Configuring the Tests

### Connecting the Equipment

The USB automated test application will prompt you to perform these connection steps:

- 1 Connect the E2697A with 10073C passive probe or the 1156A active probe on Channel 2 to the D- pin at TP2 of the E2645-66501 Device Hi-Speed Signal Quality test fixture.
- 2 Connect the E2697A with 10073C passive probe or the 1156A active probe on Channel 3 to the D+ pin at TP2. D+ on TP2 is the pin closest to the USB connector.
- 3 Connect both probe grounds to leads TP5.
- 4 Connect the [INIT PORT] of the test fixture into the HS host controller port, using the 5-meter USB cable.
- 5 Connect the [TEST PORT] on the fixture to the upstream port of the device under test.



- 6 Check I have completed these instructions.

## Running the Tests

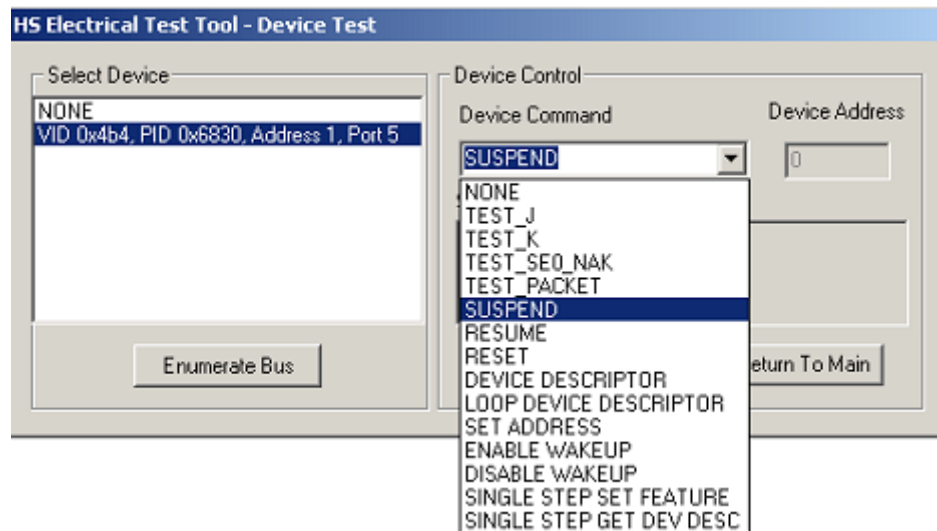
- 1 Click **Run Tests**.

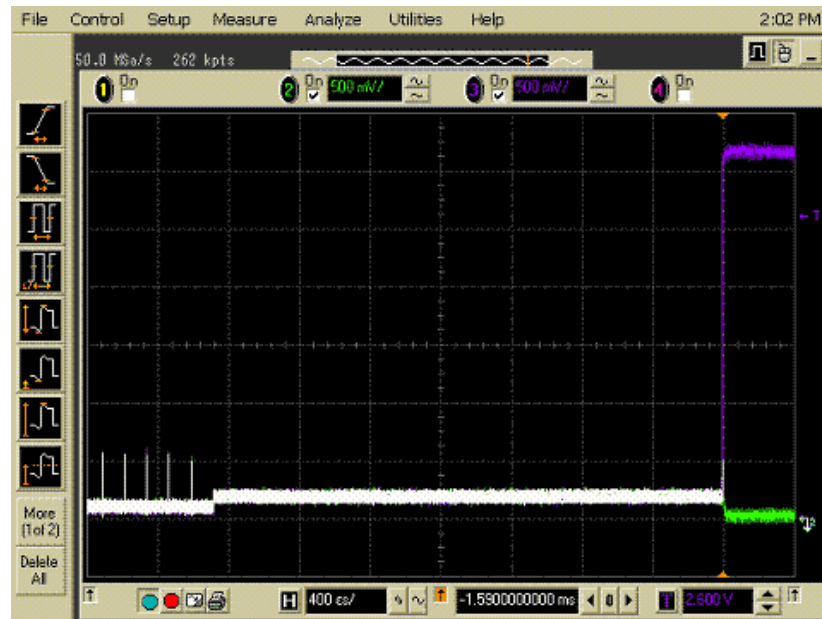
## Test Instructions

### EL\_38 EL\_39 Suspend Timing Response

The USB automated test application will prompt you to perform these steps:

- 1 On the Device Test Menu of the HS Electrical Test Tool software, click **[Enumerate Bus]** once.
- 2 Select **SUSPEND** from the Device Command drop down menu. Click **[EXECUTE]** once to place the device into suspend. The captured transition should be as in the figure below.



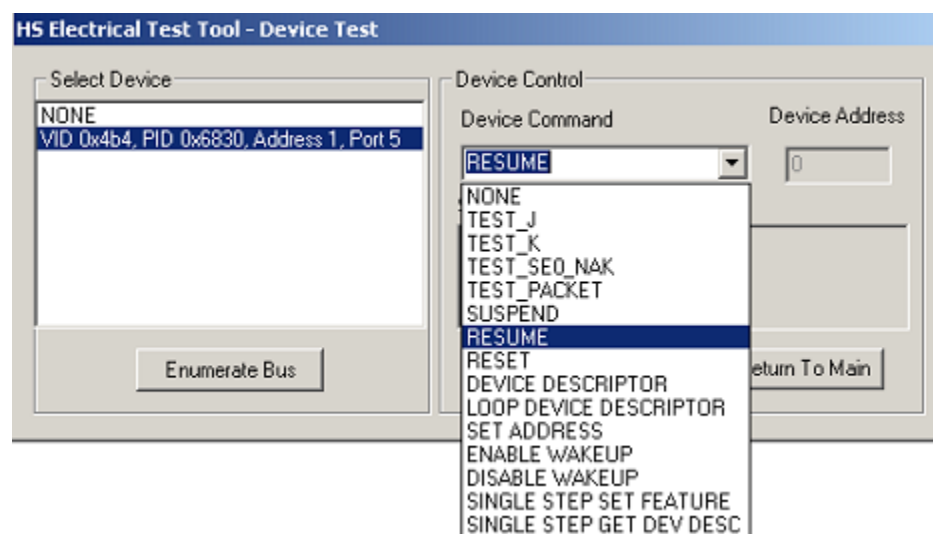


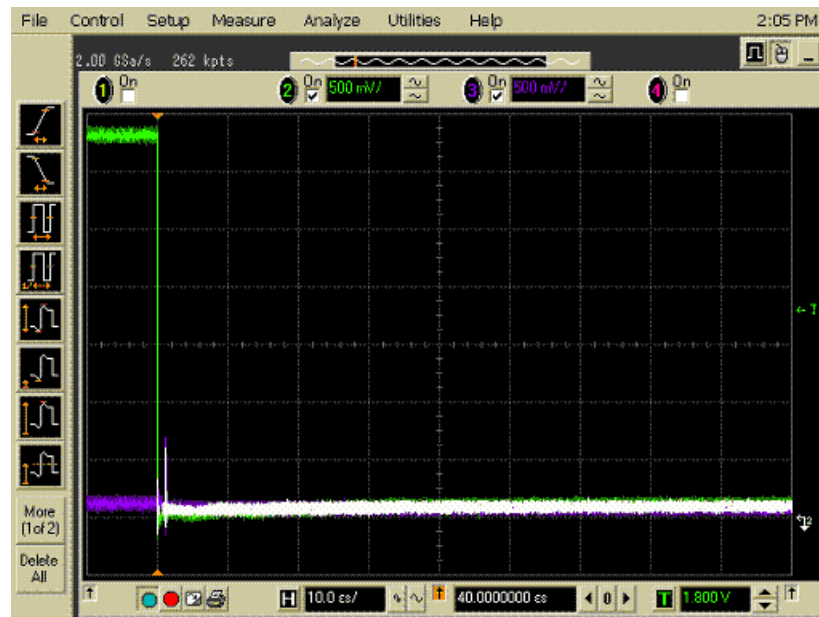
- 3 Click **OK** to close the Test Instructions dialog.

### EL\_40 Resume Timing Response

The USB automated test application will prompt you to perform these steps:

- 1 On the Device Test Menu of the HS Electrical Test Tool, select **RESUME** from the Device Command drop down menu. Click **[EXECUTE]** once to resume the hub from suspend. The captured transition should be as in the figure below.



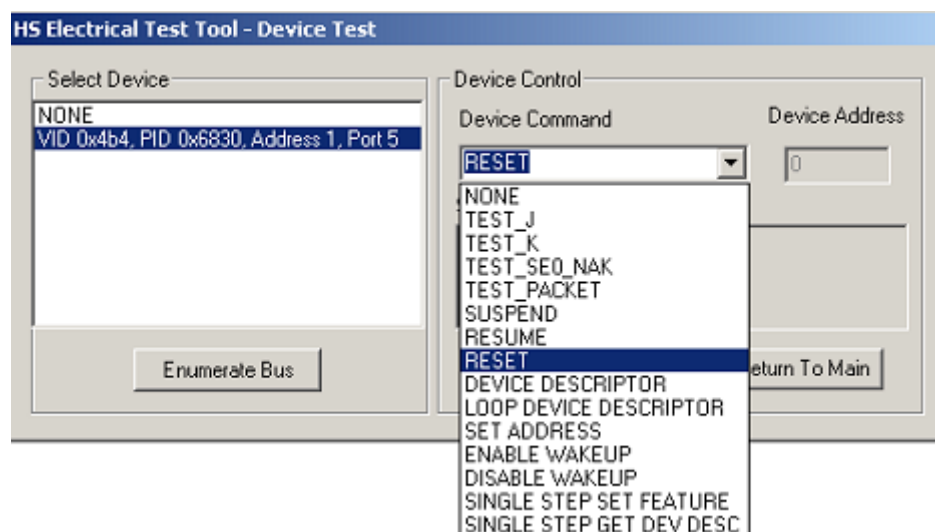


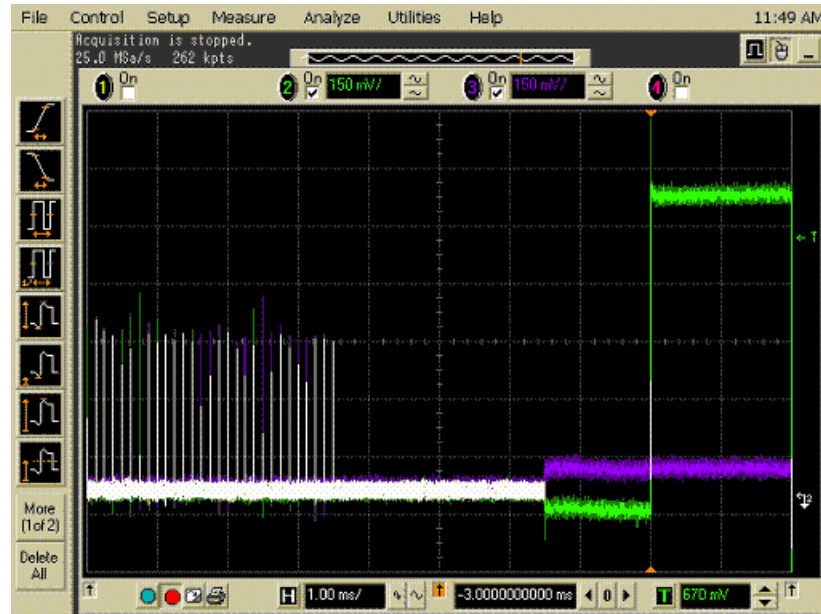
- 2 Click **OK** to close the Test Instructions dialog.

#### EL\_27 Device CHIRP Response to Reset from Hi-Speed Operation

The USB automated test application will prompt you to perform these steps:

- 1 On the Device Test Menu of the HS Electrical Test Tool, select **RESET** from the Device Command drop down menu. Click **[EXECUTE]** once to reset the device operating in high speed. The captured transition should be as in the figure below.



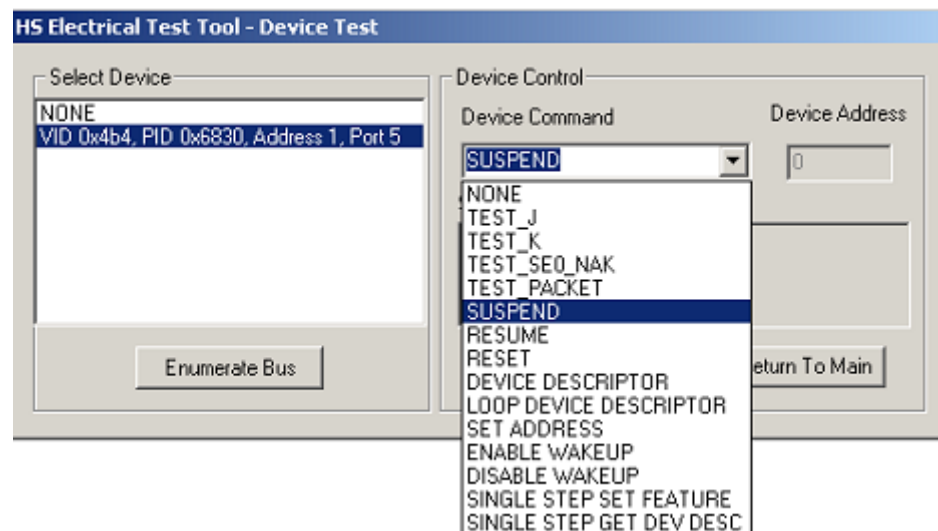


- 2 Click **OK** to close the Test Instructions dialog.

## EL\_28 Device CHIRP Response to Reset from Suspend

The USB automated test application will prompt you to perform these steps:

- 1 On the Device Test Menu of the HS Electrical Test Tool software, select **SUSPEND** from the Device Command drop down menu. Click **[EXECUTE]** once to place the device into suspend.

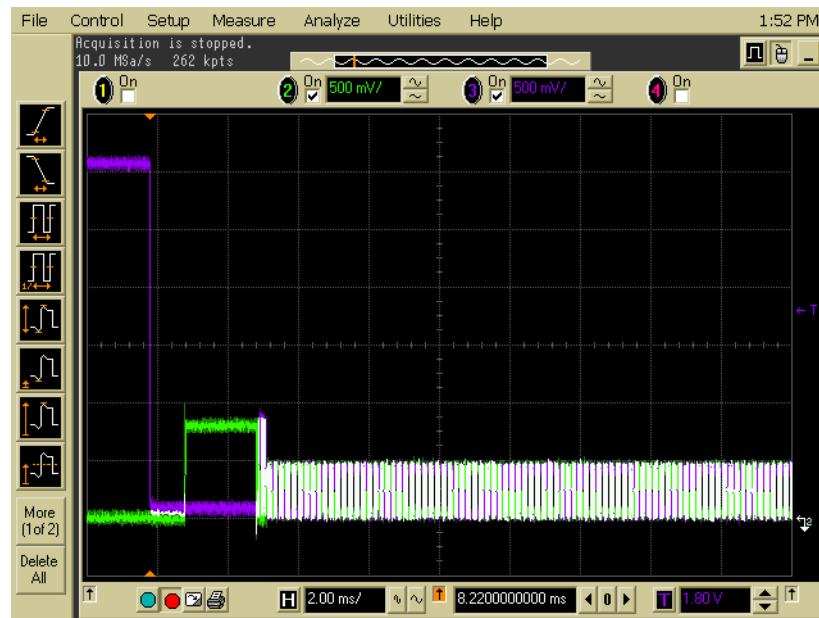
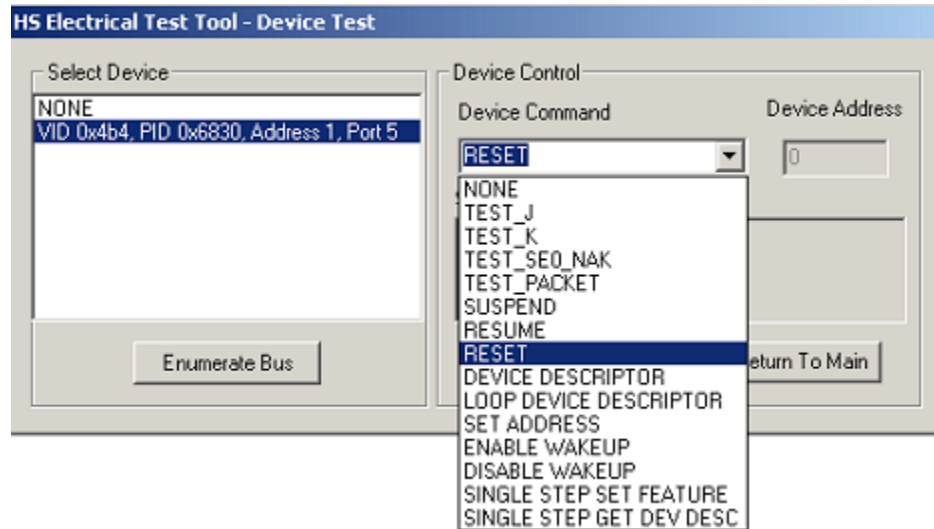


- 2 Click **OK** to close the Test Instructions dialog.

### 3 Device Hi-Speed Tests

The USB automated test application will prompt you to perform these steps:

- 1 On the Device Test Menu of the HS Electrical Test Tool, select **RESET** from the Device Command drop down menu. Click **[EXECUTE]** once to reset the device operating in high speed. The captured transition should be as in the figure below.



- 2 Click **OK** to close the Test Instructions dialog.



## Viewing Test Results

- 1 When the Testing Complete dialog appears, click **OK**.

The Results tab shows the test results.

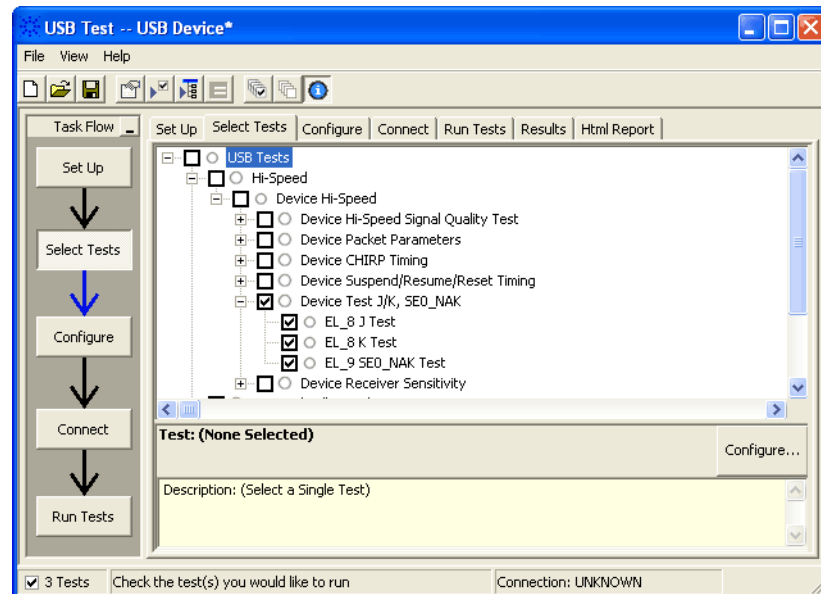
## Device Test J/K, SE0\_NAK

### Equipment Used

**Table 11** Equipment Used in Device Test J/K, SE0\_NAK Tests

Quantity	Item	Description/Model
1	Digital Multimeter (DMM)	Agilent 34401A or equivalent
1	Host test bed computer	Any computer with hi-speed USB ports
1	Device Hi-Speed Signal Quality test fixture and 4" USB cable	Agilent E2645-66501
1	5V power supply	Agilent 0950-2546 or equivalent
1	5 meter USB 2.0 hi-speed cable	Any listed on USB-IF web site

### Selecting the Tests

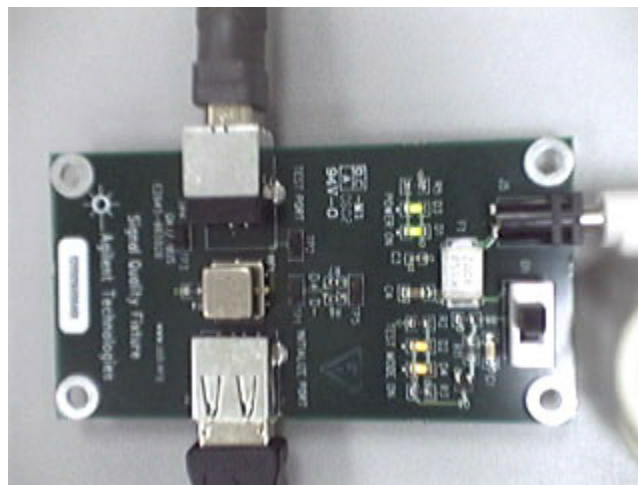


## Configuring the Tests

### Connecting the Equipment

The USB automated test application will prompt you to perform these connection steps:

- 1 Attach the 5V power supply to J5 of the E2645-66501 Device High-Speed Signal Quality test fixture.
- 2 Place the switch in the test switch to NORMAL position. Verify the green Power LED(D1) is lit, and the yellow Test LED(D2) is off.
- 3 Connect the [TEST PORT] of the test fixture into the upstream facing port of the device under test, using the 4" USB cable.
- 4 Connect the [INIT PORT] of the test fixture to a port of the Test Bed Computer, using the 5 meter cable.



- 5 Check I have completed these instructions.

## Running the Tests

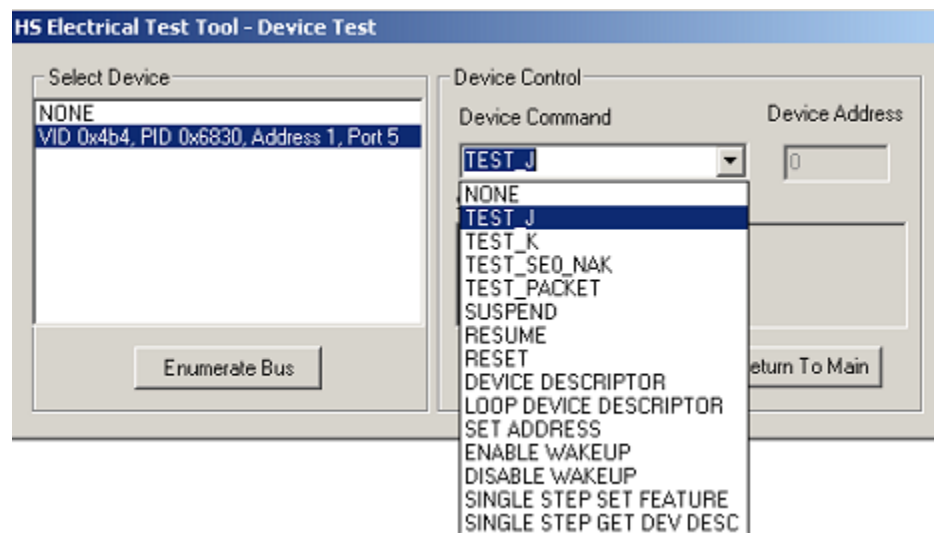
- 1 Click **Run Tests**.

## Test Instructions

### EL\_8 J Test

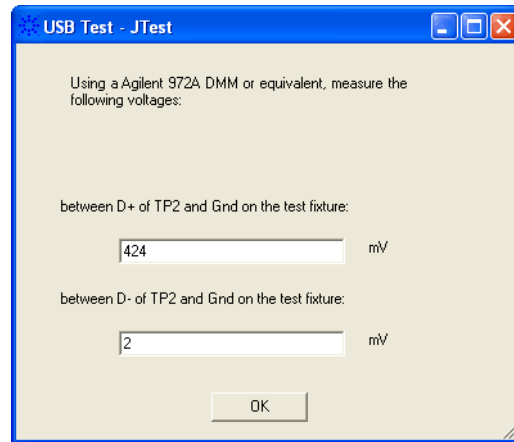
The USB automated test application will prompt you to perform these steps:

- 1 On the Device Test Menu of the HS Electrical Test Tool, click [**Enumerate Bus**] once.
- 2 Select **TEST\_J** from the Device Command drop down menu. Click [**EXECUTE**] once to place the device into TEST\_J test mode.
- 3 Switch the test fixture into the **TEST** position.



- 4 Click **OK** to close the Test Instructions dialog.

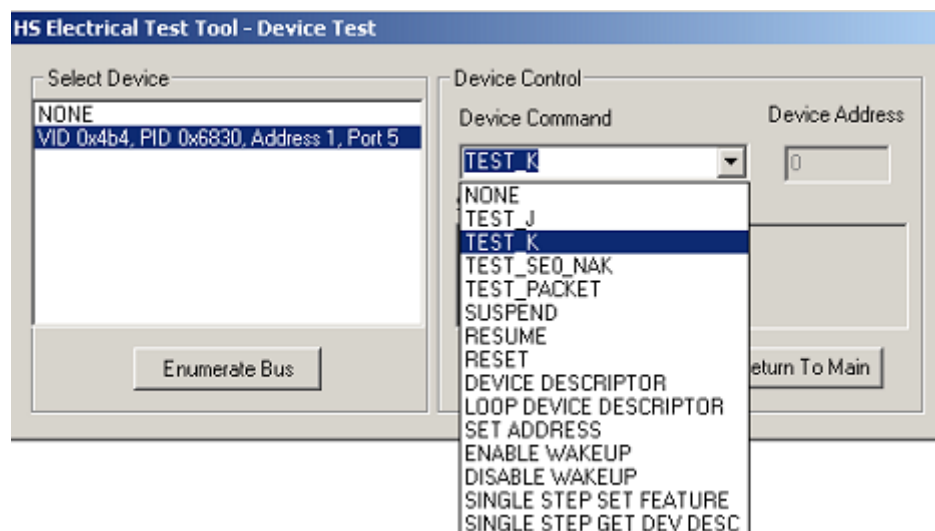
The USB automated test application will prompt you for the following voltage measurements:



### EL\_8 K Test

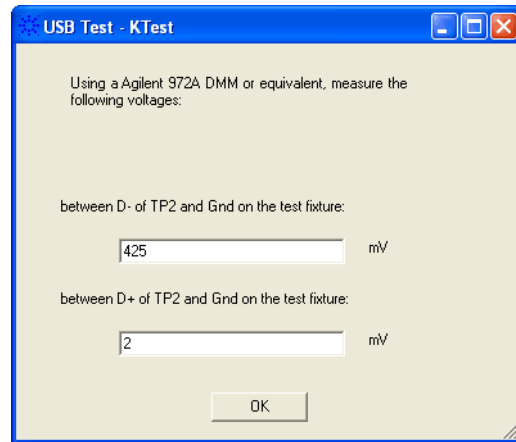
The USB automated test application will prompt you to perform these steps:

- 1 Return the Test switch of the test fixture to the **NORMAL** position.
- 2 Cycle the device power to restore the device to normal operation. On the Device Test Menu of the HS Electrical Test Tool, click [**Enumerate Bus**] once.
- 3 Select **TEST\_K** from the Device Command drop down menu. Click [**EXECUTE**] once to place the device into TEST\_K test mode.
- 4 Switch the test fixture into the **TEST** position.



- 5 Click **OK** to close the Test Instructions dialog.

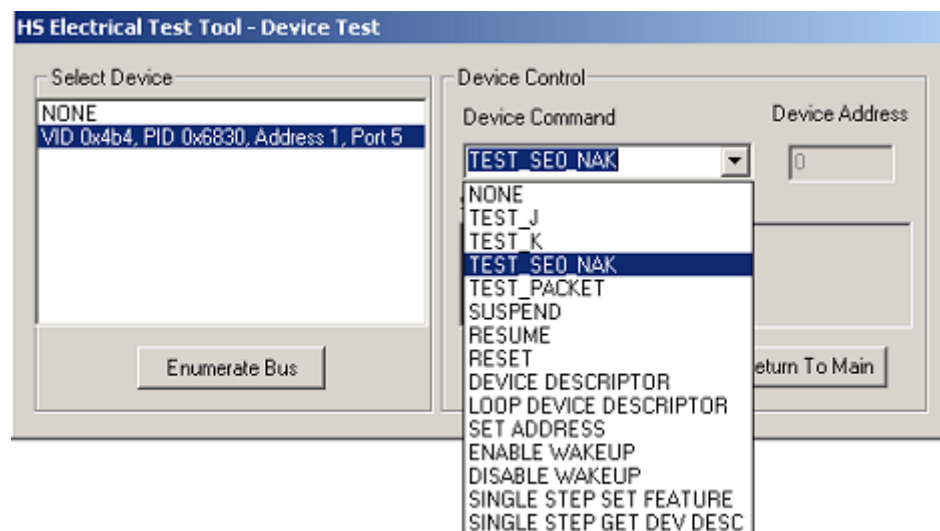
The USB automated test application will prompt you for the following voltage measurements:



#### EL\_9 SE0\_NAK Test

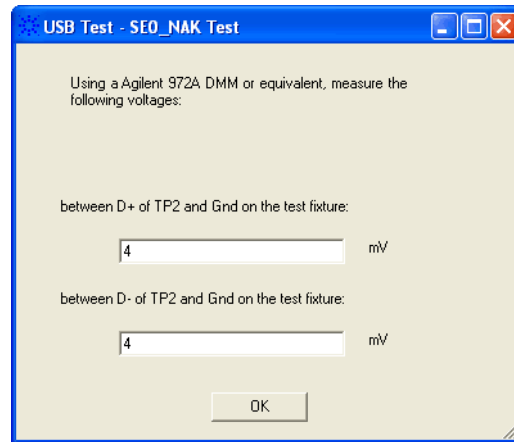
The USB automated test application will prompt you to perform these steps:

- 1 Return the Test switch of the test fixture to the **NORMAL** position.
- 2 Cycle the device power to restore the device to normal operation. On the Device Test Menu of the HS Electrical Test Tool, click [**Enumerate Bus**] once.
- 3 Select **TEST\_SE0\_NAK** from the Device Command drop down menu. Click [**EXECUTE**] once to place the device into TEST\_SE0\_NAK test mode.
- 4 Switch the test fixture into the **TEST** position.



- 5 Click **OK** to close the Test Instructions dialog.

The USB automated test application will prompt you for the following voltage measurements:



USB Test - SE0\_NAK Test

Using a Agilent 972A DMM or equivalent, measure the following voltages:

between D+ of TP2 and Gnd on the test fixture:

4 mV

between D- of TP2 and Gnd on the test fixture:

4 mV

OK

## Viewing Test Results

- 1 When the Testing Complete dialog appears, click **OK**.

The Results tab shows the test results.

## Device Receiver Sensitivity

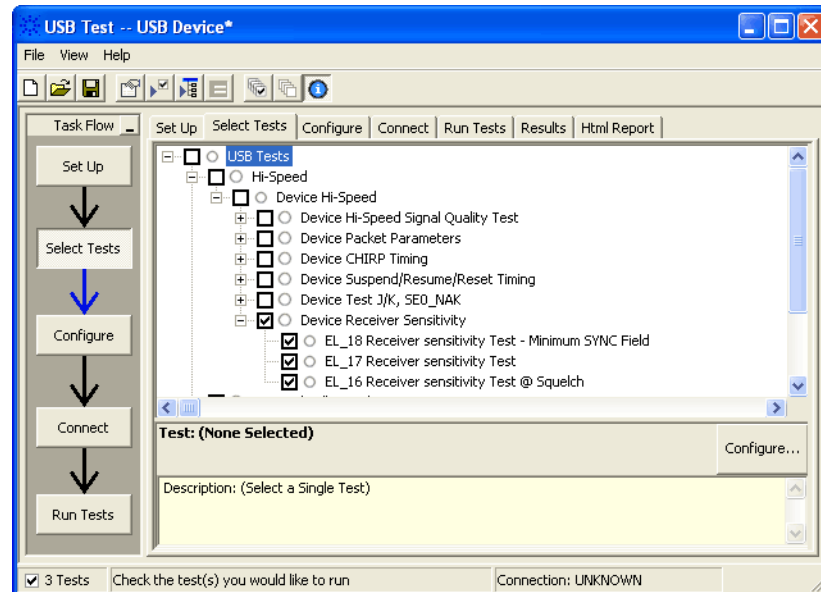
### Equipment Used

**Table 12** Equipment Used in Device Receiver Sensitivity Tests

Quantity	Item	Description/Model
1	Oscilloscope	Agilent 5485xA Series or DS080000 Series
1	Differential probe	Agilent 113xA with E2699A or E2678A
1	Header adapter	Agilent 01131-68703
1	Host test bed computer	Any computer with hi-speed USB ports
1	Receiver Sensitivity test fixture and 4" USB cable	Agilent E2645-66503
1	5V power supply	Agilent 0950-2546 or equivalent
1	Digital signal generator	Agilent 81130A (or 81134A with two 15432B transition time converters connected to the pulse generator outputs)
1	USB/GPIB interface	Agilent 82357A
2	6 dB attenuators	Agilent 8493C
2	50 ohm coaxial cable with male SMA connectors at both ends	Agilent 8120-4948 or equivalent
1	5 meter USB 2.0 hi-speed cable	Any listed on USB-IF web site



## Selecting the Tests



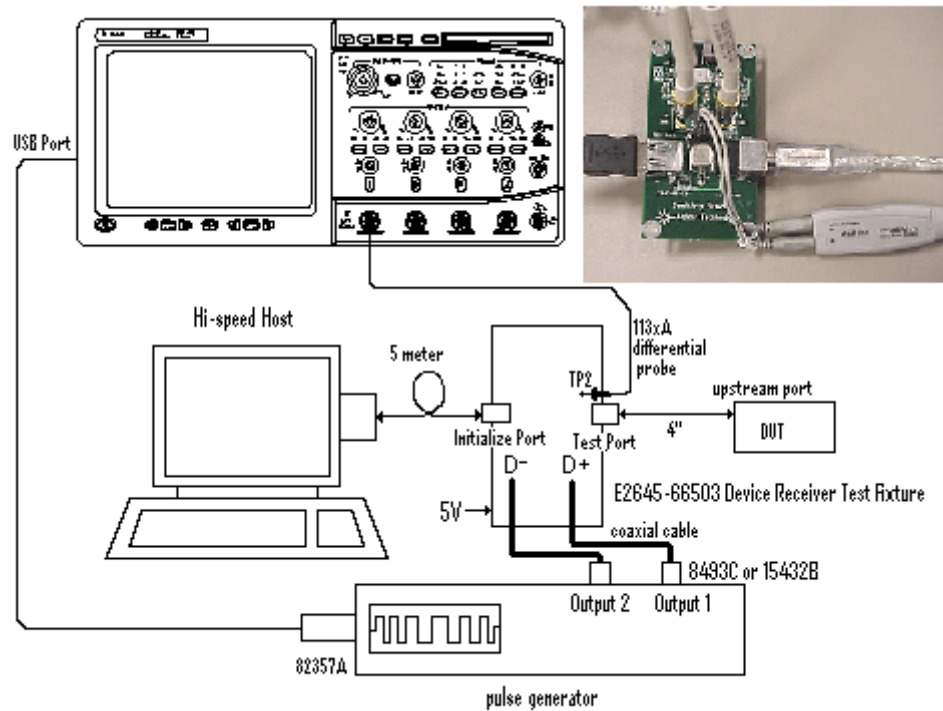
## Configuring the Tests

If the pulse generator's SICL address is different from the default, make sure you set the 81134A/81130A Instrument Address configuration option to the pulse generator's SICL address.

See also [“Configuring the 81134A pulse generator using the 82357A GPIB-USB converter”](#) on page 89.

## Connecting the Equipment

The USB automated test application will prompt you to perform these connection steps:



- 1 Attach the 5V power supply to the E2645-66503 Device Receiver test fixture (J5).
  - a Verify the green Power LED (D1) is lit.
  - b Leave the TEST switch at the Normal position (S1).
  - c The yellow LED (D2) should be off.
- 2 Connect the [INIT PORT] of the fixture to a Hi-Speed port on the Test Bed Computer, using the 5 meter USB cable.
- 3 Connect the [TEST PORT] of the fixture to the device under test, using the 4" USB cable.
- 4 Connect the differential probe to the test fixture at TP2, using the 01131-68703 header adapter. Note: Ensure the + polarity on the probe lines up with D+, which is the pin nearest the USB connector.

- 5 Connect the 81130A or 81134A pulse generator to the oscilloscope using the 82357A USB/GPIB Interface.
  - a If you choose to use the Agilent 81130A Pulse/Pattern Generator, connect the 8493C 6dB attenuators to OUTPUT1 and OUTPUT2 of Agilent 81130A Pulse/Pattern Generator.
  - b If you choose to use the Agilent 81134A Pulse/Pattern Generator, connect the 15432B Transition Time Converters to OUTPUT1 and OUTPUT2 of Agilent 81134A Pulse/Pattern Generator. Agilent 15432B Transition Time Converters are recommended, to reduce the output edge speed of the 81134A to speed close to what the 81130A provides.
- 6 Connect OUTPUT1 to SMA1 (D+) of the E2645-66503 Device Receiver Sensitivity test fixture using the 8120-4948 SMA cables.
- 7 Connect OUTPUT2 to SMA2 (D-) of the E2645-66503 Device Receiver Sensitivity test fixture using the 8120-4948 SMA cables.
- 8 Check **I have completed these instructions**.

## Running the Tests

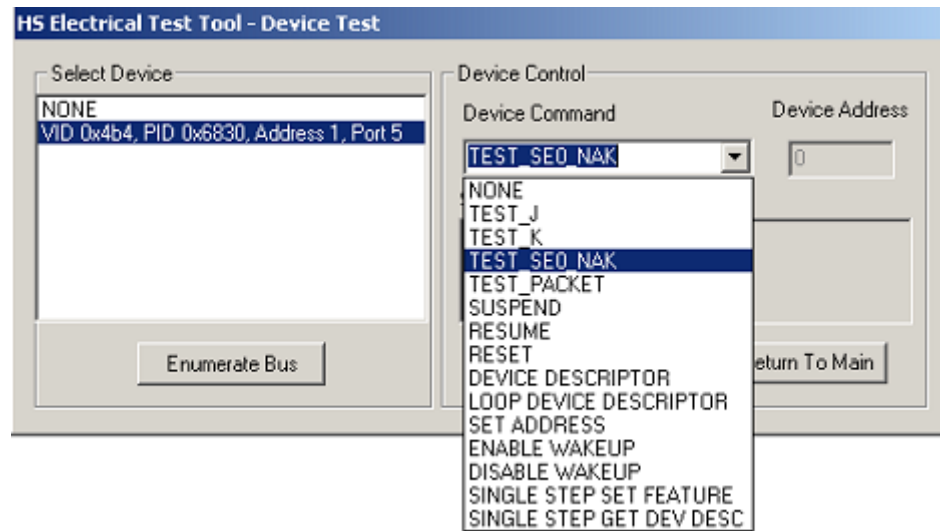
- 1 Click **Run Tests**.

## Test Instructions

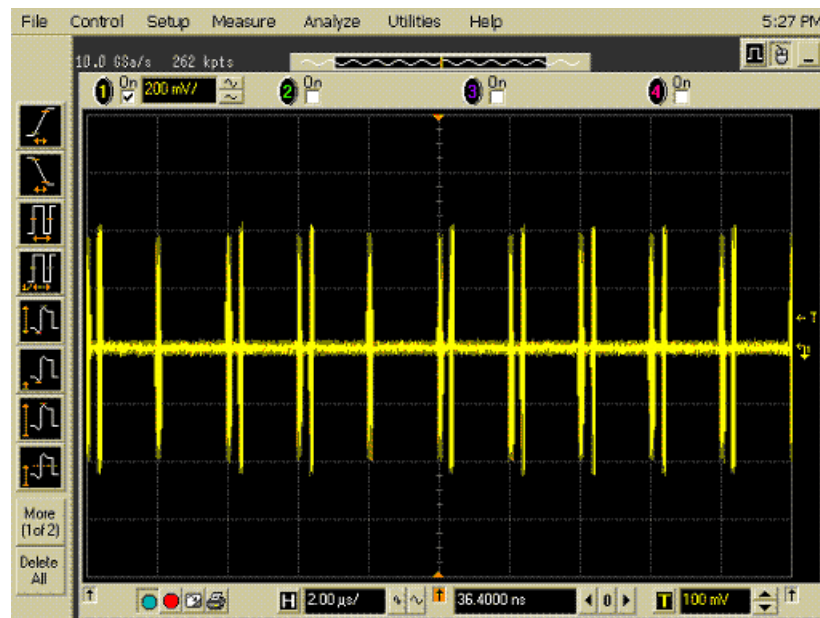
The USB automated test application will prompt you to perform these steps:

- 1 Cycle the device power to restore the device to normal operation. On the Device Test Menu of the HS Electrical Test Tool, click **[Enumerate Bus]** button once to force enumeration of the newly connected device.
- 2 Select **TEST\_SE0\_NAK** from the Device Command drop down menu. Click **[EXECUTE]** once to place the device into TEST\_SE0\_NAK test mode.

### 3 Device Hi-Speed Tests



- 3 Place the test fixture Test Switch (S1) into the **TEST** position. This switches in the data generator in place of the host controller. The data generator emulates the "IN" packets from the host controller.



- 4 Click **OK** to close the Test Instructions dialog.

**EL\_18 Receiver sensitivity Test - Minimum SYNC Field**

**EL\_17 Receiver sensitivity Test**

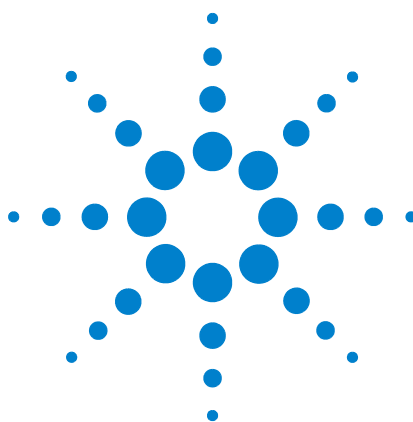
**EL\_16 Receiver sensitivity Test @ Squelch**

## **Viewing Test Results**

- 1 When the Testing Complete dialog appears, click **OK**.

The Results tab shows the test results.





## 4 Hub Hi-Speed Tests

Hub Hi-Speed Signal Quality Test - Upstream Facing Ports	65
Hub Hi-Speed Signal Quality Test - Downstream Facing Ports	69
Hub Jitter Test - Downstream Facing Ports	73
Hub Disconnect Detect	77
Hub Packet Parameters - Upstream Facing Port	81
Hub Receiver Sensitivity - Upstream Facing Port	88
Hub Repeater Test - Downstream Facing Port	97
Hub Repeater Test - Upstream Facing Port	102
Hub CHIRP Timing - Upstream Facing Port	108
Hub Suspend/Resume/Reset Timing - Upstream Facing Port	111
Hub Test J/K, SE0_NAK - Upstream Facing Port	119
Hub Test J/K, SE0_NAK - Downstream Facing Port	124

### NOTE

To give the automated test software more flexibility in making corner case measurements (and improve test performance), the oscilloscope's memory upgrade option is recommended (Option 001 when ordered with the oscilloscope, or after purchase: E2680A for the 5485xA Series oscilloscopes, or N5404A for the DSO80000 Series oscilloscopes).

Also, to reduce the bandwidth of the oscilloscope to just what is required by the USB-IF (2 GHz for USB 2.0)—this can greatly reduce system measurement noise, allowing the maximum measurement margin—the enhanced bandwidth software option is recommended for the Agilent 54855A oscilloscope (Option 008), and the noise reduction software option is recommended for the DSO80000 Series oscilloscopes (Option 005 when ordered with the oscilloscope or N5403A after purchase).

In addition to the high-speed electrical tests prescribed in this chapter, the hub under test must also pass the following legacy electrical compliance tests applicable to the high-speed hub:

- Full speed signal quality – Upstream and downstream facing ports.
- Low speed signal quality – Downstream facing ports only.
- Inrush current – Upstream facing port only.
- Drop/Droop – Downstream facing ports.



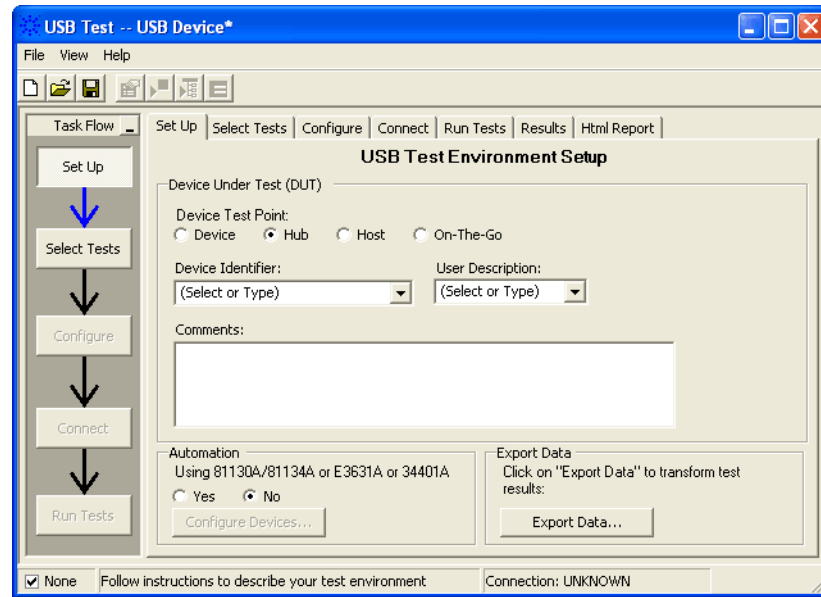
- Back-voltage.

### Before Running These Tests

If you haven't already performed the initial equipment set up, see "[Setting Up the Equipment](#)" on page 19.

### Selecting the Hub Test Environment Setup

- 1 In the USB automated test application, select the **Hub** test environment.





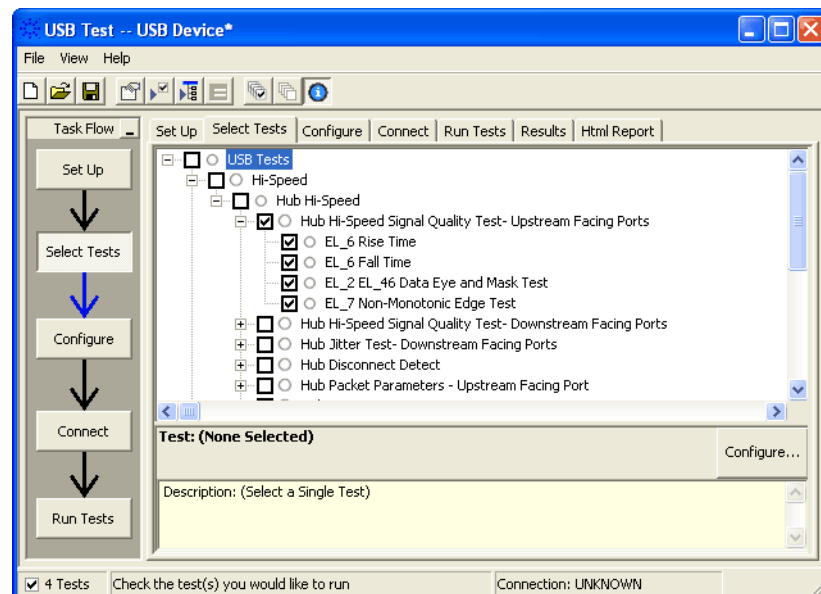
## Hub Hi-Speed Signal Quality Test - Upstream Facing Ports

### Equipment Used

**Table 13** Equipment Used in Hub Hi-Speed Signal Quality Test - Upstream Facing Ports

Quantity	Item	Description/Model
1	Oscilloscope	Agilent 5485xA Series or DS080000 Series
1	Differential probe	Agilent 113xA with E2699A or E2678A
1	Header adapter	Agilent 01131-68703
1	Host test bed computer	Any computer with hi-speed USB ports
1	Device Hi-Speed Signal Quality test fixture and 4" USB cable	Agilent E2645-66501
1	5V power supply	Agilent 0950-2546 or equivalent
1	5 meter USB 2.0 hi-speed cable	Any listed on USB-IF web site

### Selecting the Tests

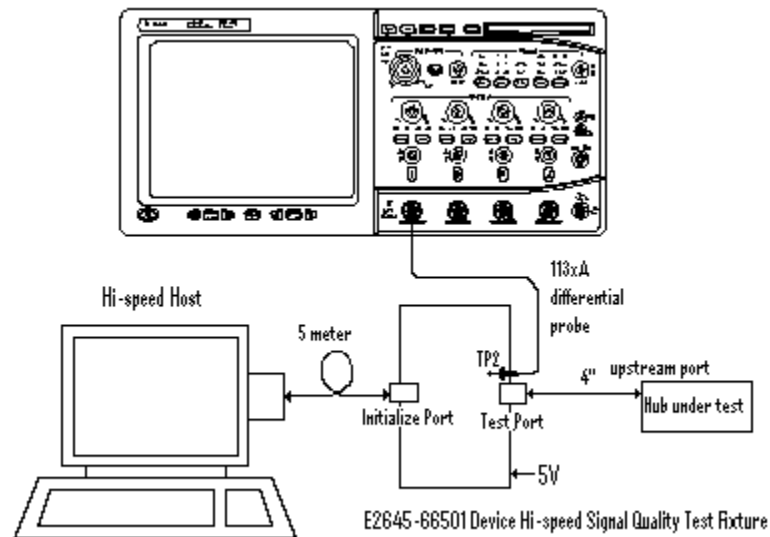


## Configuring the Tests

### Connecting the Equipment

The USB automated test application will prompt you to perform these connection steps:

- 1 Attach the 5V power supply to J5 of the E2645-66501 Device Hi-Speed Signal Quality test fixture. Verify green Power LED (D1) is lit, and yellow test LED (D2) is off.
- 2 Connect the [TEST PORT] of the test fixture into the upstream facing port of the hub under test, using the 4" USB cable.
- 3 Connect the [INIT PORT] of the test fixture to a hi-speed port of the Test Bed Computer, using a 5 meter cable. Apply power to the hub.
- 4 Attach the differential probe to TP2 of the test fixture, using the header adapter. Ensure the + polarity on the probe lines up with D+ on the fixture, located near the USB connector.



- 5 Check I have completed these instructions.

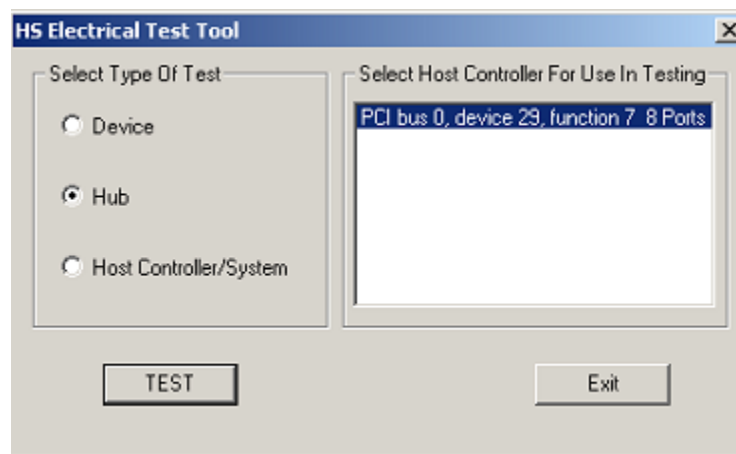
## Running the Tests

- 1 Click **Run Tests**.

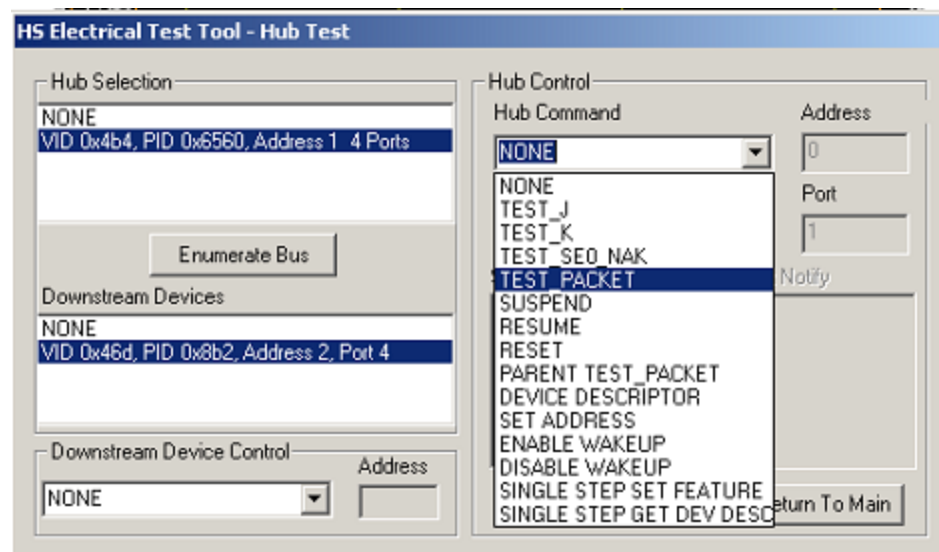
### Test Instructions, Part 1

The USB automated test application will prompt you to perform these steps:

- 1 Invoke the HS Electrical Test Tool software on the Hi-Speed Electrical Test Bed computer. Select **Hub** and click the **[TEST]** button to enter the Hub Test menu.



- 2 The hub under test should be enumerated with the hub's VID shown together with the USB address. Select **[TEST\_PACKET]** from the Hub Command drop down menu and click **[EXECUTE]**.

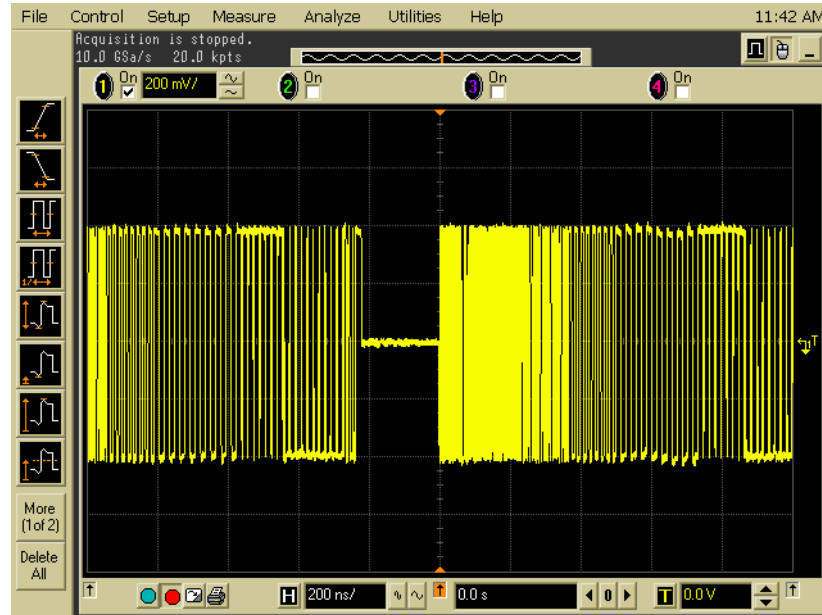


- 3 Click **OK** to close the Test Instructions dialog.

## Test Instructions, Part 2

The USB automated test application will prompt you to perform these steps:

- 1 Place the Test Switch (S1) of the test fixture in the **TEST** position. Verify the yellow TEST LED is lit. You should see the transmitted test packet on the oscilloscope as below.



- 2 Click **OK** to close the Test Instructions dialog.

### EL\_6 Rise Time

### EL\_6 Fall Time

### EL\_2 EL\_46 Data Eye and Mask Test

After viewing the test results, click **OK** to close the Test Instructions dialog.

### EL\_7 Non-Monotonic Edge Test

## Viewing Test Results

- 1 When the Testing Complete dialog appears, click **OK**.

The Results tab shows the test results.

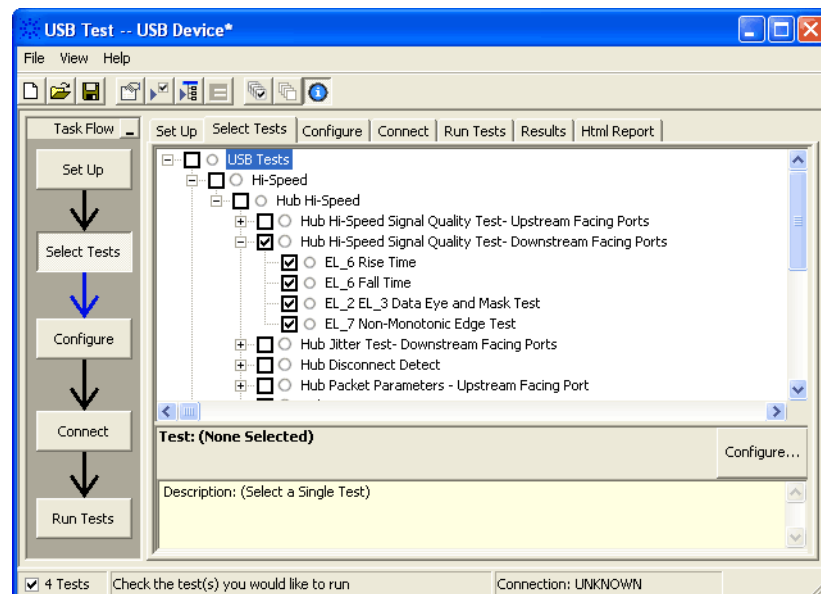
## Hub Hi-Speed Signal Quality Test - Downstream Facing Ports

### Equipment Used

**Table 14** Equipment Used in Hub Hi-Speed Signal Quality Test - Downstream Facing Ports

Quantity	Item	Description/Model
1	Oscilloscope	Agilent 5485xA Series or DS080000 Series
1	Differential probe	Agilent 113xA with E2699A or E2678A
1	Header adapter	Agilent 01131-68703
1	Host test bed computer	Any computer with hi-speed USB ports
1	Host Hi-Speed Signal Quality test fixture and 4" USB cable	Agilent E2645-66502
1	5V power supply	Agilent 0950-2546 or equivalent
1	5 meter USB 2.0 hi-speed cable	Any listed on USB-IF web site

### Selecting the Tests

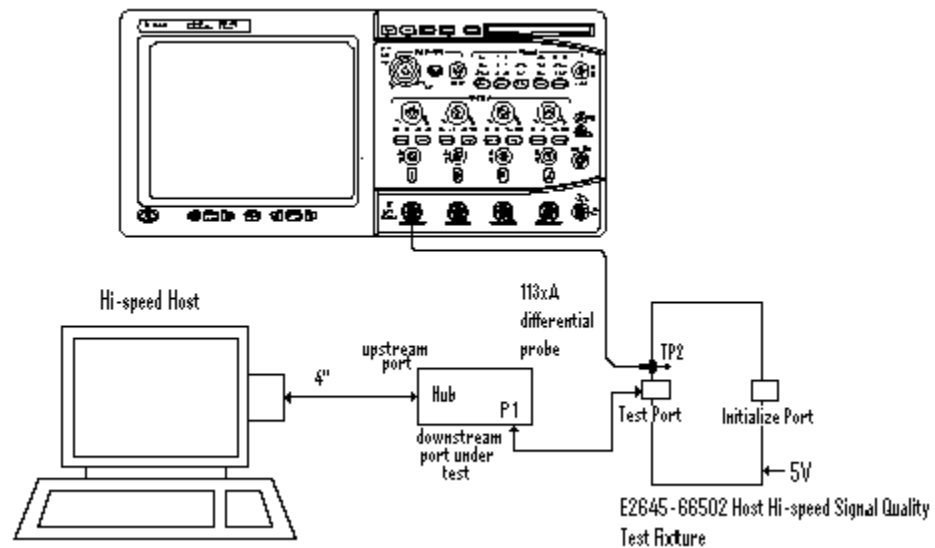


## Configuring the Tests

### Connecting the Equipment

The USB automated test application will prompt you to perform these connection steps:

- 1 Attach the 5V power supply to J5 of the E2645-66502 Host Hi-Speed Signal Quality test fixture. Set the Test switch to the TEST position. Verify green Power LED (D1) and yellow test LED (D2) are both lit.
- 2 Attach the differential probe to TP2 of the test fixture, using the header adapter. Ensure the + polarity on the probe lines up with D+ on the fixture, located nearest to the USB connector.
- 3 Connect the upstream port of the hub to a high-speed root port of the test bed computer.
- 4 Connect the [TEST PORT] of the test fixture into the down stream facing port under the test of the hub. Apply power to the hub.



- 5 Check I have completed these instructions.

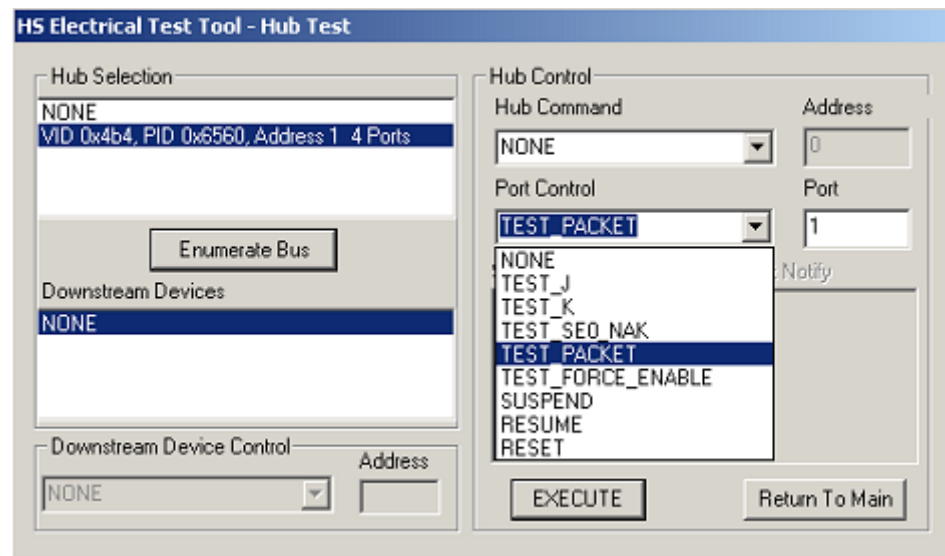
## Running the Tests

- 1 Click **Run Tests**.

## Test Instructions

The USB automated test application will prompt you to perform these steps:

- 1 On the Hub Test menu of the HS Electrical Test Tool, click the [**Enumerate Bus**] button once. The hub under test should be enumerated with the hub's VID shown together with the USB address.
- 2 Select **TEST\_PACKET** from the Port Control drop down menu.
- 3 Enter the port number of the hub port being tested and click [**EXECUTE**].



- 4 Click **OK** to close the Test Instructions dialog.

### EL\_6 Rise Time

### EL\_6 Fall Time

### EL\_2 EL\_3 Data Eye and Mask Test

After viewing the test results, click **OK** to close the Test Instructions dialog.

### EL\_7 Non-Monotonic Edge Test

## **Viewing Test Results**

- 1**    When the Testing Complete dialog appears, click **OK**.

The Results tab shows the test results.



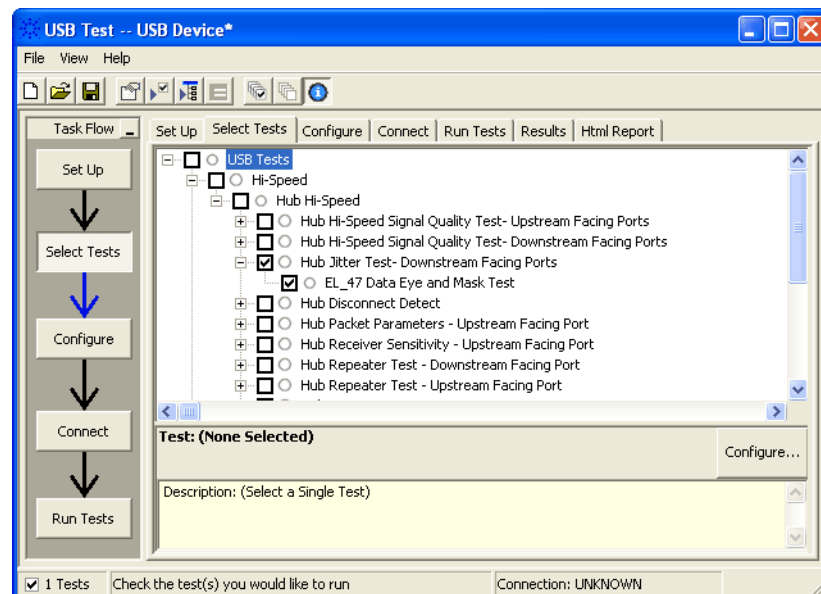
## Hub Jitter Test - Downstream Facing Ports

### Equipment Used

**Table 15** Equipment Used in Hub Jitter Test - Downstream Facing Ports

Quantity	Item	Description/Model
1	Oscilloscope	Agilent 5485xA Series or DS080000 Series
1	Differential probe	Agilent 113xA with E2699A or E2678A
1	Header adapter	Agilent 01131-68703
1	Host test bed computer	Any computer with hi-speed USB ports
1	Host Hi-Speed Signal Quality test fixture and 4" USB cable	Agilent E2645-66502
1	5V power supply	Agilent 0950-2546 or equivalent
1	5 meter USB 2.0 hi-speed cable	Any listed on USB-IF web site

### Selecting the Tests

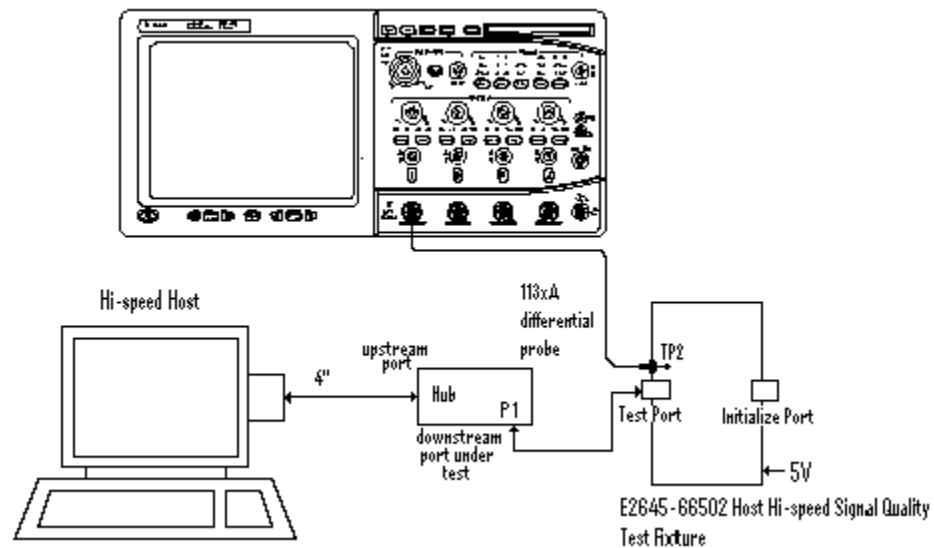


## Configuring the Tests

### Connecting the Equipment

The USB automated test application will prompt you to perform these connection steps:

- 1 Attach the 5V power supply to J5 of the E2645-66502 Host Hi-Speed Signal Quality test fixture. Set the Test switch to the TEST position. Verify green Power LED (D1) and yellow test LED (D2) are both lit.
- 2 Attach the differential probe to TP2 of the test fixture, using the header adapter. Ensure the + polarity on the probe lines up with D+ on the fixture, located nearest to the USB connector.
- 3 Connect the upstream port of the hub to a high-speed root port of the test bed computer.
- 4 Connect the [TEST PORT] of the test fixture into the down stream facing port under the test of the hub. Apply power to the hub.



- 5 Check I have completed these instructions.

## Running the Tests

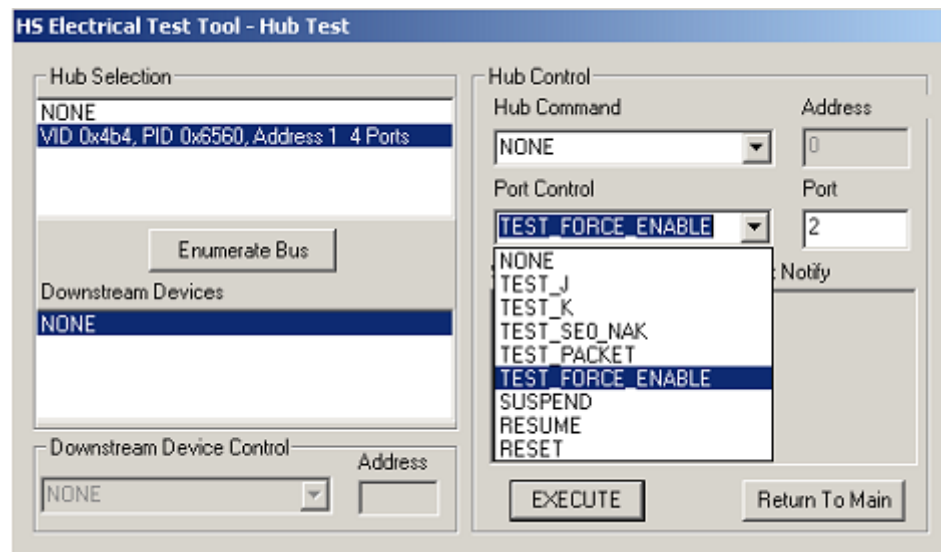
- 1 Click **Run Tests**.

## Test Instructions

### EL\_47 Data Eye and Mask Test

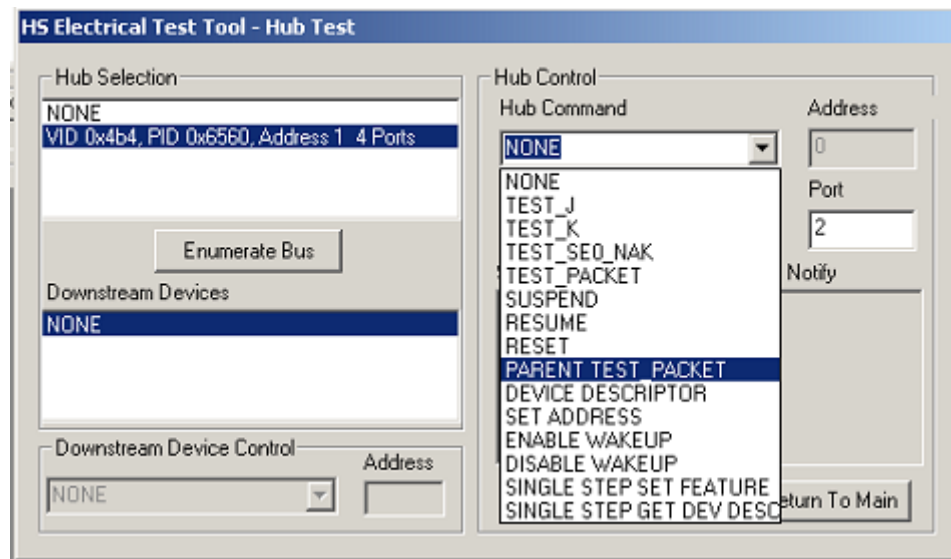
The USB automated test application will prompt you to perform these steps:

- 1 On the Hub Test menu of the HS Electrical Test Tool, click **[Enumerate Bus]** once.
- 2 Select **TEST\_FORCE\_ENABLE** from the Port Control drop down menu.
- 3 Enter the port number of the hub port being tested and click **[EXECUTE]** once to force-enable the hub port under test.



- 4 Select **PARENT TEST\_PACKET** from the Hub Command drop down menu and click **[EXECUTE]**.

## 4 Hub Hi-Speed Tests



- 5 Click **OK** to close the Test Instructions dialog.

After viewing the test results, click **OK** to close the Test Instructions dialog.

### Viewing Test Results

- 1 When the Testing Complete dialog appears, click **OK**.

The Results tab shows the test results.

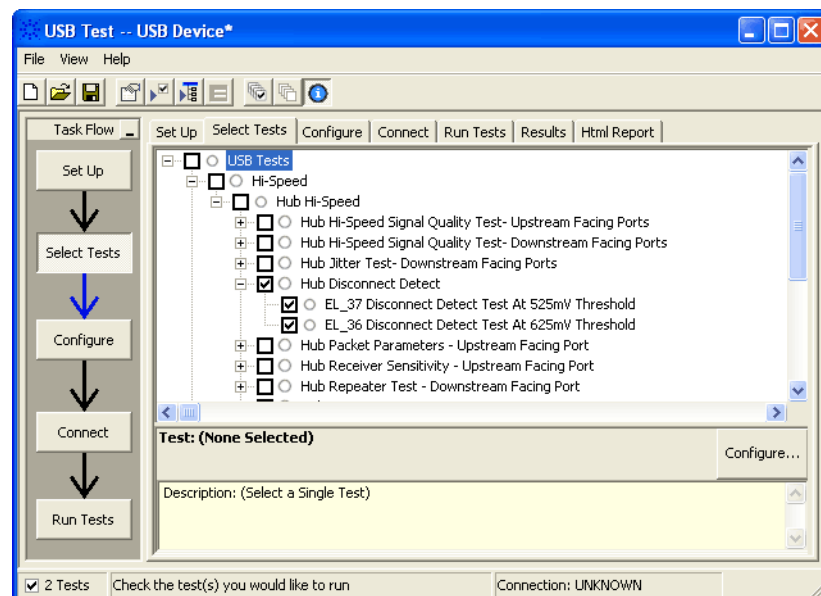
## Hub Disconnect Detect

### Equipment Used

**Table 16** Equipment Used in Hub Disconnect Detect

Quantity	Item	Description/Model
1	Oscilloscope	Agilent 5485xA Series or DS080000 Series
1	Differential probe	Agilent 113xA with E2699A or E2678A
1	Header adapter	Agilent 01131-68703
1	Host test bed computer	Any computer with hi-speed USB ports
1	Host Disconnect test fixture and 4" USB cable	Agilent E2645-66506
1	5V power supply	Agilent 0950-2546 or equivalent
1	5 meter USB 2.0 hi-speed cable	Any listed on USB-IF web site

### Selecting the Tests

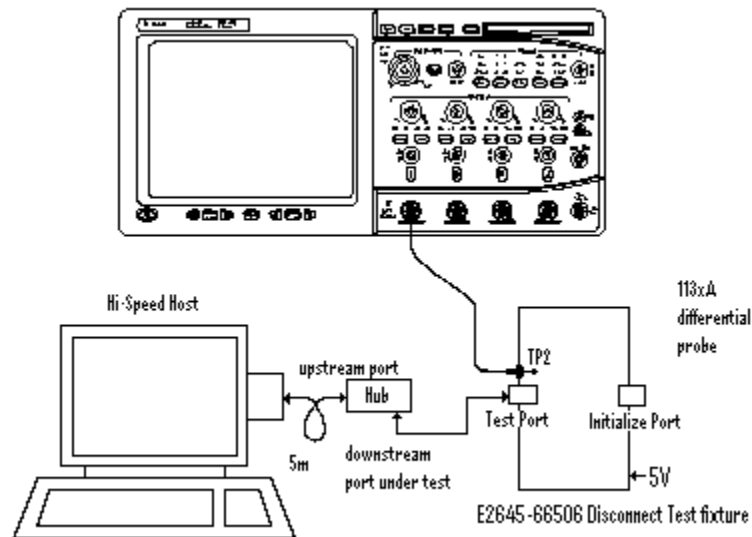


## Configuring the Tests

### Connecting the Equipment

The USB automated test application will prompt you to perform these connection steps:

- 1 Attach the 5V power supply to E2645-66506 Disconnect test fixture (J5).
- 2 Attach the Agilent 113xA differential probe to TP2 of the test fixture, using a damped header adapter. Ensure the + polarity on the probe lines up with D+, which is the pin nearest the USB connector.
- 3 Set the Test switch to the TEST position. This sets the test fixture to emulate a must-not-disconnect threshold.
  - a Verify both the green Power LED (D1) and yellow Test LED (D2) are lit
- 4 Cycle power on the hub under test. Connect the upstream port of the hub to the host computer, using the 5 meter USB cable.



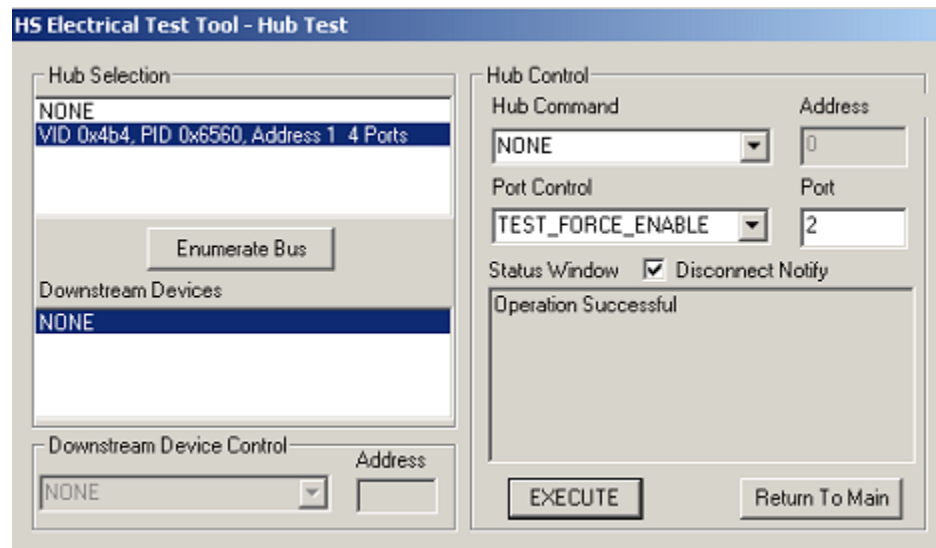
- 5 Check I have completed these instructions.

## Running the Tests

- 1 Click **Run Tests**.

## Test Instructions

- 1 In the Hub Test menu of the HS Electrical Test Tool, click [**Enumerate Bus**] once and verify the hub successfully enumerates.
- 2 Attach the [TEST PORT] of the test fixture to the port under test.
- 3 From the Port Control window of the Hub Test menu, select **TEST\_FORCE\_ENABLE**.
- 4 Enter the port number and click [**EXECUTE**] once and ensure operation is successful in the Status Window.
- 5 Click the **Disconnect Notify** check box to monitor the disconnect status in the Status Window.



- 6 Click **OK** to close the Test Instructions dialog.

### EL\_37 Disconnect Detect Test At 525mV Threshold

The USB automated test application will prompt you to answer the question “Does the Status Window display Disconnect Event Detected?”

### EL\_36 Disconnect Detect Test At 625mV Threshold

The USB automated test application will prompt you to: Set the Test switch of the E2645-66506 Disconnect test fixture to the Normal position and verify the yellow TEST LED (D2) is not lit.

The USB automated test application will prompt you to answer the question “Does the Status Window now display Disconnect Event Detected?”

### Viewing Test Results

- 1 When the Testing Complete dialog appears, click **OK**.

The Results tab shows the test results.



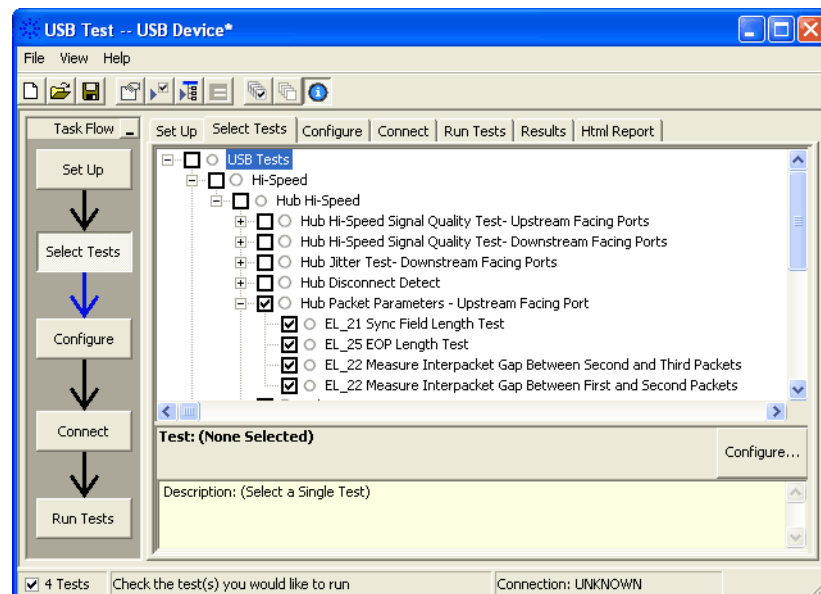
## Hub Packet Parameters - Upstream Facing Port

### Equipment Used

**Table 17** Equipment Used in Hub Packet Parameters - Upstream Facing Port

Quantity	Item	Description/Model
1	Oscilloscope	Agilent 5485xA Series or DS080000 Series
1	Differential probe	Agilent 113xA with E2699A or E2678A
1	Header adapter	Agilent 01131-68703
1	Host test bed computer	Any computer with hi-speed USB ports
1	Device Hi-Speed Signal Quality test fixture and 4" USB cable	Agilent E2645-66501
1	5V power supply	Agilent 0950-2546 or equivalent
1	5 meter USB 2.0 hi-speed cable	Any listed on USB-IF web site

### Selecting the Tests



## Configuring the Tests

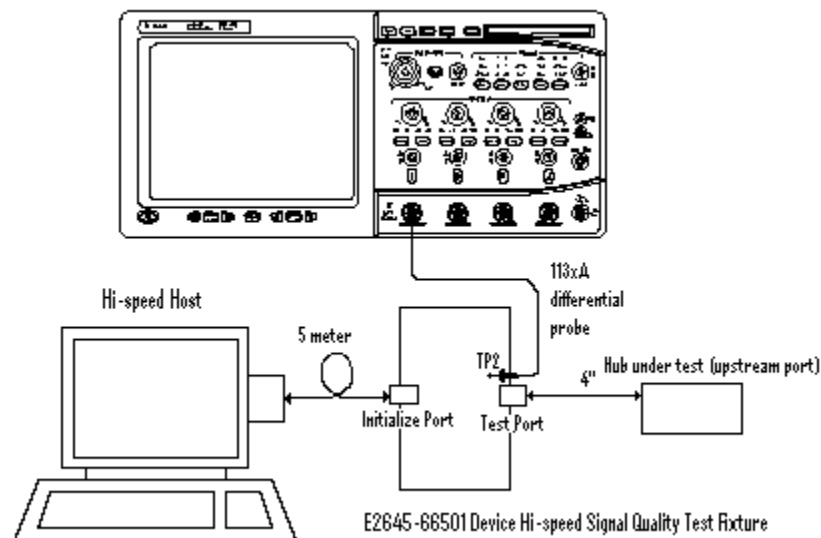
### Connecting the Equipment

The USB automated test application will prompt you to perform these connection steps:

- 1 Connect the E2645-66501 Device Hi-Speed Signal Quality test fixture [INIT PORT] into a high-speed capable port of the test bed, using the 5 meter USB cable. Do not apply 5V to the test fixture.
- 2 Connect the test fixture [TEST PORT] into B receptacle of the upstream facing port under test of the hub, using the 4" USB cable. Apply power to the hub.
- 3 Attach the Agilent 113xA differential probe to TP2 of the test fixture, using a damped header adapter.

#### NOTE

Ensure the + polarity on the probe lines up with D+, which is the pin nearest the USB connector.



- 4 Check I have completed these instructions.

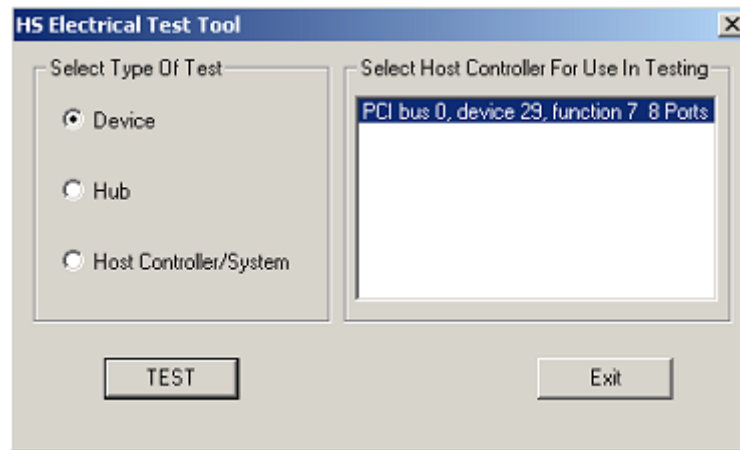
## Running the Tests

- 1 Click **Run Tests**.

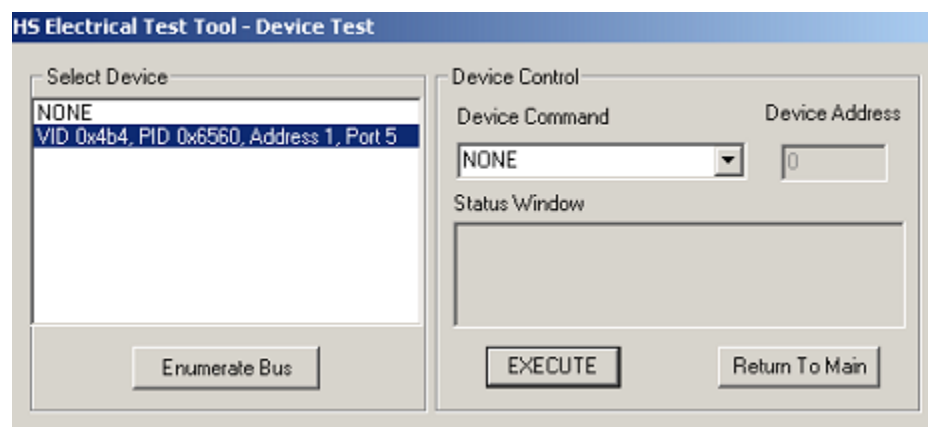
### Test Instructions, Part 1

The USB automated test application will prompt you to perform these steps:

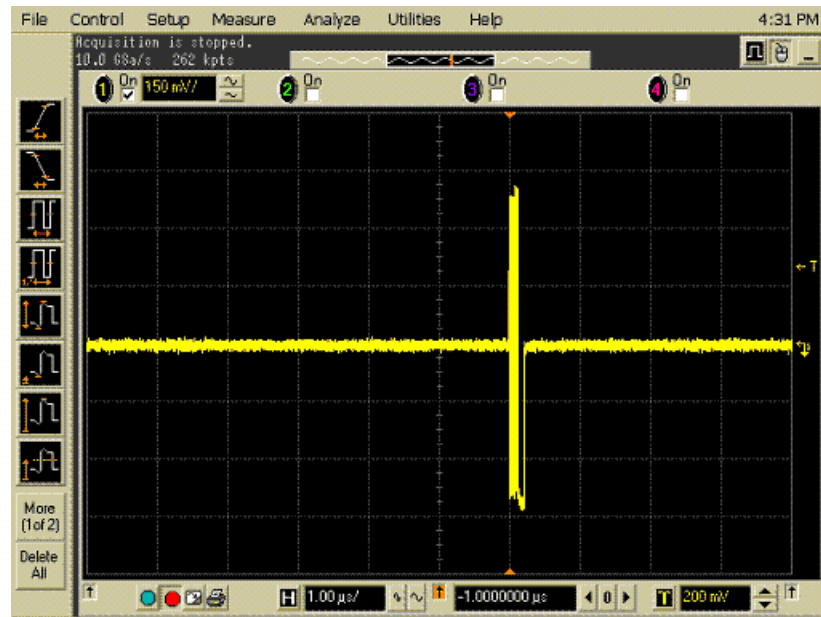
- 1 Exit the Hub Test menu of the HS Electrical Test Tool by clicking the **[Return to Main button]**.
- 2 From the HS Electrical Test Tool main menu select **Device** and click **[TEST]** to enter the Device Test menu.



- 3 The Device Test menu of the HS Electrical Test Tool should appear as below.



- 4 Using the oscilloscope, verify the SOFs (Start Of Frame) packets are being transmitted on the port under test. You may need to lower the trigger level to somewhat below 400 mV.

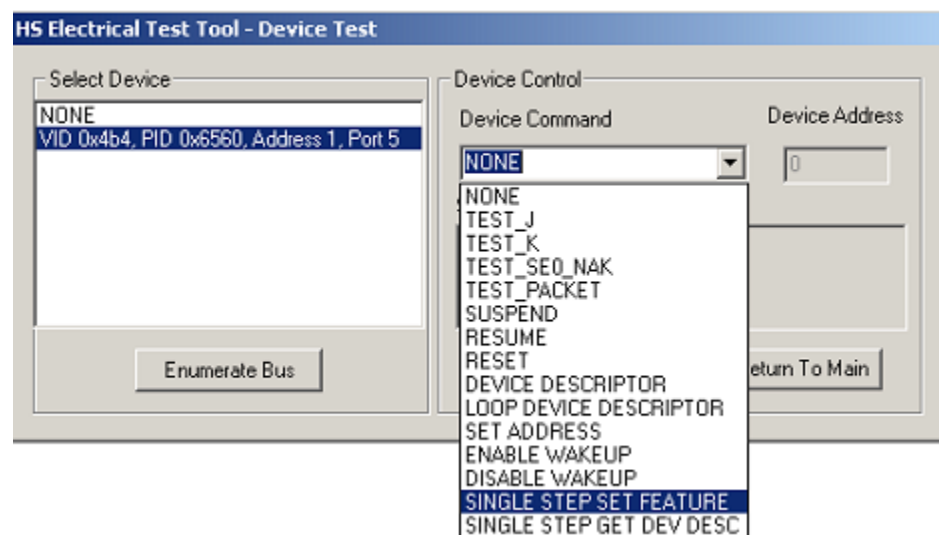


- 5 Click **OK** to close the Test Instructions dialog.

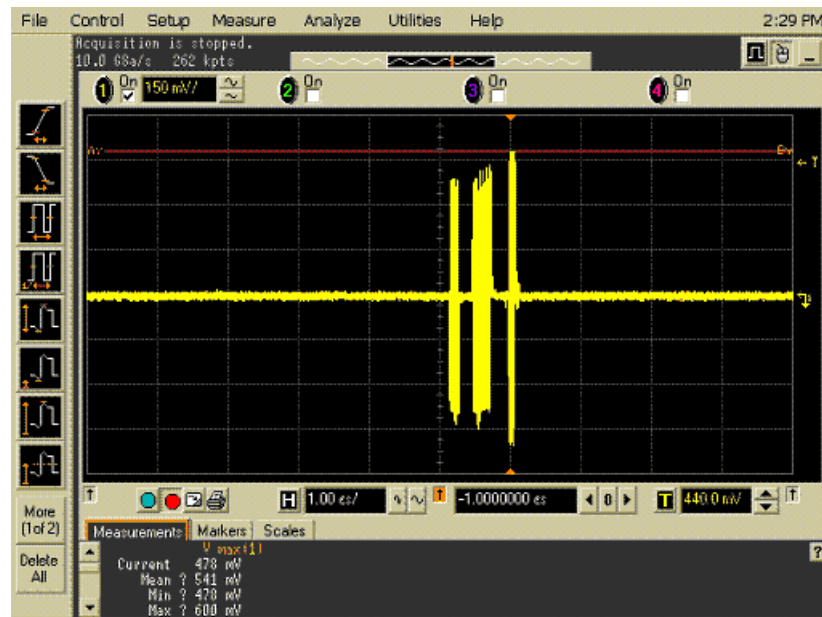
### Test Instructions, Part 2

The USB automated test application will prompt you to perform these steps:

- 1 In the Device Test menu of the HS Electrical Test Tool, ensure that the hub under test is selected.
- 2 Select **SINGLE STEP SET FEATURE** from the Device Command window. Click **[EXECUTE]** once.



- 3 You should see the transmitted test packet on the oscilloscope as below.



- 4 Click **OK** to close the Test Instructions dialog.

**EL\_21 Sync Field Length Test**

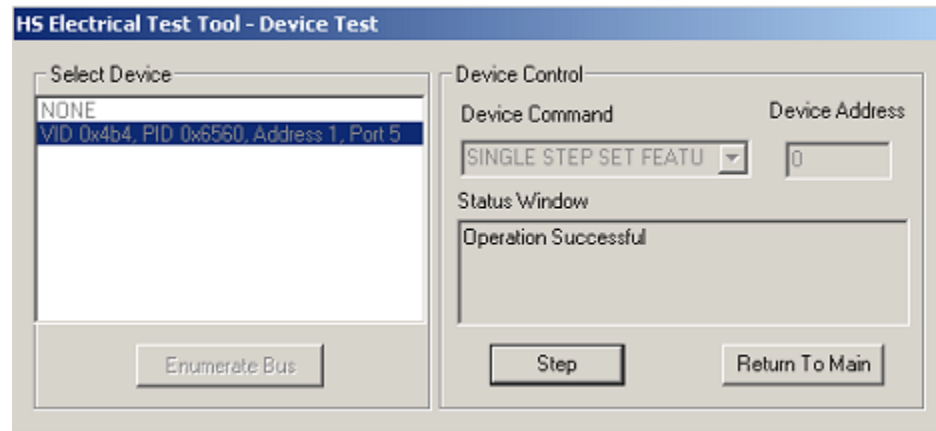
**EL\_25 EOP Length Test**

**EL\_22 Measure Interpacket Gap Between Second and Third Packets**

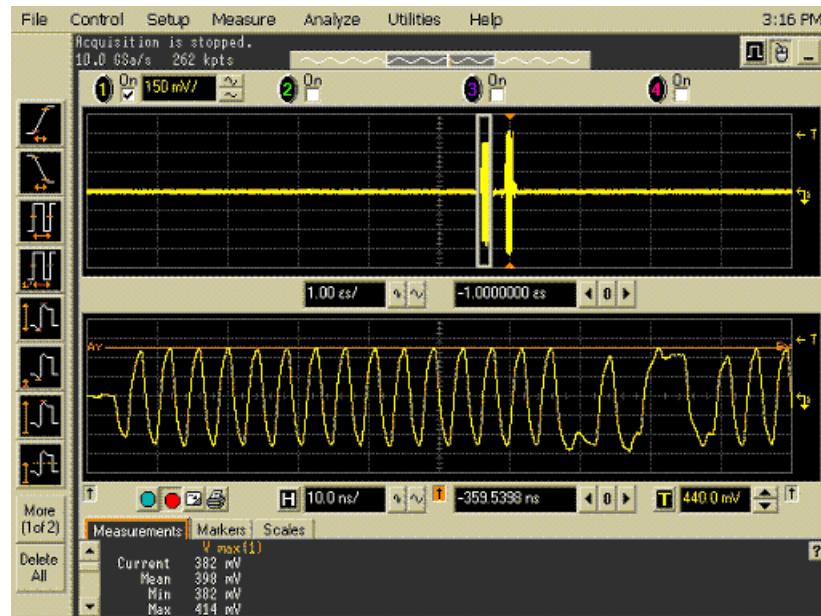
**EL\_22 Measure Interpacket Gap Between First and Second Packets**

The USB automated test application will prompt you to perform these steps:

- 1 In the Device Test menu of the HS Electrical Test Tool, click **[STEP]** once again. This is the second step of the two-step Single Step Set Feature command.



- 2 You should see the transmitted test packet on the oscilloscope as below.



- 3 Click **OK** to close the Test Instructions dialog.

## Viewing Test Results

- 1 When the Testing Complete dialog appears, click **OK**.

The Results tab shows the test results.

## Hub Receiver Sensitivity - Upstream Facing Port

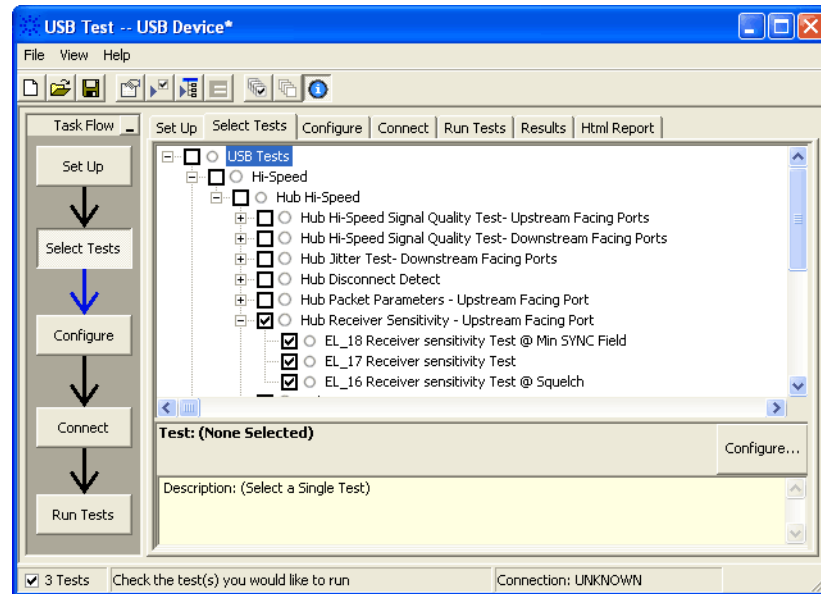
### Equipment Used

**Table 18** Equipment Used in Hub Receiver Sensitivity - Upstream Facing Port

Quantity	Item	Description/Model
1	Oscilloscope	Agilent 5485xA Series or DS080000 Series
1	Differential probe	Agilent 113xA with E2699A or E2678A
1	Header adapter	Agilent 01131-68703
1	Host test bed computer	Any computer with hi-speed USB ports
1	Receiver Sensitivity test fixture and 4" USB cable	Agilent E2645-66503
1	5V power supply	Agilent 0950-2546 or equivalent
1	Digital signal generator	Agilent 81130A (or 81134A with two 15432B transition time converters connected to the pulse generator outputs)
1	USB/GPIB interface	Agilent 82357A
2	6 dB attenuators	Agilent 8493C
2	50 ohm coaxial cable with male SMA connectors at both ends	Agilent 8120-4948 or equivalent
1	5 meter USB 2.0 hi-speed cable	Any listed on USB-IF web site



## Selecting the Tests

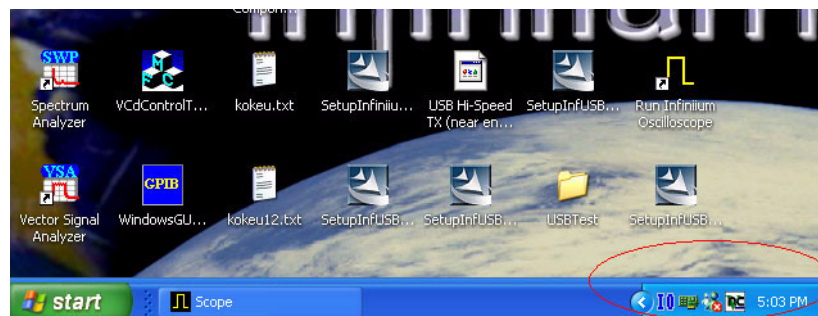


## Configuring the Tests

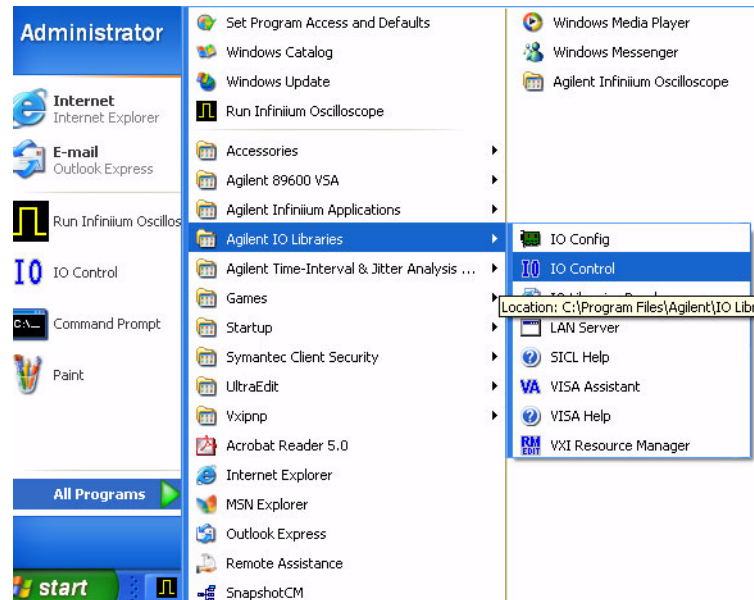
If the pulse generator's SICL address is different from the default, make sure you set the 81134A/81130A Instrument Address configuration option to the pulse generator's SICL address.

### Configuring the 81134A pulse generator using the 82357A GPIB-USB converter

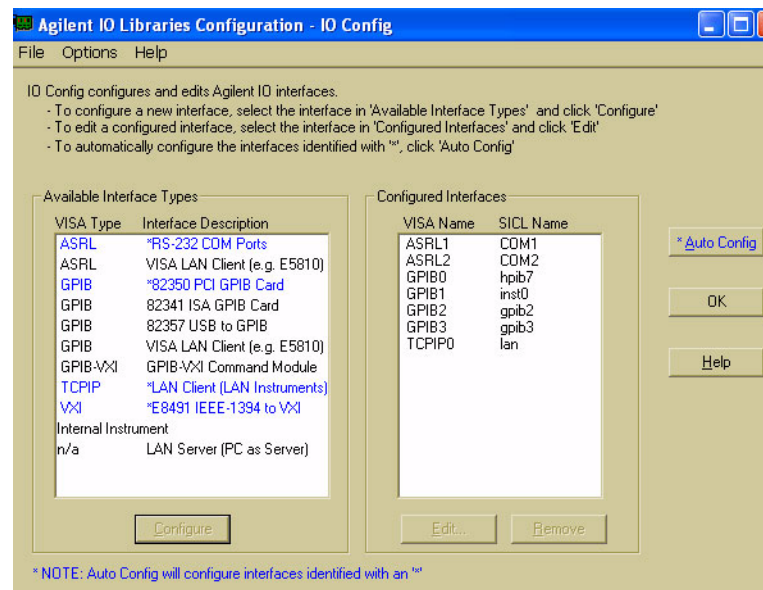
- 1 Ensure that IO Controls is already running by checking the task bar at the bottom right of the screen.



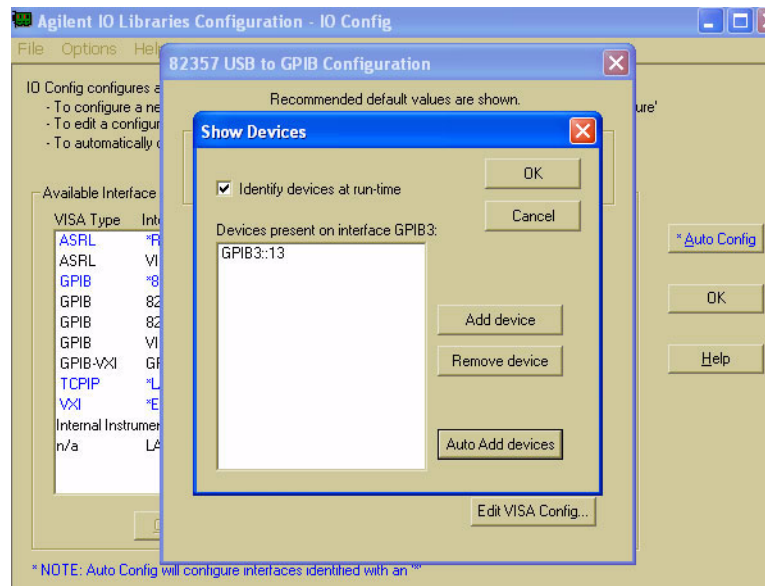
- 2 If the IO Control has not been launched, go to **Start>Programs>Agilent IO Libraries>IO Control**.



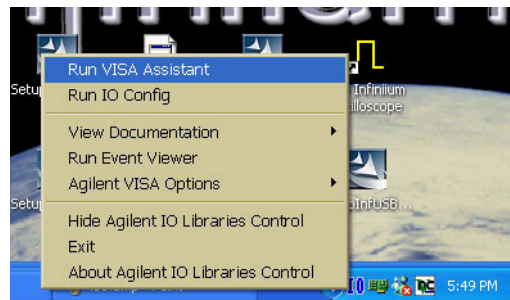
- 3 Run **IO Config>Auto Config**. This should automatically detect the 82357 device.



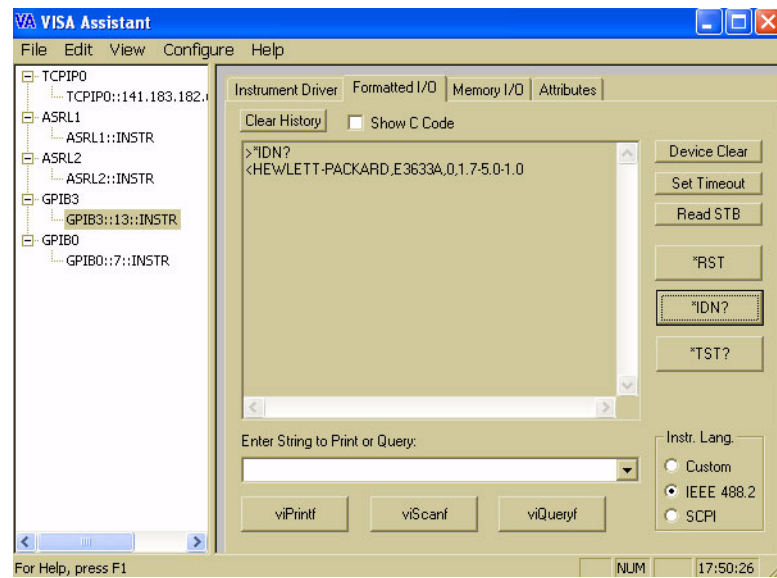
- 4 Select **GPIB# (last digit is the USB device)>Edit VISA Config...>Auto Add devices.**



- 5 Click **OK**, and close the IO Config window.
- 6 Launch VISA Assistant.

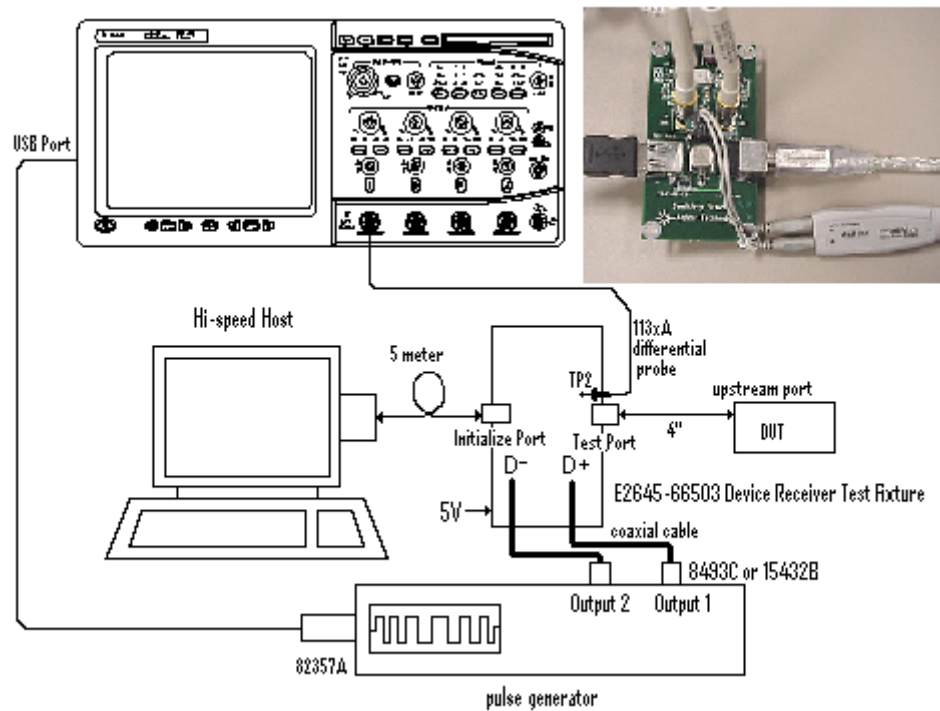


7 You can now verify the device connection.



## Connecting the Equipment

The USB automated test application will prompt you to perform these connection steps:



- 1 Attach the 5V power supply to the E2645-66503 Device Receiver test fixture (J5).
  - a Verify the green Power LED (D1) is lit.
  - b Leave the TEST switch at the Normal position (S1).
  - c The yellow LED (D2) should be off.
- 2 Connect the [INIT PORT] of the fixture to a Hi-Speed port on the Test Bed Computer, using the 5 meter USB cable.
- 3 Connect the [TEST PORT] of the fixture to the device under test, using the 4" USB cable.
- 4 Connect the differential probe to the test fixture at TP2, using the 01131-68703 header adapter.

### NOTE

Ensure the + polarity on the probe lines up with D+, which is the pin nearest the USB connector.

- 5 Connect the 81130A or 81134A pulse generator to the oscilloscope using the 82357A USB/GPIB Interface.
  - a If you choose to use the Agilent 81130A Pulse/Pattern Generator, connect the 8493C 6dB attenuators to OUTPUT1 and OUTPUT2 of Agilent 81130A Pulse/Pattern Generator.
  - b If you choose to use the Agilent 81134A Pulse/Pattern Generator, connect the 15432B Transition Time Converters to OUTPUT1 and OUTPUT2 of Agilent 81134A Pulse/Pattern Generator. Agilent 15432B Transition Time Converters are recommended, to reduce the output edge speed of the 81134A to speed close to what the 81130A provides.
- 6 Connect OUTPUT1 to SMA1 (D+) of the E2645-66503 Device Receiver Sensitivity test fixture using the 8120-4948 SMA cables.
- 7 Connect OUTPUT2 to SMA2 (D-) of the E2645-66503 Device Receiver Sensitivity test fixture using the 8120-4948 SMA cables.
- 8 Check **I have completed these instructions**.

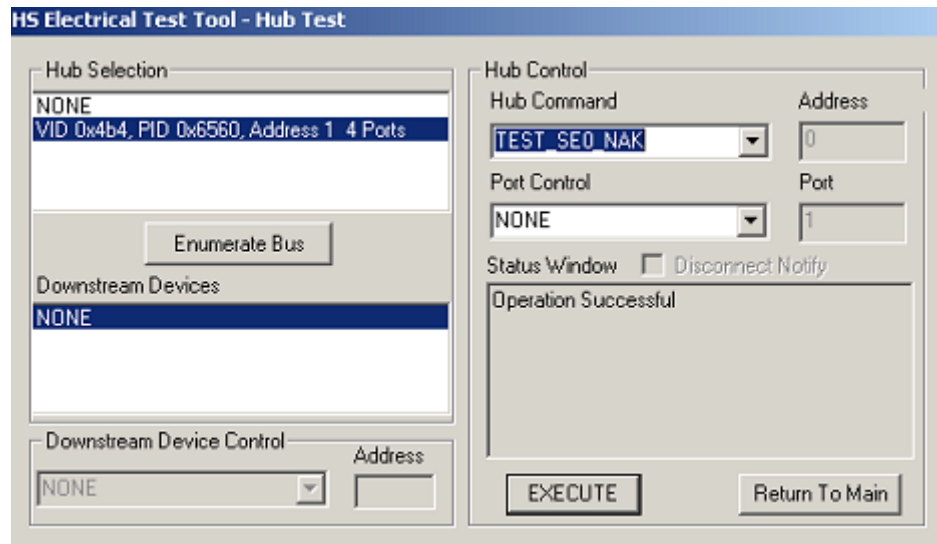
### Running the Tests

- 1 Click **Run Tests**.

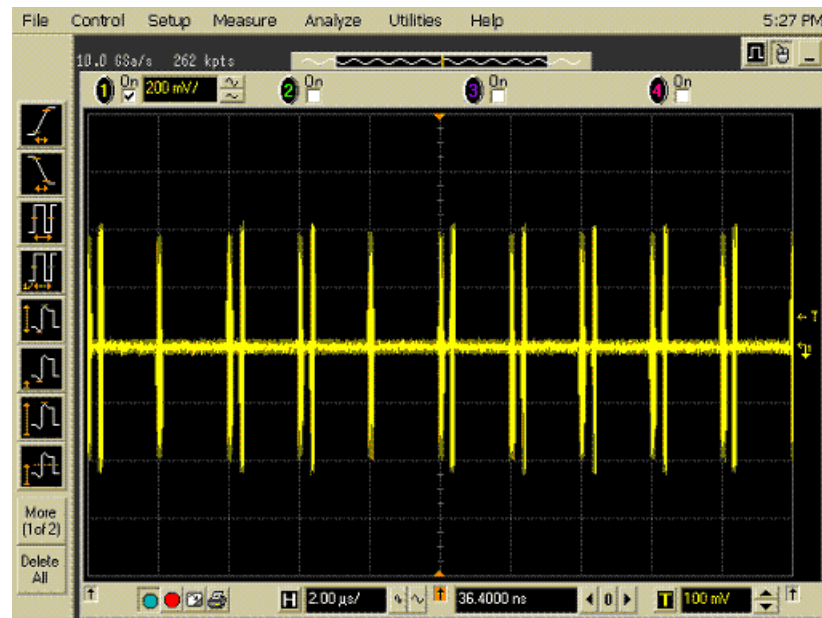
### Test Instructions

The USB automated test application will prompt you to perform these steps:

- 1 Exit the HS Electrical Test Tool - Device Test menu by clicking the **[Return to Main]** button. From the HS Electrical Test Tool main menu select **Hub** and click **[TEST]** to enter the Hub Test menu.
- 2 On the Hub Test Menu, click **[Enumerate Bus]** button once and verify that the hub enumerates properly.
- 3 Select **TEST\_SE0\_NAK** from the Hub Command drop down menu. Click **[EXECUTE]** once to place the hub into TEST\_SE0\_NAK test mode.



- 4 Place the test fixture Test Switch (S1) into the **TEST** position. This switches in the data generator in place of the host controller. The data generator emulates the "IN" packets from the host controller.



- 5 Click **OK** to close the Test Instructions dialog.

**EL\_18 Receiver sensitivity Test @ Min SYNC Field**

**EL\_17 Receiver sensitivity Test**

**EL\_16 Receiver sensitivity Test @ Squelch**

## **Viewing Test Results**

- 1 When the Testing Complete dialog appears, click **OK**.

The Results tab shows the test results.



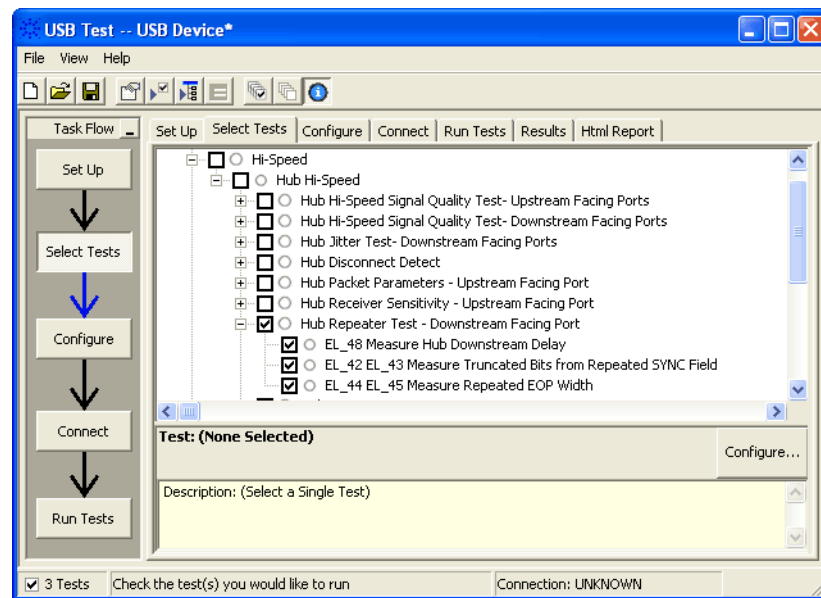
## Hub Repeater Test - Downstream Facing Port

### Equipment Used

**Table 19** Equipment Used in Hub Repeater Test - Downstream Facing Port

Quantity	Item	Description/Model
1	Oscilloscope	Agilent 5485xA Series or DS080000 Series
2	Differential probe	Agilent 113xA with E2699A or E2678A
2	Header adapter	Agilent 01131-68703
1	Host test bed computer	Any computer with hi-speed USB ports
1	Device Hi-Speed Signal Quality test fixture and 4" USB cable	Agilent E2645-66501
1	Host Hi-Speed Signal Quality test fixture and 4" USB cable	Agilent E2645-66502
2	5 meter USB 2.0 hi-speed cable	Any listed on USB-IF web site
2	1 meter USB cable	Any listed on USB-IF web site

### Selecting the Tests

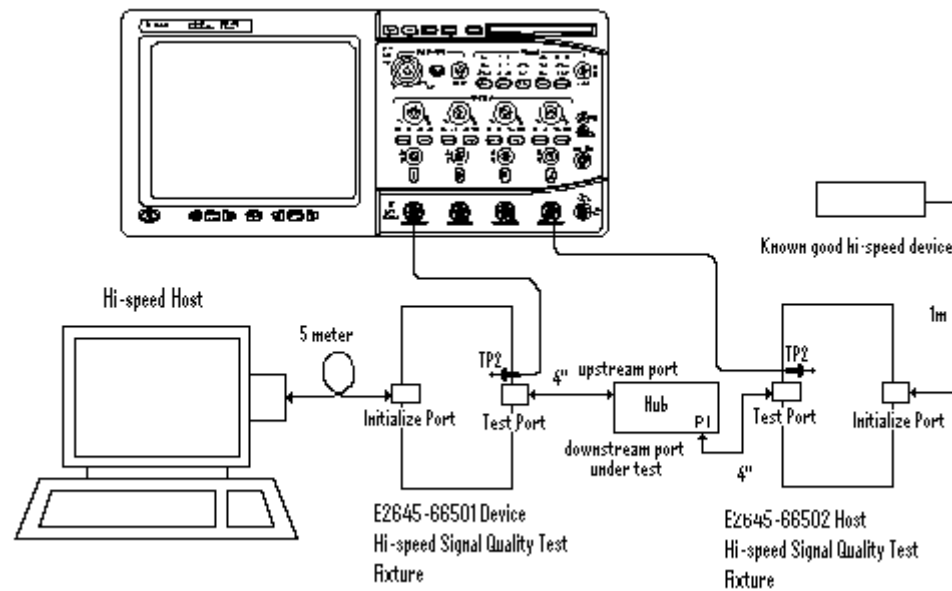


## Configuring the Tests

### Connecting the Equipment

The USB automated test application will prompt you to perform these connection steps:

- 1** Connect the E2645-66501 Device Hi-Speed Signal Quality test fixture between the upstream facing port of the hub and the host controller port.
  - a** Attach the Channel 1 differential probe to TP2 of the fixture. Ensure the + polarity on the probe lines up with D+ on the fixture. The D+ pin is the pin closest to the USB connector.
  - b** Connect the fixture's [TEST PORT] to the hub's upstream port with the 4" USB cable.
  - c** Connect the fixture's [INIT PORT] to the controller port with the 5 meter USB cable.
- 2** Connect the E2645-66502 Host Hi-Speed Signal Quality test fixture between the downstream port under test of the hub and a known-good hi-speed device.
  - a** Attach the Channel 4 differential probe to TP2 of the fixture. Ensure the + polarity on the probe lines up with the D+ on the fixture. The D+ pin is the pin closest to the USB connector.
  - b** Connect the test fixture's [TEST PORT] to the hub downstream port under test, using the 4" USB cable.
  - c** Connect the test fixture's [INIT PORT] to the known good device using the 1 meter USB cable.
  - d** Apply power to the hub and the known good device.



### 3 Check I have completed these instructions.

## Running the Tests

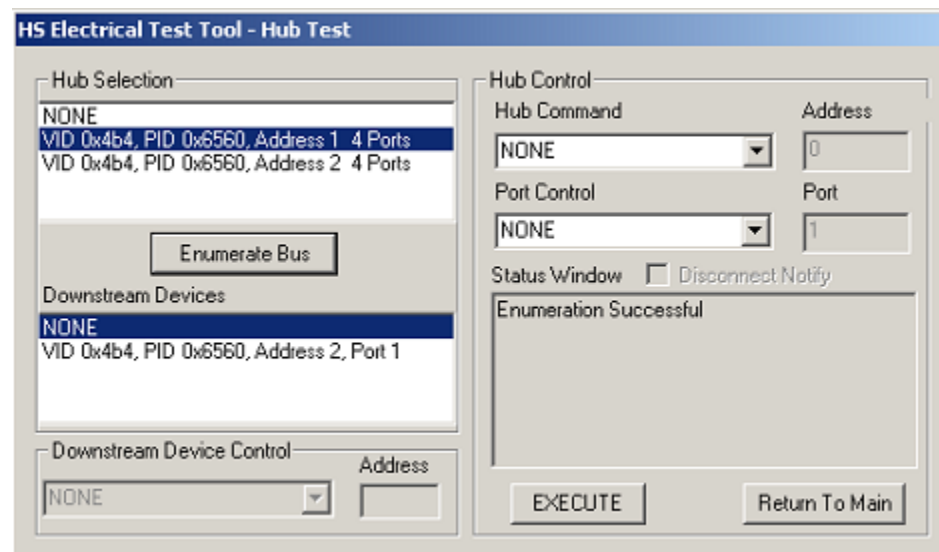
- 1 Click **Run Tests**.

## Test Instructions

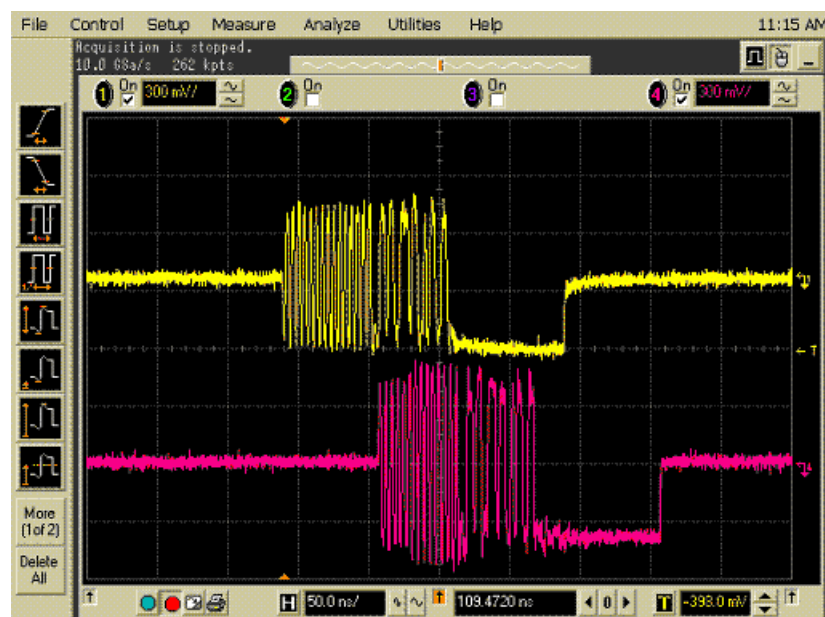
The USB automated test application will prompt you to perform these steps:

- 1 On the Hub Test menu of the HS Electrical Test Tool, click [**Enumerate Bus**] once.
  - a The hub under test should be enumerated with the hub's VID shown together with the USB address.
  - b Likewise the known good device should be enumerated with its VID shown together with the hub port in which it is connected.

## 4 Hub Hi-Speed Tests



- 2 The captured transition should be as in the figure below.



- 3 Check I have completed these instructions.

**EL\_48 Measure Hub Downstream Delay**

**EL\_42 EL\_43 Measure Truncated Bits from Repeated SYNC Field**

**EL\_44 EL\_45 Measure Repeated EOP Width**

## **Viewing Test Results**

- 1 When the Testing Complete dialog appears, click **OK**.

The Results tab shows the test results.

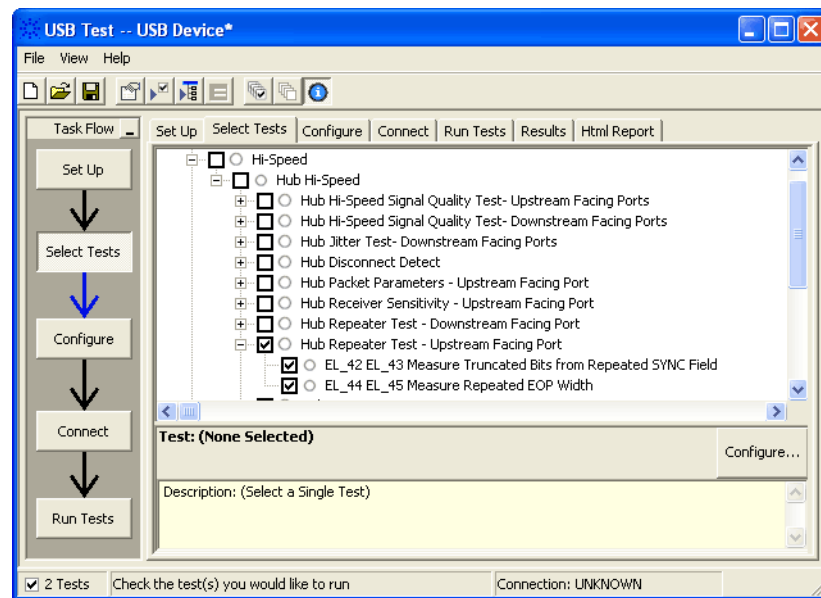
## Hub Repeater Test - Upstream Facing Port

### Equipment Used

**Table 20** Equipment Used in Hub Repeater Test - Upstream Facing Port

Quantity	Item	Description/Model
1	Oscilloscope	Agilent 5485xA Series or DS080000 Series
2	Differential probe	Agilent 113xA with E2699A or E2678A
2	Header adapter	Agilent 01131-68703
1	Host test bed computer	Any computer with hi-speed USB ports
1	Device Hi-Speed Signal Quality test fixture and 4" USB cable	Agilent E2645-66501
1	Host Hi-Speed Signal Quality test fixture and 4" USB cable	Agilent E2645-66502
2	5 meter USB 2.0 hi-speed cable	Any listed on USB-IF web site
2	1 meter USB cable	Any listed on USB-IF web site

### Selecting the Tests

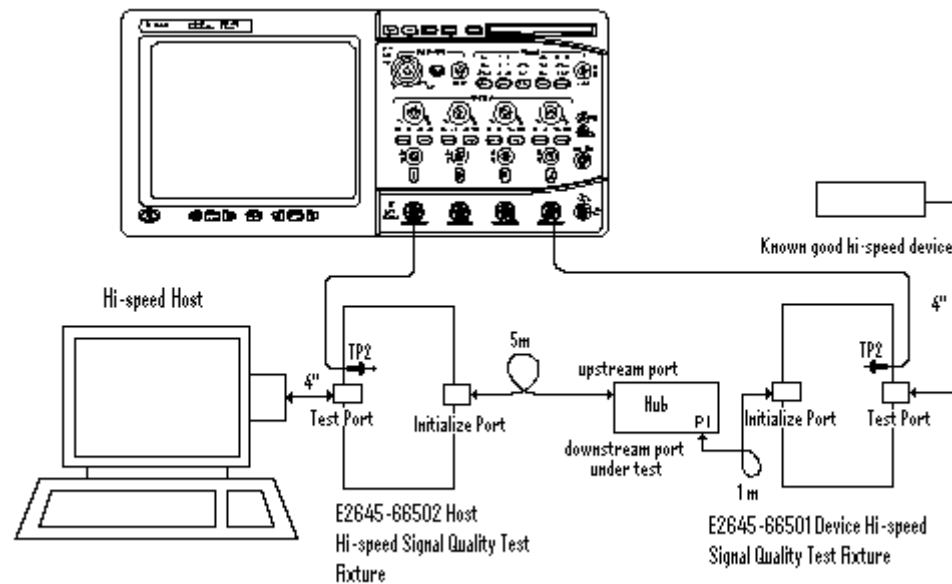


## Configuring the Tests

### Connecting the Equipment

The USB automated test application will prompt you to perform these connection steps:

- 1** Connect the E2645-66502 Host Hi-Speed Signal Quality test fixture between the upstream facing port of the hub and the host controller port.
  - a** Attach the Channel 1 differential probe to TP2 of the fixture. Ensure the + polarity on the probe lines up with D+ on the fixture. The D+ pin is the pin closest to the USB connector.
  - b** Connect the fixture's [INIT PORT] to the hub's upstream port, with the 5 meter USB cable.
  - c** Connect the fixture's [TEST PORT] to the host controller port, using the 4" USB cable.
- 2** Connect the E2645-66501 Device Hi-Speed Signal Quality test fixture between the downstream port under test of the hub and a known good hi-speed device, nearest to the device.
  - a** Attach the Channel 4 differential probe to TP2 of the fixture. Ensure the + polarity on the probe lines up with the D+ on the fixture. The D+ pin is the pin closest to the USB connector.
  - b** Connect the test fixture's [TEST PORT] to a known good device using the 4" USB cable.
  - c** Connect the test fixture's [INIT PORT] to the hub's downstream port under test using the 1 meter USB cable.
  - d** Apply power to the hub and the known good device.



### 3 Check I have completed these instructions.

## Running the Tests

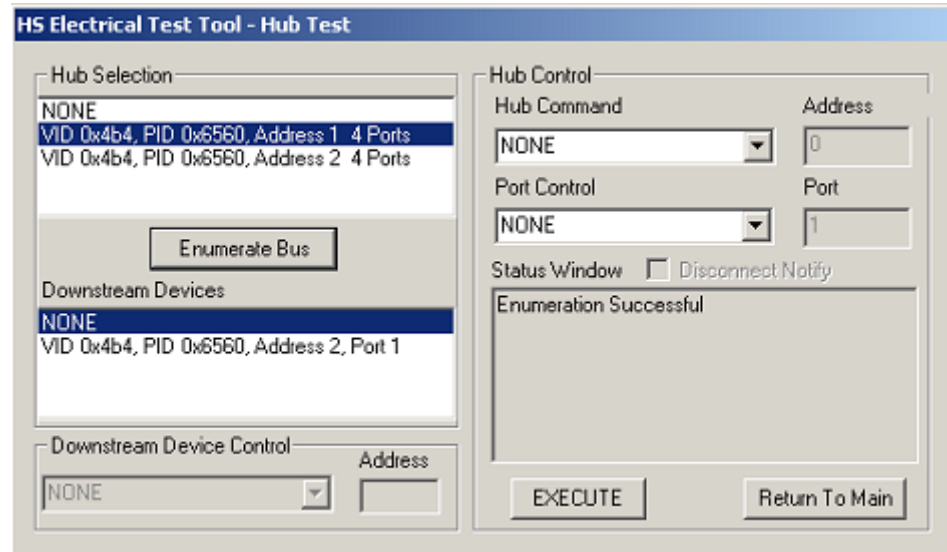
### 1 Click Run Tests.

## Test Instructions, Part 1

The USB automated test application will prompt you to perform these steps:

- 1 On the Hub Test menu of the HS Electrical Test Tool, click **[Enumerate Bus]** once.
  - a The hub under test should be enumerated with the hub's VID shown together with the USB address.
  - b Likewise the known good device should be enumerated with its VID shown together with the hub port in which it is connected.



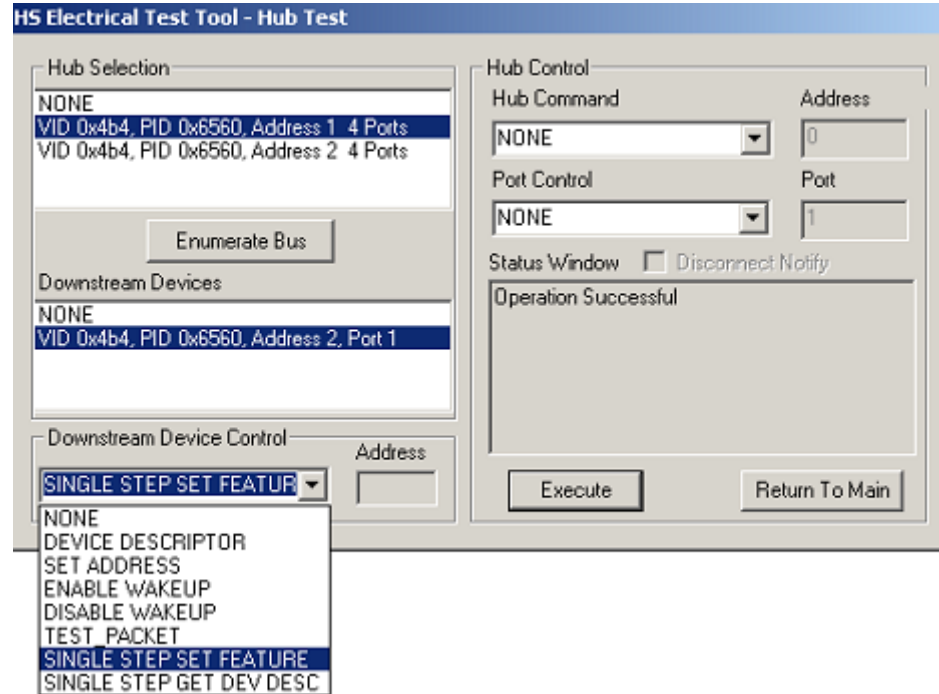


- 2 Check I have completed these instructions.

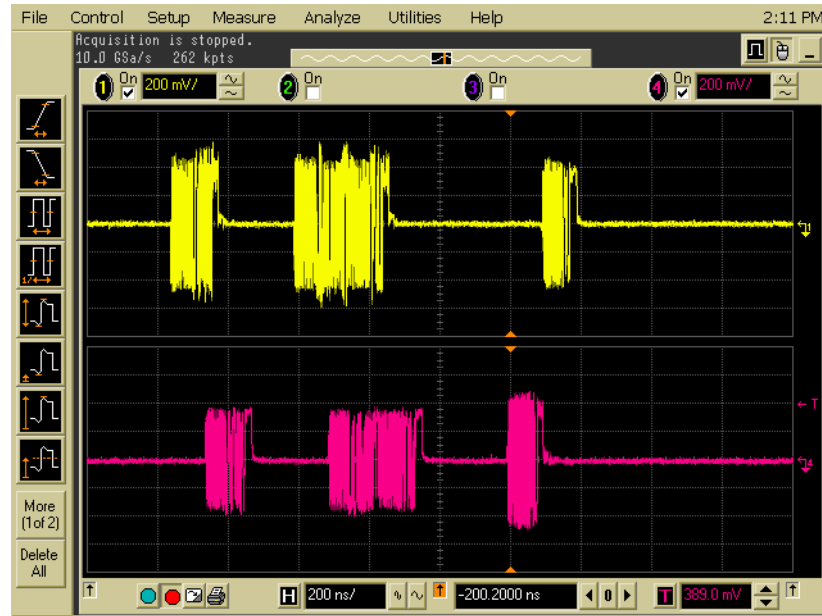
## Test Instructions, Part 2

The USB automated test application will prompt you to perform these steps:

- 1 On the Hub Test menu of the HS Electrical Test Tool, select **SINGLE STEP SET FEATURE** from the Downstream Device Control drop down menu and click [EXECUTE] once.



- 2 The captured transition should be as in the figure below.



3 Check I have completed these instructions.

EL\_42 EL\_43 Measure Truncated Bits from Repeated SYNC Field

EL\_44 EL\_45 Measure Repeated EOP Width

## Viewing Test Results

1 When the Testing Complete dialog appears, click **OK**.

The Results tab shows the test results.

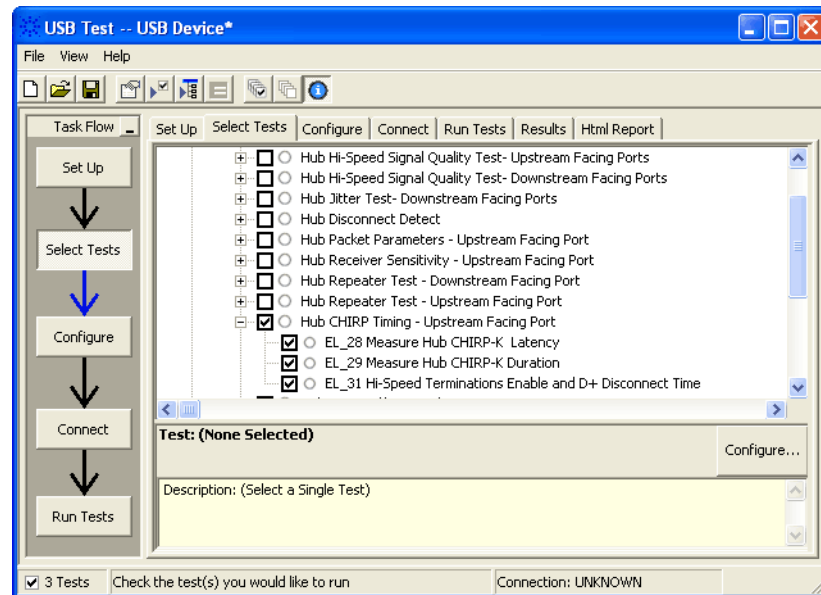
## Hub CHIRP Timing - Upstream Facing Port

### Equipment Used

**Table 21** Equipment Used in Hub CHIRP Timing - Upstream Facing Port

Quantity	Item	Description/Model
1	Oscilloscope	Agilent 5485xA Series or DS080000 Series
2	Passive or active probes	Agilent E2697A with 10073C, or 1156A
1	Host test bed computer	Any computer with hi-speed USB ports
1	Device Hi-Speed Signal Quality test fixture	Agilent E2645-66501
1	5 meter USB 2.0 hi-speed cable	Any listed on USB-IF web site

### Selecting the Tests

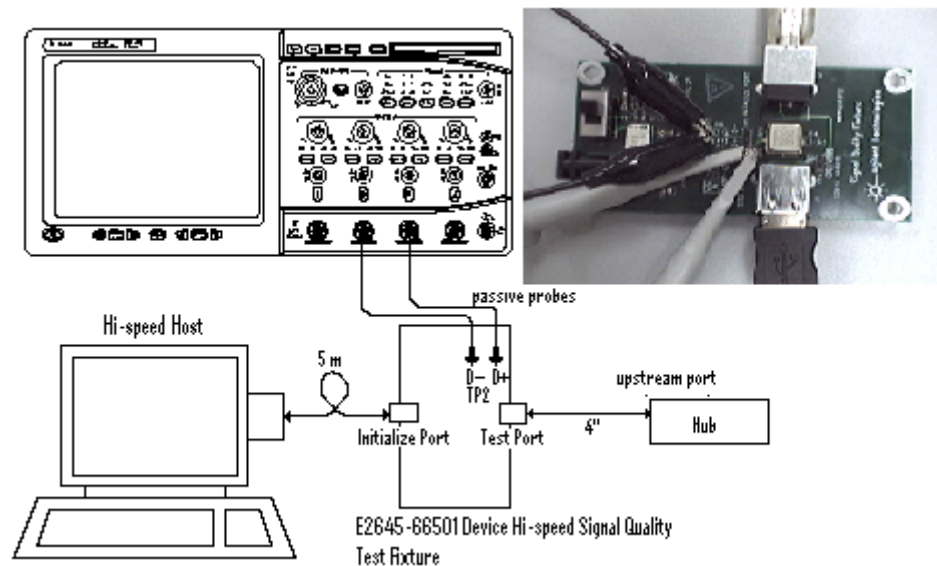


## Configuring the Tests

### Connecting the Equipment

The USB automated test application will prompt you to perform these connection steps:

- 1 Connect the E2697A with 10073C passive probe or the 1156A active probe on Channel 2 to the D- pin at TP2 of the E2645-66501 Device Hi-Speed Signal Quality test fixture.
- 2 Connect the E2697A with 10073C passive probe or the 1156A active probe on Channel 3 to the D+ pin at TP2. D+ on TP2 is the pin closest to the USB connector.
- 3 Connect both probe grounds to leads TP5.
- 4 Connect the [INIT PORT] of the test fixture into the host controller port, using the 5-meter USB cable.
- 5 Connect the [TEST PORT] on the fixture to the upstream port of the hub.
- 6 Apply power to the hub.



- 7 Check I have completed these instructions.

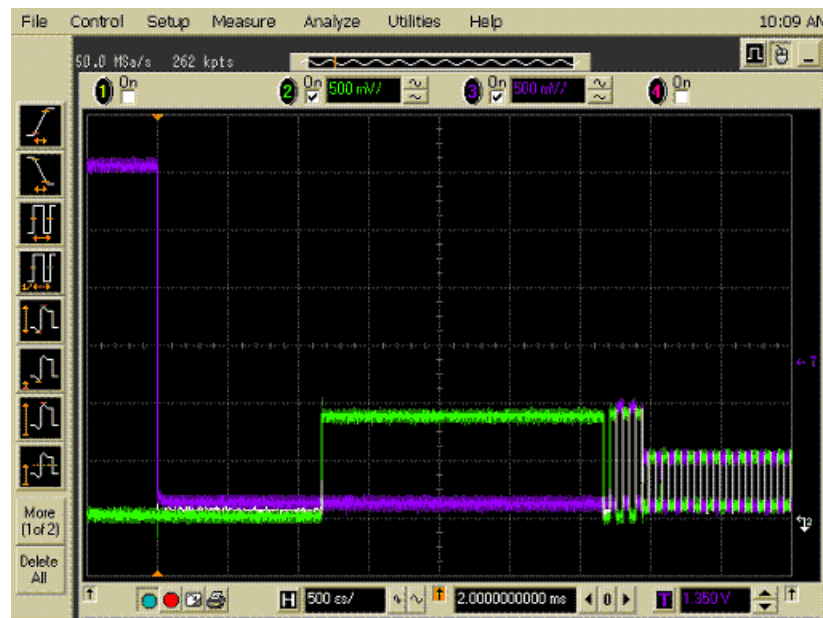
### Running the Tests

- 1 Click **Run Tests**.

### Test Instructions

The USB automated test application will prompt you to perform these steps:

- 1 On the HS Electrical Test Tool software, click [**Enumerate Bus**] once. You should capture the CHIRP handshake as in the below figure.



- 2 Click **OK** to close the Test Instructions dialog.

**EL\_28 Measure Hub CHIRP-K Latency**

**EL\_29 Measure Hub CHIRP-K Duration**

**EL\_31 Hi-Speed Terminations Enable and D+ Disconnect Time**

### Viewing Test Results

- 1 When the Testing Complete dialog appears, click **OK**.

The Results tab shows the test results.

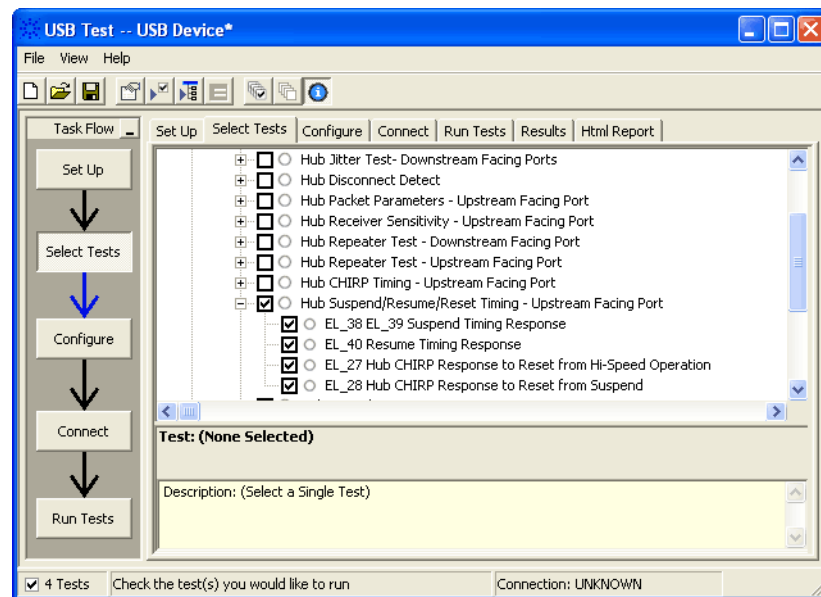
## Hub Suspend/Resume/Reset Timing - Upstream Facing Port

### Equipment Used

**Table 22** Equipment Used in Hub Suspend/Resume/Reset - Upstream Facing Port

Quantity	Item	Description/Model
1	Oscilloscope	Agilent 5485xA Series or DS080000 Series
2	Passive or active probes	Agilent E2697A with 10073C, or 1156A
1	Host test bed computer	Any computer with hi-speed USB ports
1	Device Hi-Speed Signal Quality test fixture	Agilent E2645-66501
1	5 meter USB 2.0 hi-speed cable	Any listed on USB-IF web site

### Selecting the Tests

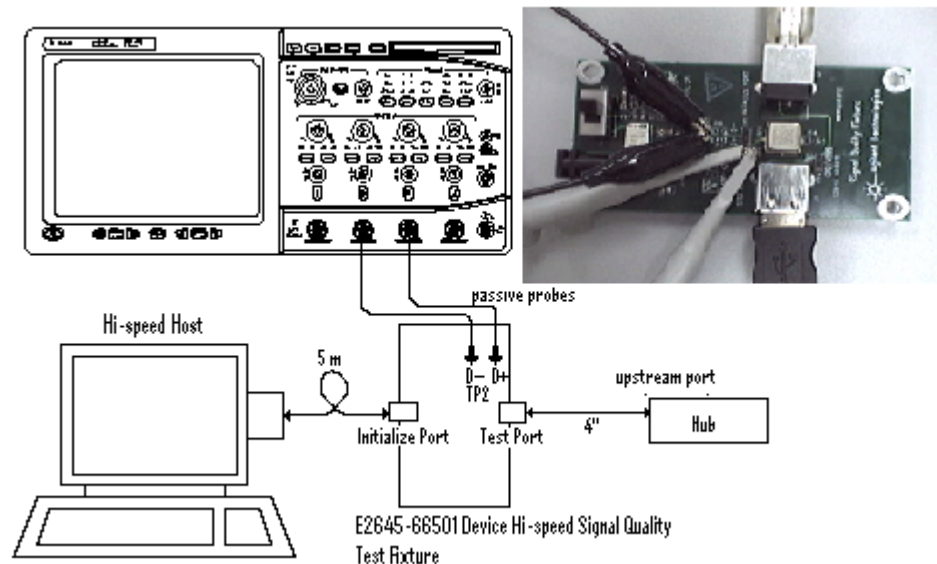


## Configuring the Tests

### Connecting the Equipment

The USB automated test application will prompt you to perform these connection steps:

- 1 Connect the E2697A with 10073C passive probe or the 1156A active probe on Channel 2 to the D- pin at TP2 of the E2645-66501 Device Hi-Speed Signal Quality test fixture.
- 2 Connect the E2697A with 10073C passive probe or the 1156A active probe on Channel 3 to the D+ pin at TP2. D+ on TP2 is the pin closest to the USB connector.
- 3 Connect both probe grounds to leads TP5.
- 4 Connect the [INIT PORT] of the test fixture into the host controller port, using the 5-meter USB cable.
- 5 Connect the [TEST PORT] on the fixture to the upstream port of the hub.
- 6 Apply power to the hub.



- 7 Check I have completed these instructions.



## Running the Tests

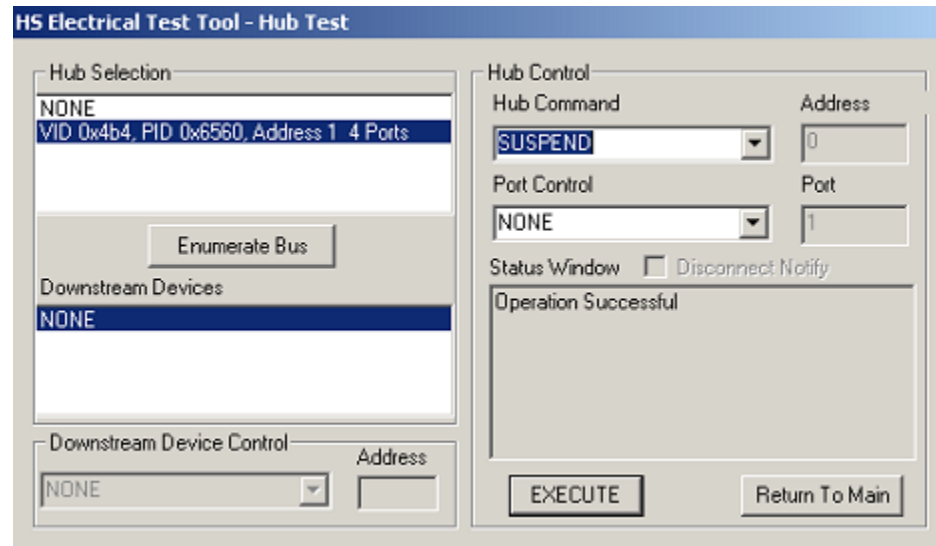
- 1 Click **Run Tests**.

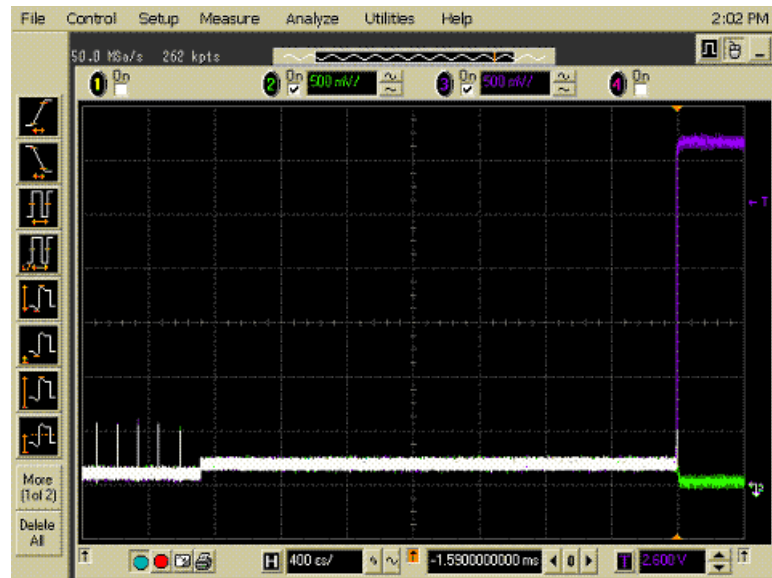
## Test Instructions

### EL\_38 EL\_39 Suspend Timing Response

The USB automated test application will prompt you to perform these steps:

- 1 On the Hub Test menu of the HS Electrical Test Tool software, click **[Enumerate Bus]** once.
- 2 Select **SUSPEND** from the Hub Command drop down menu. Click **[EXECUTE]** once to place the device into suspend. The captured transition should be as in the figure below.



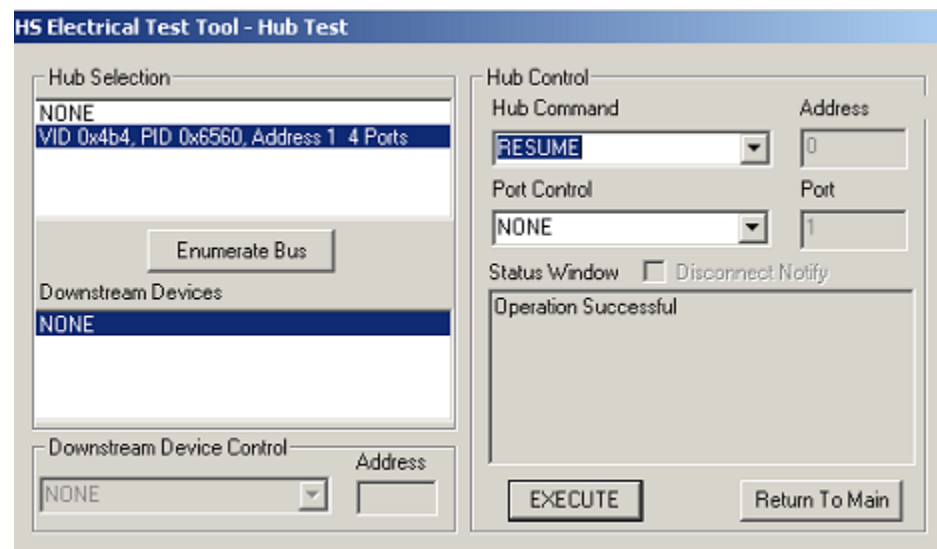


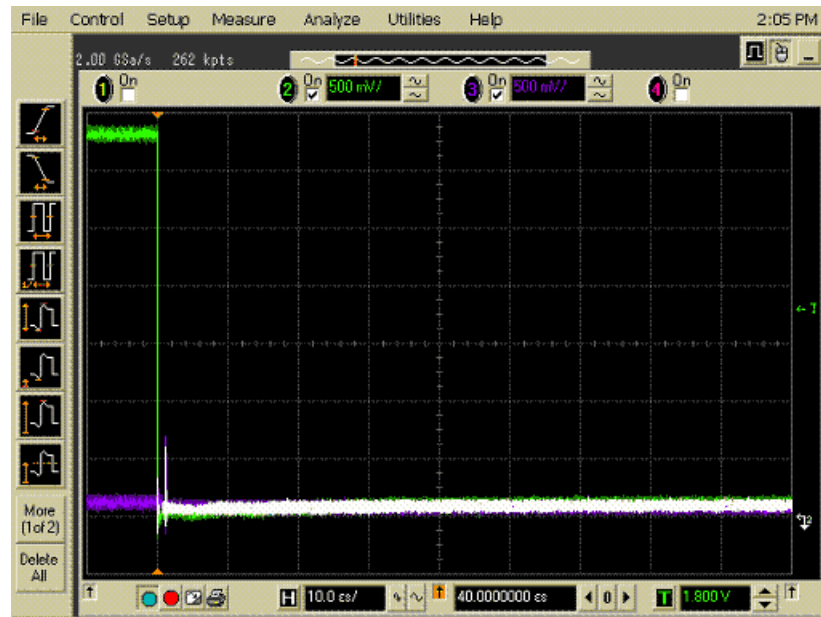
- 3 Click **OK** to close the Test Instructions dialog.

### EL\_40 Resume Timing Response

The USB automated test application will prompt you to perform these steps:

- 1 On the Hub Test menu of the HS Electrical Test Tool, select **RESUME** from the Hub Command drop down menu. Click **[EXECUTE]** once to resume the hub from suspend. The captured transition should be as in the figure below.



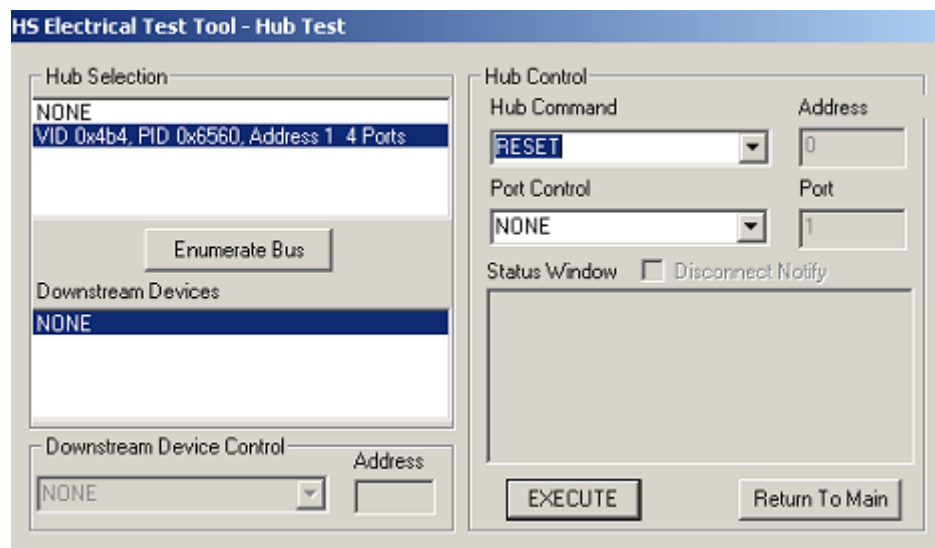


- 2 Click **OK** to close the Test Instructions dialog.

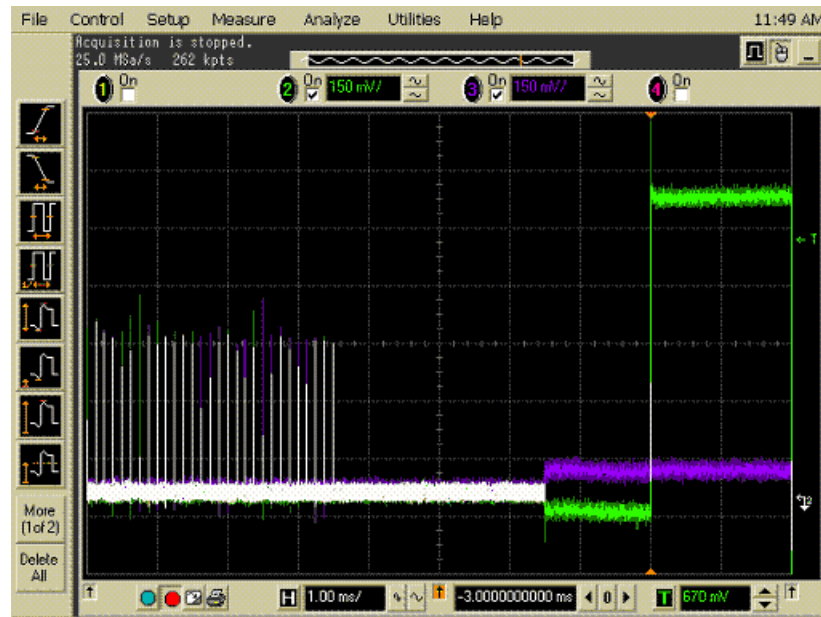
### EL\_27 Hub CHIRP Response to Reset from Hi-Speed Operation

The USB automated test application will prompt you to perform these steps:

- 1 On the Hub Test menu of the HS Electrical Test Tool, select **RESET** from the Hub Command drop down menu. Click **[EXECUTE]** once to reset the hub operating in high speed. The captured transition should be as in the figure below.



## 4 Hub Hi-Speed Tests

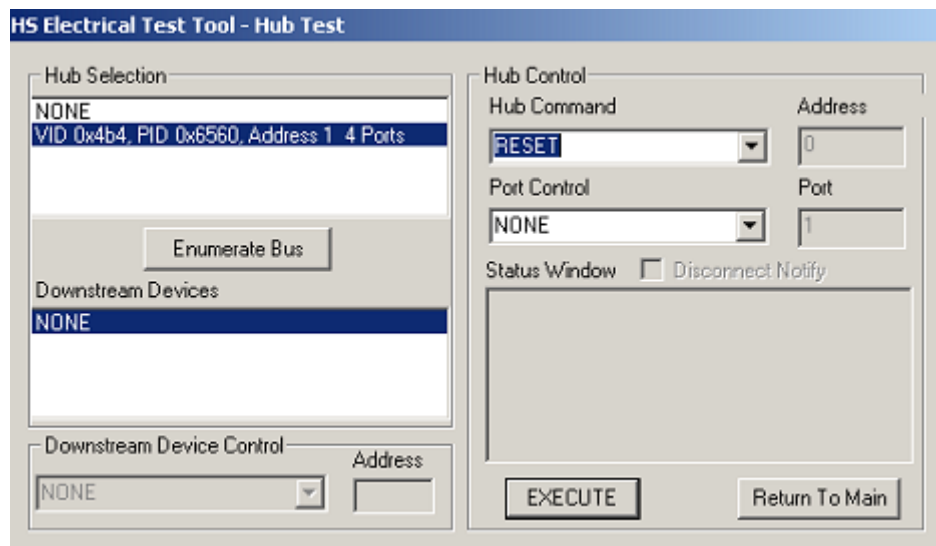


- 2 Click **OK** to close the Test Instructions dialog.

### EL\_28 Hub CHIRP Response to Reset from Suspend

The USB automated test application will prompt you to perform these steps:

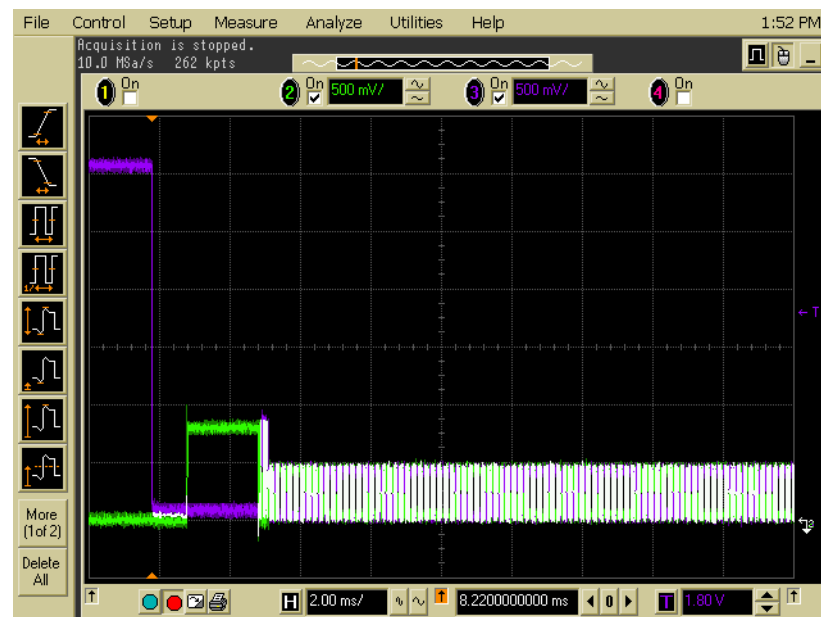
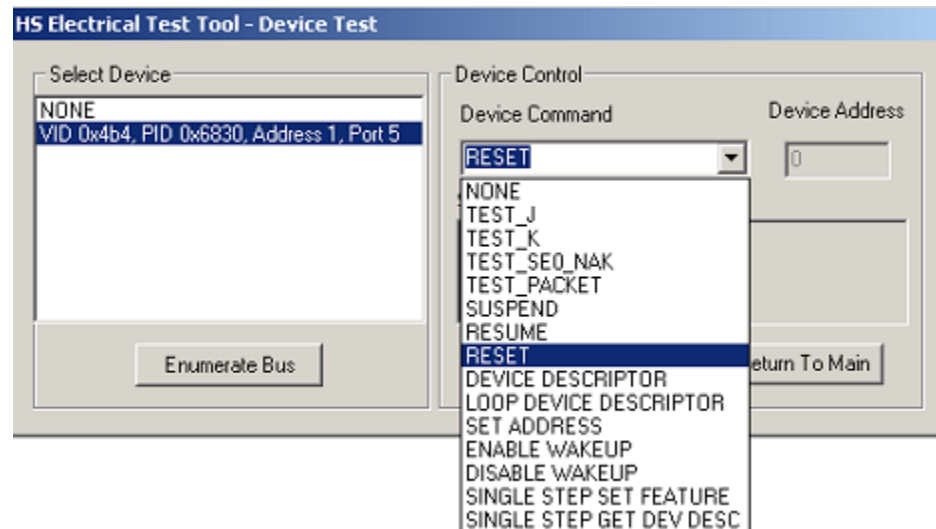
- 1 On the Hub Test menu of the HS Electrical Test Tool software, select **SUSPEND** from the Hub Command drop down menu. Click [**EXECUTE**] once to place the device into suspend.



- 2 Click **OK** to close the Test Instructions dialog.

The USB automated test application will prompt you to perform these steps:

- 1 On the Device Test Menu of the HS Electrical Test Tool, select **RESET** from the Device Command drop down menu. Click **[EXECUTE]** once to reset the device operating in high speed. The captured transition should be as in the figure below.



- 2 Click **OK** to close the Test Instructions dialog.

## **Viewing Test Results**

- 1    When the Testing Complete dialog appears, click **OK**.

The Results tab shows the test results.

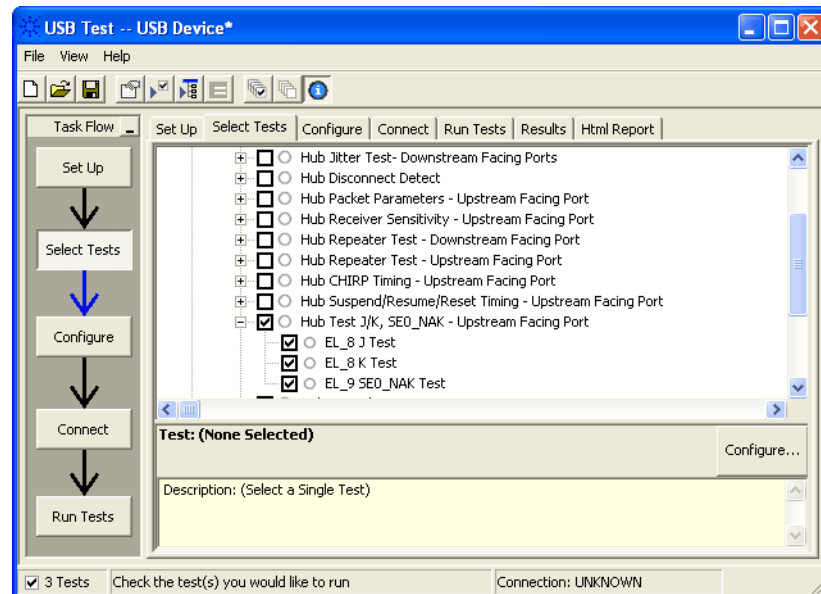
## Hub Test J/K, SE0\_NAK - Upstream Facing Port

### Equipment Used

**Table 23** Equipment Used in Hub Test J/K, SE0\_NAK - Upstream Facing Port

Quantity	Item	Description/Model
1	Digital Multimeter (DMM)	Agilent 34401A or equivalent
1	Host test bed computer	Any computer with hi-speed USB ports
1	Device Hi-Speed Signal Quality test fixture and 4" USB cable	Agilent E2645-66501
1	5V power supply	Agilent 0950-2546 or equivalent
1	5 meter USB 2.0 hi-speed cable	Any listed on USB-IF web site

### Selecting the Tests

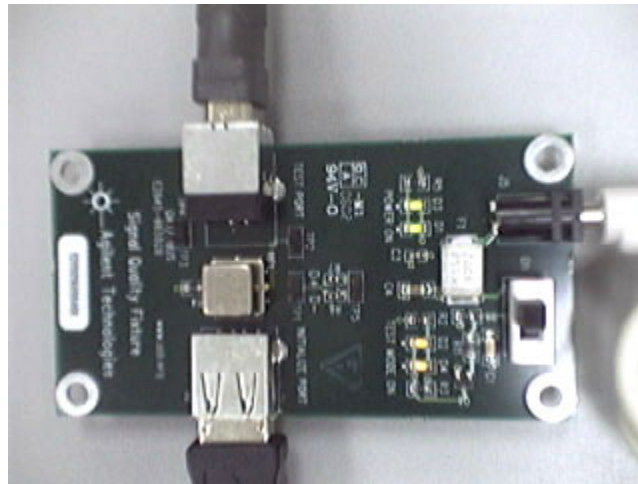


## Configuring the Tests

### Connecting the Equipment

The USB automated test application will prompt you to perform these connection steps:

- 1 Attach the 5V power supply to J5 of the E2645-66501 Device High-Speed Signal Quality test fixture. Verify the green Power LED(D1) is lit, and the yellow Test LED(D2) is off.
- 2 Connect the [TEST PORT] of the test fixture into the upstream facing port of the hub under test, using the 4" USB cable.
- 3 Connect the [INIT PORT] of the test fixture to a port of the Test Bed Computer, using the 5 meter cable.
- 4 Apply power to the hub.



- 5 Check I have completed these instructions.

### Running the Tests

- 1 Click **Run Tests**.

### Test Instructions

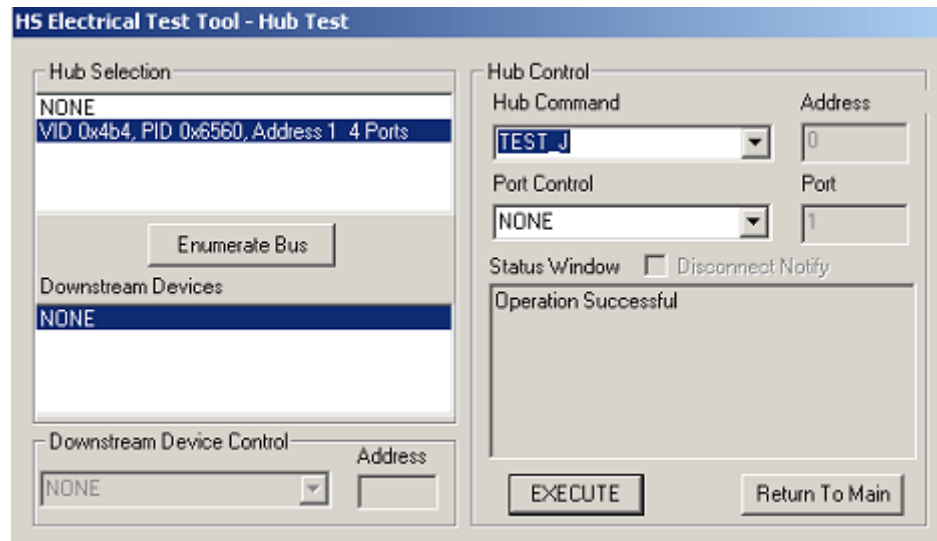
#### EL\_8 J Test

The USB automated test application will prompt you to perform these steps:

- 1 On the Hub Test menu of the HS Electrical Test Tool, click [**Enumerate Bus**] once.
- 2 Select **TEST\_J** from the Hub Command drop down menu. Click [**EXECUTE**] once to place the hub into TEST\_J test mode.

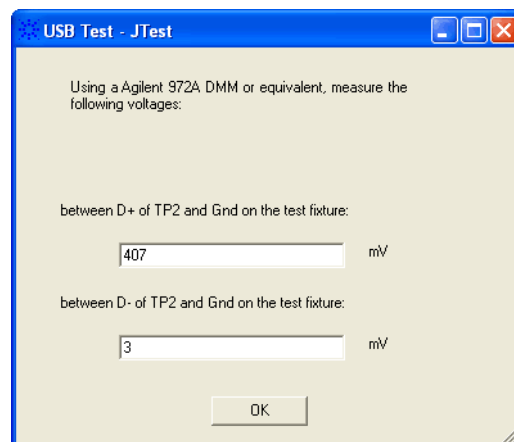


- 3 Switch the test fixture into the **TEST** position.



- 4 Click **OK** to close the Test Instructions dialog.

The USB automated test application will prompt you for the following voltage measurements:

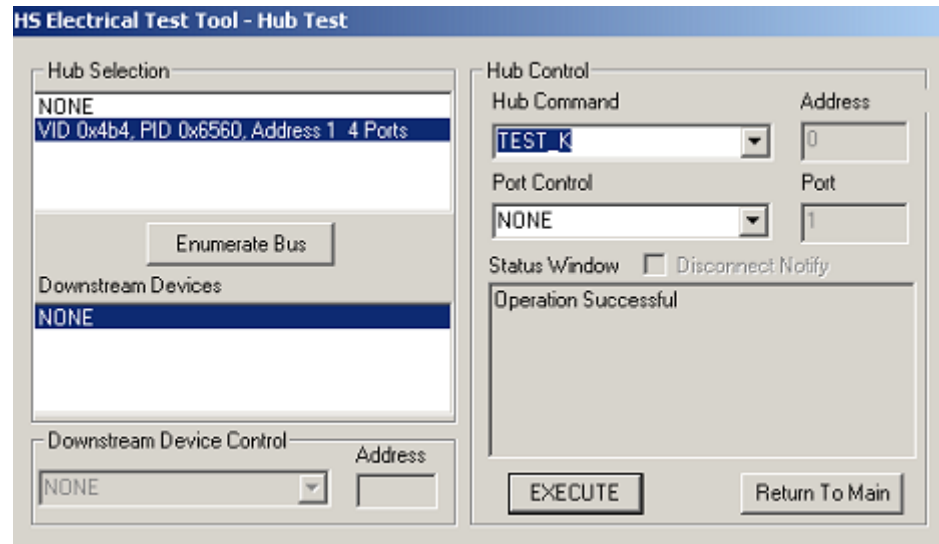


### EL\_8 K Test

The USB automated test application will prompt you to perform these steps:

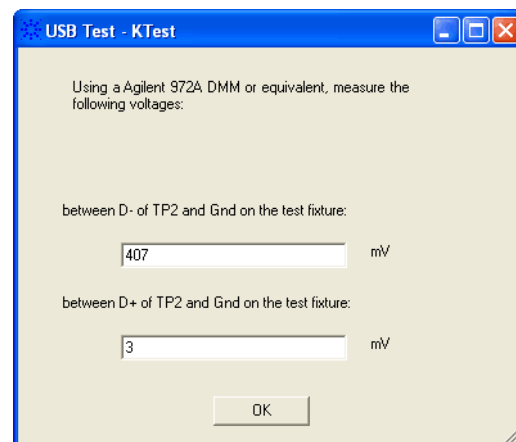
- 1 Return the Test switch of the test fixture to the **NORMAL** position.
- 2 Cycle the hub power to restore the hub to normal operation. On the Hub Test menu of the HS Electrical Test Tool, click [**Enumerate Bus**] once.
- 3 Select **TEST\_K** from the Hub Command drop down menu. Click [**EXECUTE**] once to place the hub into TEST\_K test mode.

- 4 Switch the test fixture into the **TEST** position.



- 5 Click **OK** to close the Test Instructions dialog.

The USB automated test application will prompt you for the following voltage measurements:

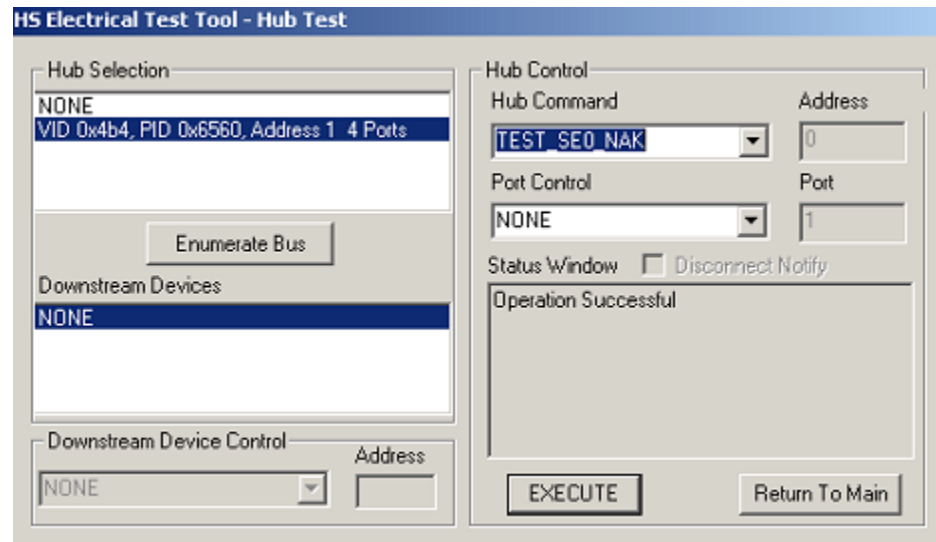


### EL\_9 SE0\_NAK Test

The USB automated test application will prompt you to perform these steps:

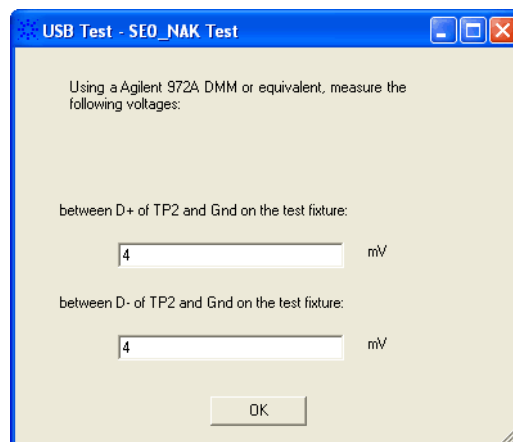
- 1 Return the Test switch of the test fixture to the **NORMAL** position.
- 2 Cycle the hub power to restore the hub to normal operation. On the Hub Test menu of the HS Electrical Test Tool, click [**Enumerate Bus**] once.
- 3 Select **TEST\_SE0\_NAK** from the Hub Command drop down menu. Click [**EXECUTE**] once to place the hub into TEST\_SE0\_NAK test mode.

- 4 Switch the test fixture into the **TEST** position.



- 5 Click **OK** to close the Test Instructions dialog.

The USB automated test application will prompt you for the following voltage measurements:



## Viewing Test Results

- 1 When the Testing Complete dialog appears, click **OK**.

The Results tab shows the test results.

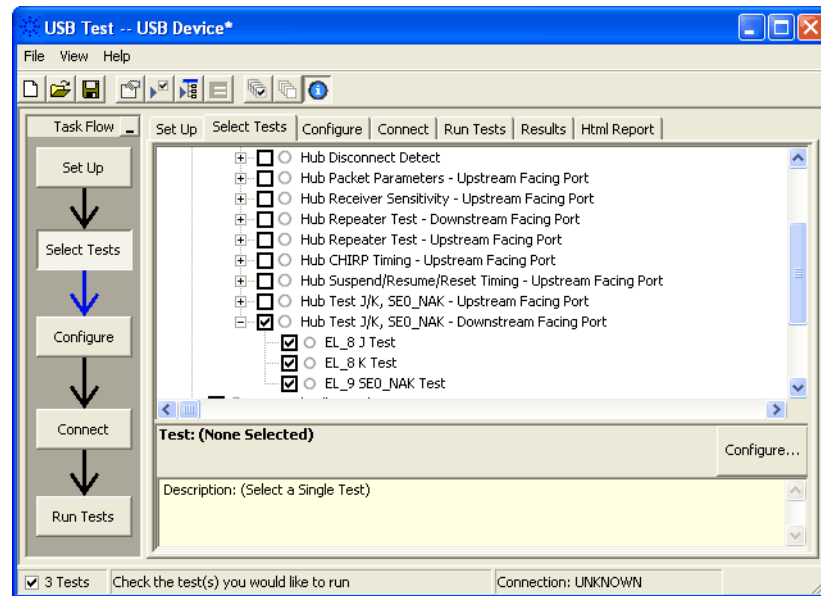
## Hub Test J/K, SE0\_NAK - Downstream Facing Port

### Equipment Used

**Table 24** Equipment Used in Hub Test J/K, SE0\_NAK - Downstream Facing Port

Quantity	Item	Description/Model
1	Digital Multimeter (DMM)	Agilent 34401A or equivalent
1	Host test bed computer	Any computer with hi-speed USB ports
1	Host Hi-Speed Signal Quality test fixture and 4" USB cable	Agilent E2645-66502
1	5V power supply	Agilent 0950-2546 or equivalent
1	5 meter USB 2.0 hi-speed cable	Any listed on USB-IF web site

### Selecting the Tests

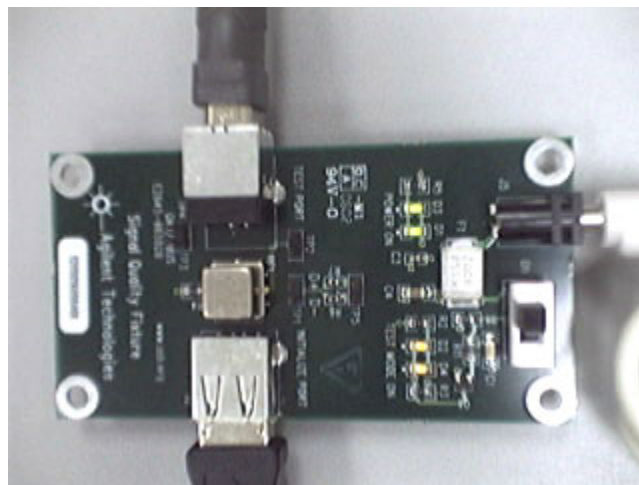


## Configuring the Tests

### Connecting the Equipment

The USB automated test application will prompt you to perform these connection steps:

- 1 Attach the 5V power supply to J5 of the E2645-66502 Host High-Speed Signal Quality test fixture. Verify the green Power LED(D1) is lit. Place the TEST switch (S1) in the Test position and the yellow Test LED(D2) is lit.
- 2 Connect the [TEST PORT] of the test fixture into the downstream facing port of the hub under test, using the 4" USB cable.
- 3 Attach the hub upstream port to the host controller port, using the 5 meter cable.
- 4 Apply power to the hub.



- 5 Check I have completed these instructions.

## Running the Tests

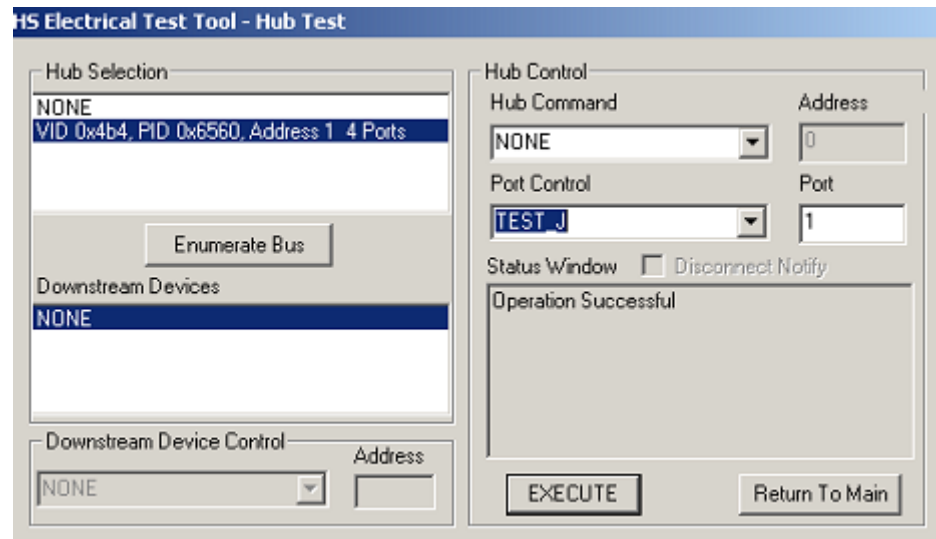
- 1 Click **Run Tests**.

## Test Instructions

### EL\_8 J Test

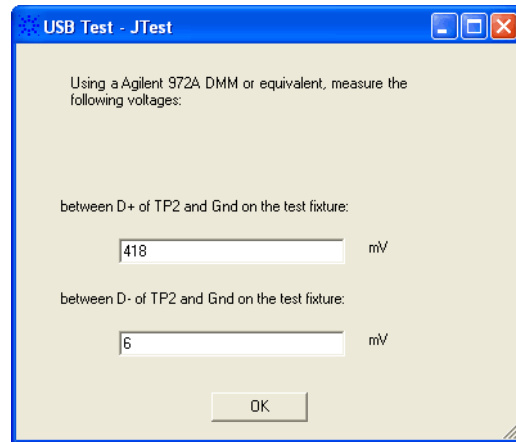
The USB automated test application will prompt you to perform these steps:

- 1 On the Hub Test menu of the HS Electrical Test Tool, click [**Enumerate Bus**] once.
- 2 Select **TEST\_J** from the Port Control drop down menu. Enter port number and click [**EXECUTE**] once to place the port under test into TEST\_J test mode.



- 3 Click **OK** to close the Test Instructions dialog.

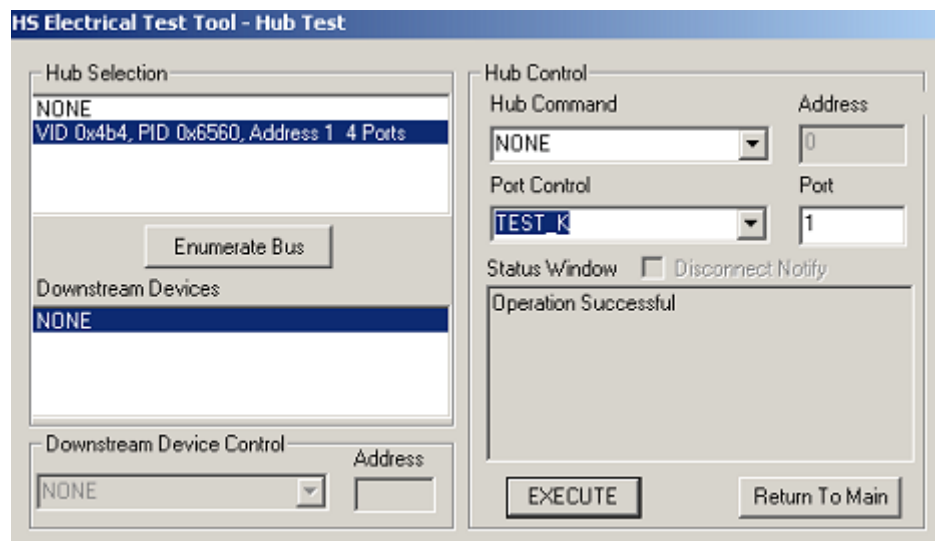
The USB automated test application will prompt you for the following voltage measurements:



### EL\_8 K Test

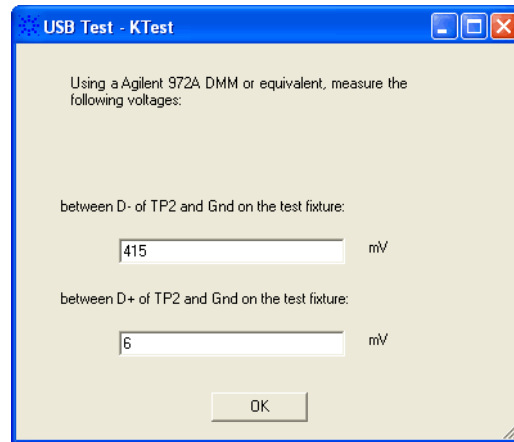
The USB automated test application will prompt you to perform these steps:

- 1 On the Hub Test menu of the HS Electrical Test Tool, click [**Enumerate Bus**] once.
- 2 Select **TEST\_K** from the Port Control drop down menu. Enter port number and click [**EXECUTE**] once to place the port under test into TEST\_K test mode.



- 3 Click **OK** to close the Test Instructions dialog.

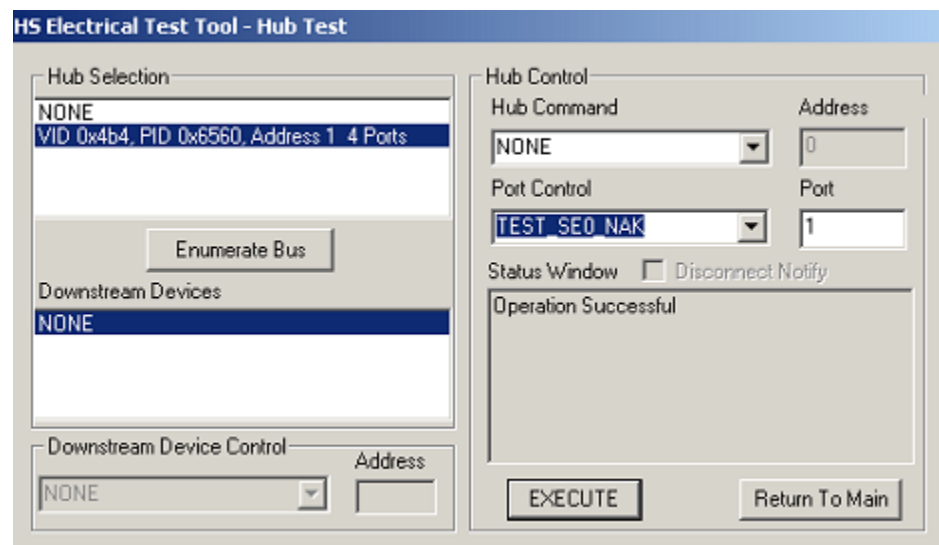
The USB automated test application will prompt you for the following voltage measurements:



### EL\_9 SE0\_NAK Test

The USB automated test application will prompt you to perform these steps:

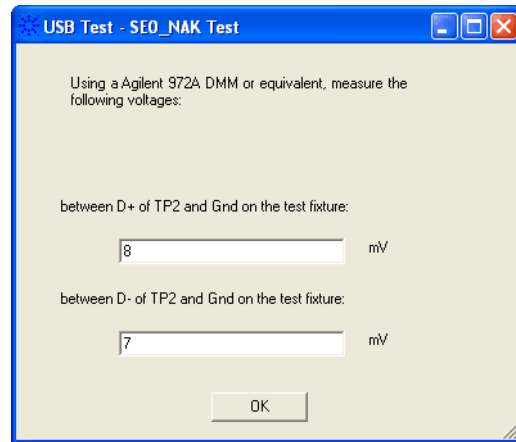
- 1 On the Hub Test menu of the HS Electrical Test Tool, click **[Enumerate Bus]** once.
- 2 Select **TEST\_SE0\_NAK** from the Port Control drop down menu. Enter port number and click **[EXECUTE]** once to place the port under test into TEST\_SE0\_NAK test mode.



- 3 Click **OK** to close the Test Instructions dialog.



The USB automated test application will prompt you for the following voltage measurements:



USB Test - SE0\_NAK Test

Using a Agilent 972A DMM or equivalent, measure the following voltages:

between D+ of TP2 and Gnd on the test fixture:

8 mV

between D- of TP2 and Gnd on the test fixture:

7 mV

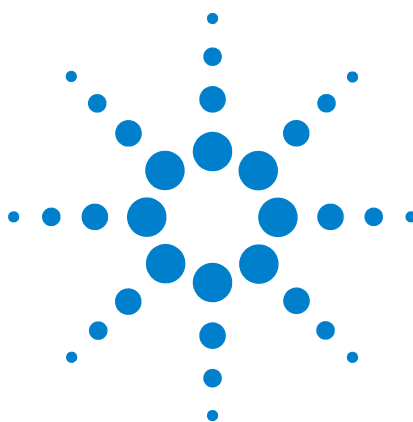
OK

## Viewing Test Results

- 1 When the Testing Complete dialog appears, click **OK**.

The Results tab shows the test results.





## 5 Host Hi-Speed Electrical Tests

Host Hi-Speed Signal Quality	133
Host Controller Packet Parameters	137
Host Disconnect Detect	144
Host CHIRP Timing	148
Host Suspend/Resume Timing	152
Host Test J/K, SE0_NAK	157

### NOTE

To give the automated test software more flexibility in making corner case measurements (and improve test performance), the oscilloscope's memory upgrade option is recommended (Option 001 when ordered with the oscilloscope, or after purchase: E2680A for the 5485xA Series oscilloscopes, or N5404A for the DSO80000 Series oscilloscopes).

Also, to reduce the bandwidth of the oscilloscope to just what is required by the USB-IF (2 GHz for USB 2.0)—this can greatly reduce system measurement noise, allowing the maximum measurement margin—the enhanced bandwidth software option is recommended for the Agilent 54855A oscilloscope (Option 008), and the noise reduction software option is recommended for the DSO80000 Series oscilloscopes (Option 005 when ordered with the oscilloscope or N5403A after purchase).

In addition to the hi-speed electrical tests prescribed in this chapter, the host controller under test must also pass the following electrical compliance tests applicable to the EHCI Host Controller:

- Full speed signal quality.
- Low speed signal quality.
- Drop/Droop.

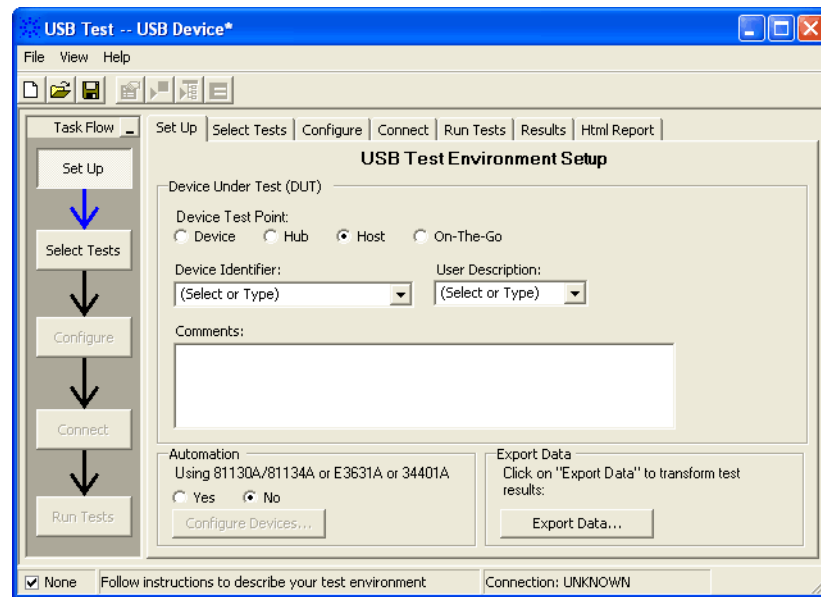
### Before Running These Tests

If you haven't already performed the initial equipment set up, see [“Setting Up the Equipment”](#) on page 19.



### Selecting the Host Test Environment Setup

- 1 In the USB automated test application, select the **Host** test environment.



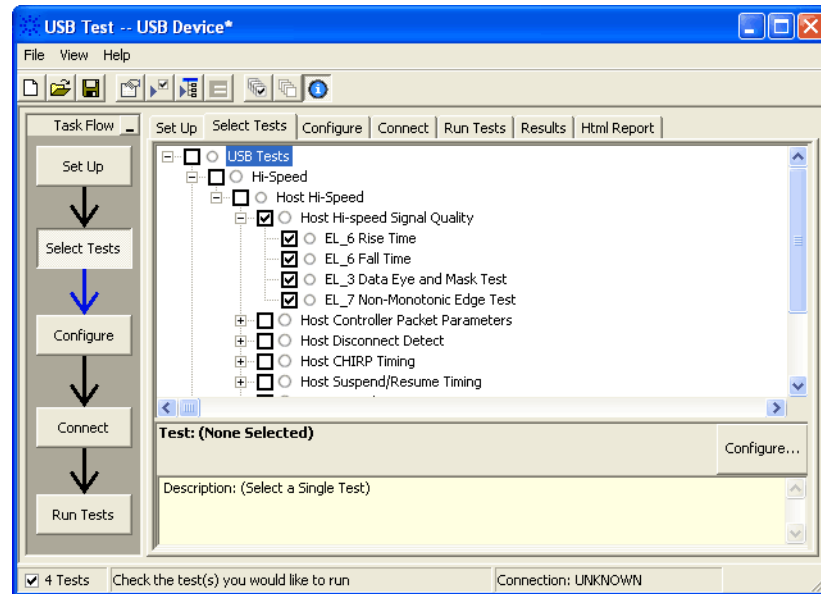
## Host Hi-Speed Signal Quality

### Equipment Used

**Table 25** Equipment Used in Host Hi-Speed Signal Quality Tests

Quantity	Item	Description/Model
1	Oscilloscope	Agilent 5485xA Series or DS080000 Series
1	Differential probe	Agilent 113xA with E2699A or E2678A
1	Header adapter	Agilent 01131-68703
1	Host test bed computer	Any computer with hi-speed USB ports
1	Host Hi-Speed Signal Quality test fixture and 4" USB cable	Agilent E2645-66502
1	5V power supply	Agilent 0950-2546 or equivalent

### Selecting the Tests

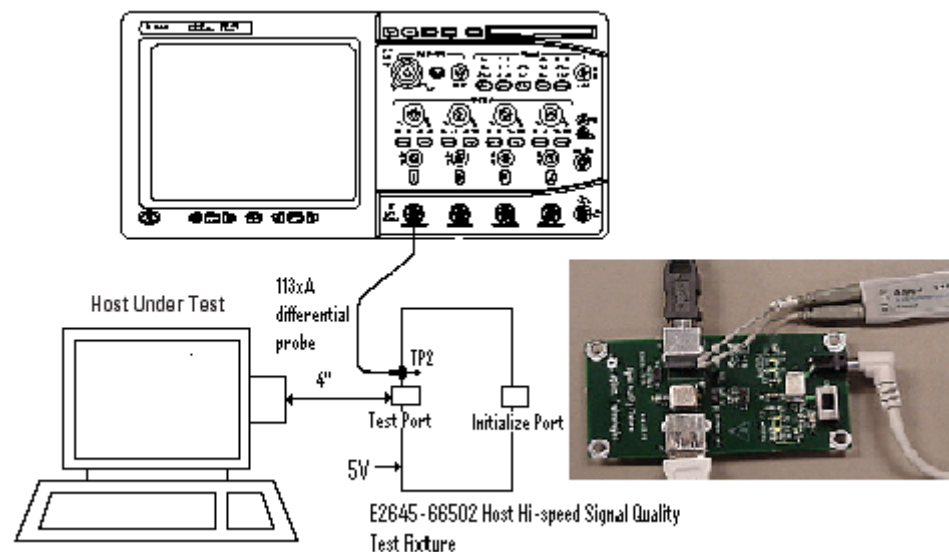


## Configuring the Tests

### Connecting the Equipment

The USB automated test application will prompt you to perform these connection steps:

- 1 Attach the 5V power supply to J5 of the E2645-66502 Host Hi-Speed Signal Quality test fixture and verify the green Power LED (D1) is lit.
  - a Set the Test switch (S1) of the test fixture to **TEST** and verify the yellow TEST LED is lit.
- 2 Attach the differential probe to TP2 of the test fixture, using the damped header adapter. Ensure the + polarity on the probe lines up with D+, which is the pin nearest the USB connector.



- 3 Check **I have completed these instructions.**

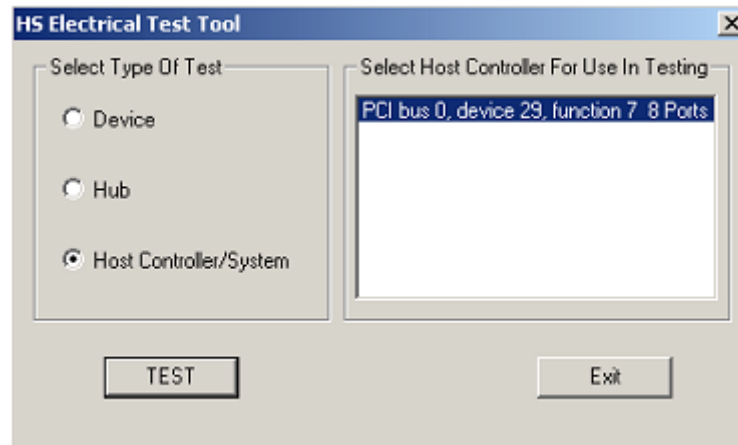
### Running the Tests

- 1 Click **Run Tests.**

### Test Instructions, Part 1

The USB automated test application will prompt you to perform these steps:

- 1 Invoke the HS Electrical Test Tool software on the Hi-Speed Electrical Test Bed computer.
- 2 Select **Host Controller/System** and click the **[TEST]** button to enter the Host Test menu.

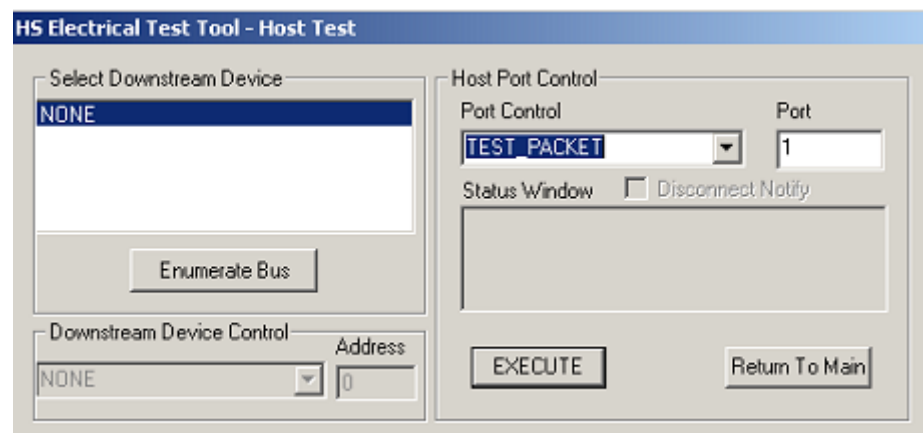


- 3 Click **OK** to close the Test Instructions dialog.

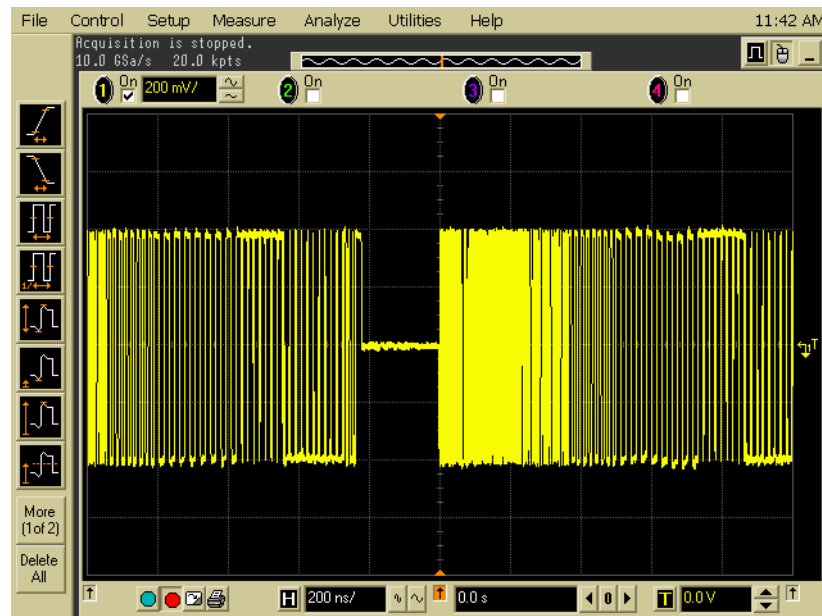
## Test Instructions, Part 2

The USB automated test application will prompt you to perform these steps:

- 1 Connect the [TEST PORT] of the E2645-66502 Host Hi-Speed Signal Quality test fixture into the port under test of the host controller, using the 4" USB cable. The host controller here refers to the Hi-speed Electrical Test Bed Computer that has the HS Electrical Test Tool on it.
- 2 Select **TEST\_PACKET** from the Port Control drop down menu.
- 3 Enter the port number of the port under test and click [**EXECUTE**]. This forces the port under test to continuously transmit test packets.



You should see the transmitted test packet on the oscilloscope as below.



- 4 Click **OK** to close the Test Instructions dialog.

### EL\_6 Rise Time

### EL\_6 Fall Time

### EL\_3 Data Eye and Mask Test

After viewing the test results, click **OK** to close the Test Instructions dialog.

### EL\_7 Non-Monotonic Edge Test

## Viewing Test Results

- 1 When the Testing Complete dialog appears, click **OK**.

The Results tab shows the test results.



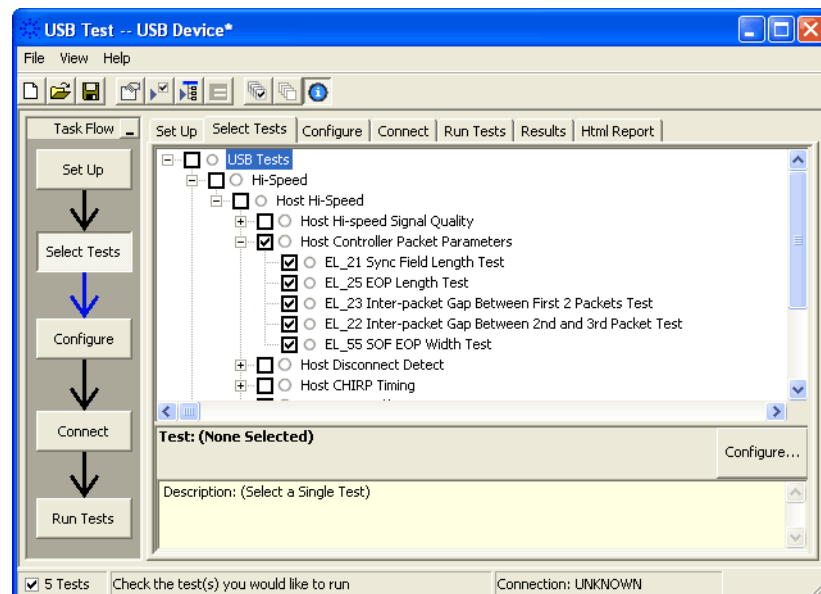
## Host Controller Packet Parameters

### Equipment Used

**Table 26** Equipment Used in Host Controller Packet Parameters Tests

Quantity	Item	Description/Model
1	Oscilloscope	Agilent 5485xA Series or DS080000 Series
1	Differential probe	Agilent 113xA with E2699A or E2678A
1	Header adapter	Agilent 01131-68703
1	Host test bed computer	Any computer with hi-speed USB ports
1	Device Hi-Speed Signal Quality test fixture and 4" USB cable	Agilent E2645-66501
1	Hi-Speed USB hub	Any listed on USB-IF web site
1	5 meter USB 2.0 hi-speed cable	Any listed on USB-IF web site

### Selecting the Tests



## Configuring the Tests

### Connecting the Equipment

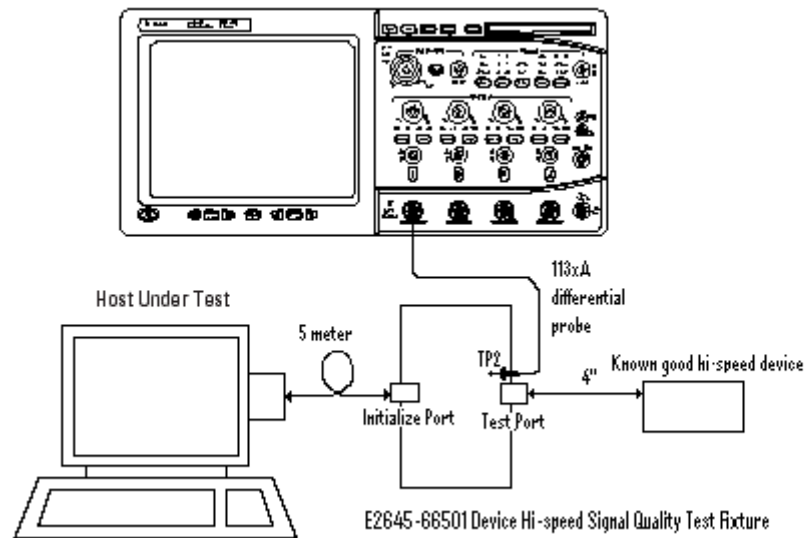
The USB automated test application will prompt you to perform these connection steps:

- 1 Connect the E2645-66501 Device Hi-Speed Signal Quality test fixture ([TEST PORT]) into B receptable of a known good hi-speed hub, using the 4" USB cable.
  - a Apply power to the known good hub. Do not apply 5V to the test fixture.
- 2 Attach the Agilent 113xA differential probe to TP2 of the test fixture, using a damped header adapter.

#### NOTE

Ensure the + polarity on the probe lines up with D+, which is the pin nearest the USB connector.

- 3 Connect the test fixture ([INIT PORT]) into the host controller under test, using the 5 meter USB cable.



- 4 Check I have completed these instructions.

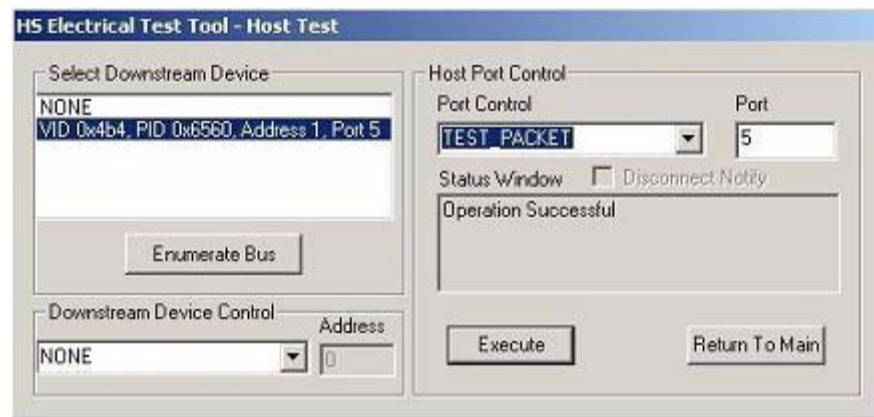
## Running the Tests

- 1 Click **Run Tests**.

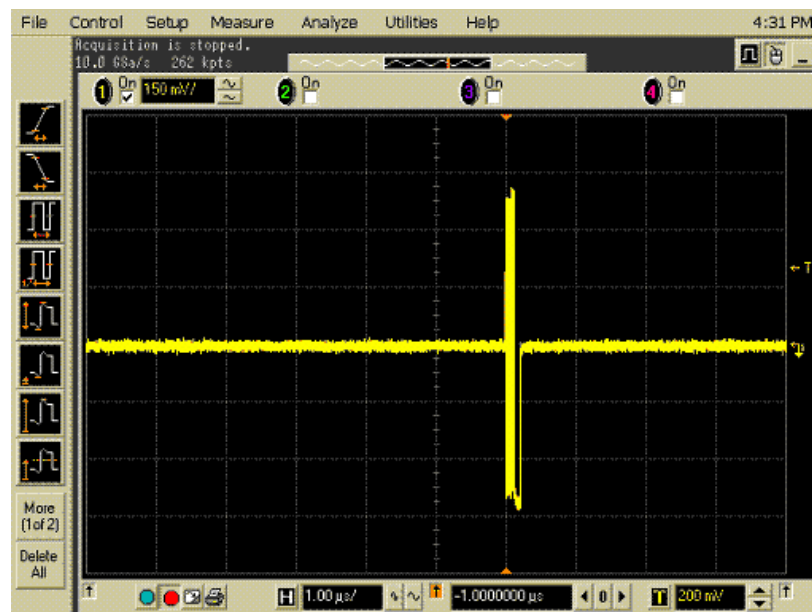
### Test Instructions, Part 1

The USB automated test application will prompt you to perform these steps:

- 1 Click [**Enumerate Bus**] and verify that the device enumerates properly.



- 2 Using the oscilloscope, verify SOFs (Start of Frame packets) are being transmitted by the port under test. You may need to lower the trigger level to somewhat below 400 mV to obtain a trigger.

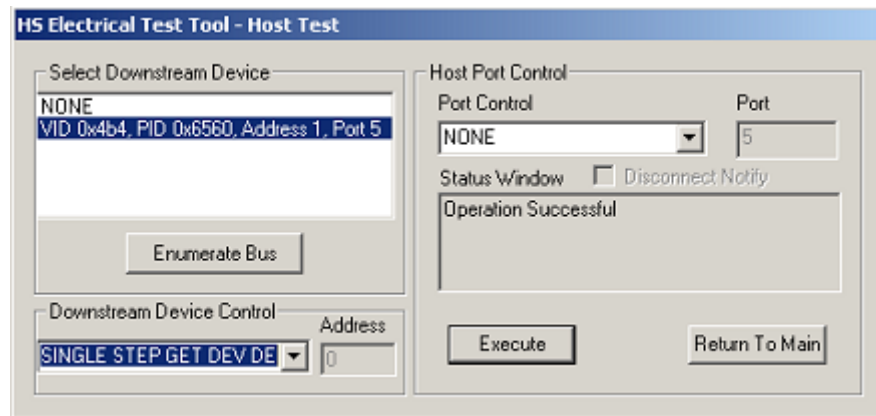


- 3 Click **OK** to close the Test Instructions dialog.

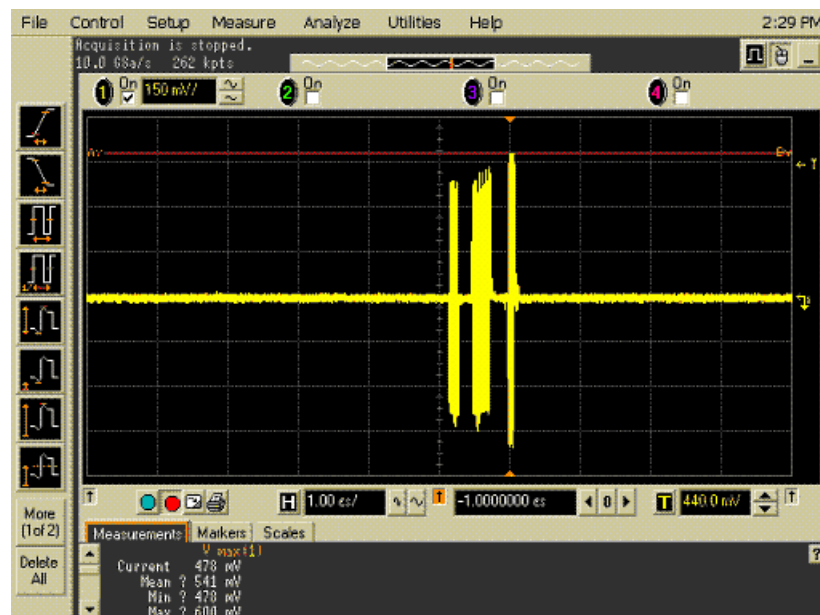
## Test Instructions, Part 2

The USB automated test application will prompt you to perform these steps:

- 1 In the Host Test menu of the HS Electrical Test Tool software, ensure that the device is selected.
- 2 Select **SINGLE STEP GET DEV DESC** from the Downstream Device Control menu and click **[EXECUTE]**.



You should see the transmitted test packet on the oscilloscope as below.

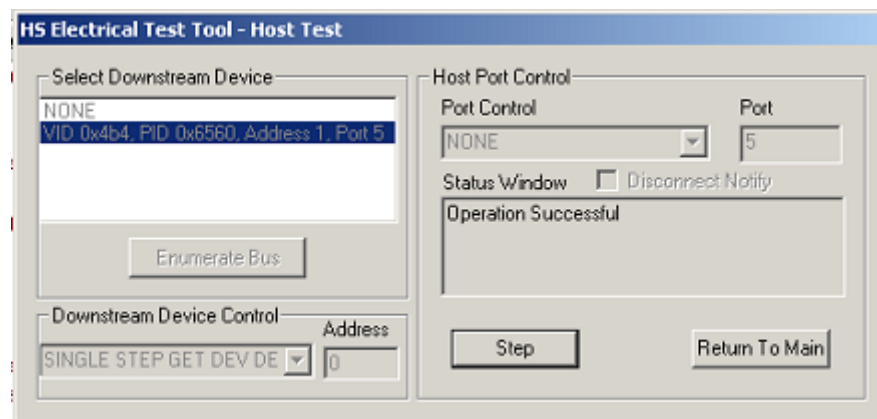


- 3 Click **OK** to close the Test Instructions dialog.

**EL\_21 Sync Field Length Test****EL\_25 EOP Length Test****EL\_23 Inter-packet Gap Between First 2 Packets Test****EL\_22 Inter-packet Gap Between 2nd and 3rd Packet Test****Test Instructions, Part 3**

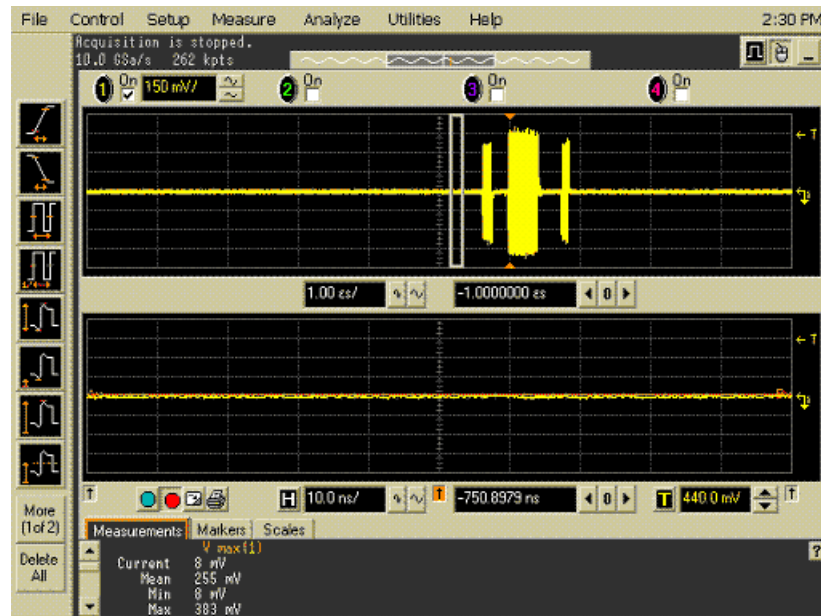
The USB automated test application will prompt you to perform these steps:

- 1 In the Host Test menu of the HS Electrical Test Tool software, click **[STEP]** once again.



You should see the transmitted test packet on the oscilloscope as below.

## 5 Host Hi-Speed Electrical Tests



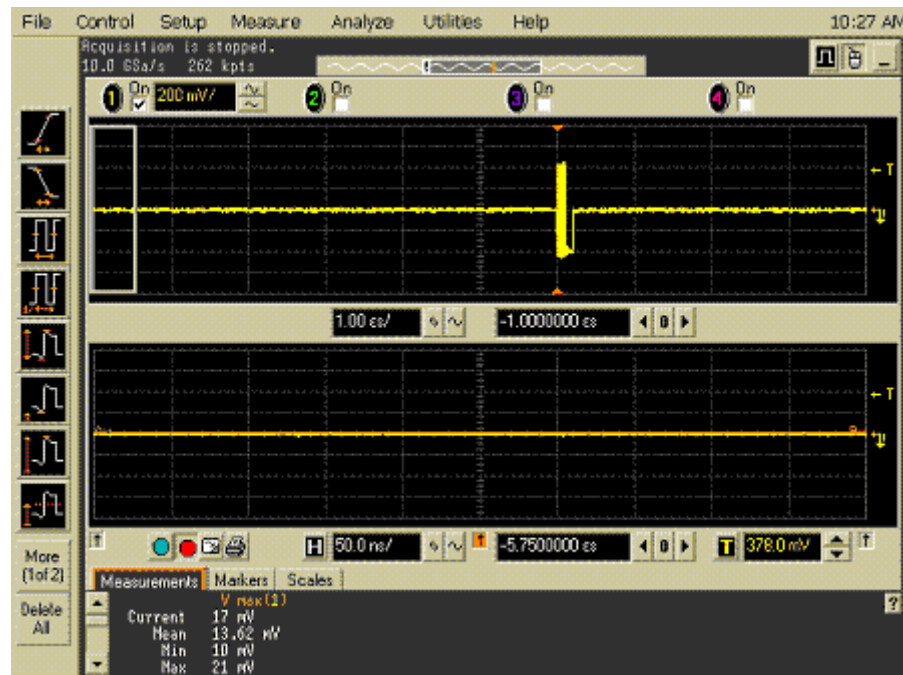
- 2 Click **OK** to close the Test Instructions dialog.

## EL\_55 SOF EOP Width Test

### Test Instructions

The USB automated test application will prompt you to perform these steps:

- 1 Using the oscilloscope, verify SOFs(Start of Frame packets) are being transmitted by the port under test. You may need to lower the trigger level to somewhat below 400mV to obtain a trigger.



- 2 Click **OK** to close the Test Instructions dialog.

### Viewing Test Results

- 1 When the Testing Complete dialog appears, click **OK**.

The Results tab shows the test results.

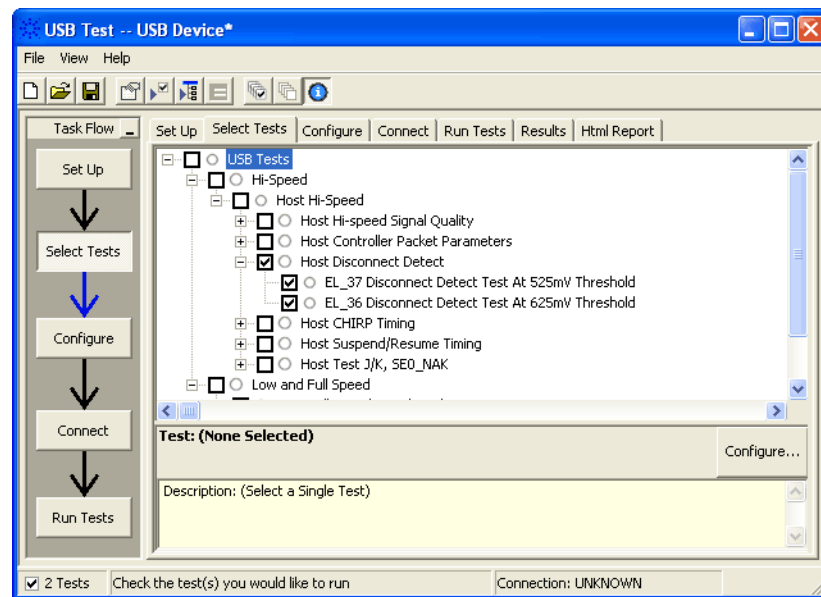
## Host Disconnect Detect

### Equipment Used

**Table 27** Equipment Used in Host Disconnect Detect Tests

Quantity	Item	Description/Model
1	Oscilloscope	Agilent 5485xA Series or DS080000 Series
1	Differential probe	Agilent 113xA with E2699A or E2678A
1	Header adapter	Agilent 01131-68703
1	Host test bed computer	Any computer with hi-speed USB ports
1	Host Disconnect test fixture and 4" USB cable	Agilent E2645-66506
1	5V power supply	Agilent 0950-2546 or equivalent

### Selecting the Tests



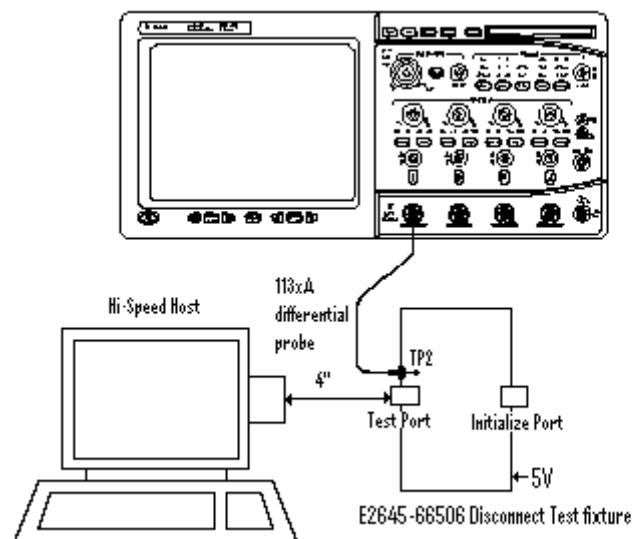


## Configuring the Tests

### Connecting the Equipment

The USB automated test application will prompt you to perform these connection steps:

- 1 Attach the 5V power supply to E2645-66506 Disconnect test fixture (J5).
- 2 Attach the Agilent 113xA differential probe to TP2 of the test fixture, using a damped header adapter. Ensure the + polarity on the probe lines up with D+, which is the pin nearest the USB connector.
- 3 Set the TEST switch to the Test position. This sets the test fixture to emulate a must-not-disconnect threshold.
  - a Verify both the green Power LED (D1) and yellow Test LED (D2) are lit.



- 4 Check I have completed these instructions.

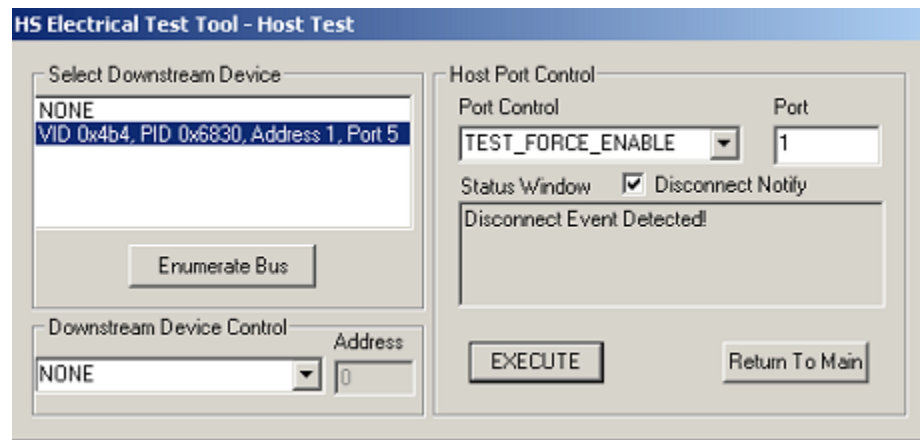
## Running the Tests

- 1 Click **Run Tests**.

## Test Instructions

The USB automated test application will prompt you to perform these steps:

- 1 Attach the [TEST PORT] of the test fixture to the port under test, using the 4" USB cable.
- 2 In the Host Test Menu of the HS Electrical Test Tool, select **TEST\_FORCE\_ENABLE** from the Port Control drop down menu.
- 3 Enter the port number and click **[EXECUTE]** once and ensure operation is successful in the Status Window.
- 4 Click the **Disconnect Notify** check box to monitor the disconnect status in the Status Window.



- 5 Click **OK** to close the Test Instructions dialog.

### EL\_37 Disconnect Detect Test At 525mV Threshold

The USB automated test application will prompt you to answer the question “Does the Status Window display Disconnect Event Detected?”

### EL\_36 Disconnect Detect Test At 625mV Threshold

The USB automated test application will prompt you to: Set the Test switch of the E2645-66506 Disconnect test fixture to the Normal position and verify the yellow TEST LED (D2) is not lit.

The USB automated test application will prompt you to answer the question “Does the Status Window now display Disconnect Event Detected?”

## Viewing Test Results

- 1 When the Testing Complete dialog appears, click **OK**.

The Results tab shows the test results.

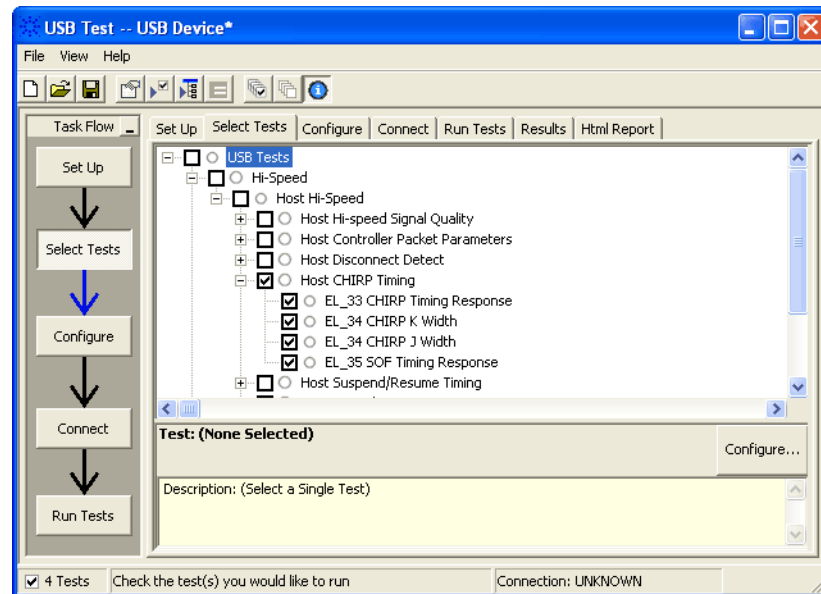
## Host CHIRP Timing

### Equipment Used

**Table 28** Equipment Used in Host CHIRP Timing Tests

Quantity	Item	Description/Model
1	Oscilloscope	Agilent 5485xA Series or DS080000 Series
2	Passive or active probes	Agilent E2697A with 10073C, or 1156A
1	Host test bed computer	Any computer with hi-speed USB ports
1	Host Hi-Speed Signal Quality test fixture and 4" USB cable	Agilent E2645-66502
1	Hi-Speed USB device	Any listed on USB-IF web site
1	5 meter USB 2.0 hi-speed cable	Any listed on USB-IF web site

### Selecting the Tests

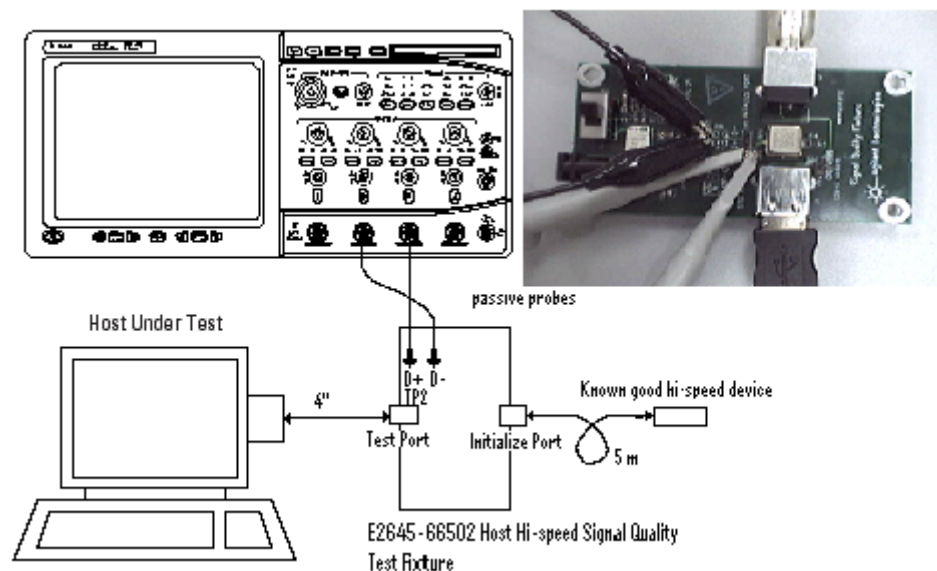


## Configuring the Tests

### Connecting the Equipment

The USB automated test application will prompt you to perform these connection steps:

- 1 Replace the E2645-66506 Disconnect test fixture with the E2645-66502 Host Hi-Speed Signal Quality test fixture. Do not apply 5V to the test fixture.
- 2 Connect the E2697A with 10073C passive probe or the 1156A active probe on Channel 2 to the D- pin at TP2 of the E2645-66502 Host Hi-Speed Signal Quality test fixture.
- 3 Connect the E2697A with 10073C passive probe or the 1156A active probe on Channel 3 to the D+ pin at TP2. D+ on TP2 is the pin closest to the USB connector.
- 4 Connect both probe grounds to leads TP5.
- 5 Connect a known good Hi-Speed device into the [INIT PORT] of the test fixture, using the 5-meter USB cable.
- 6 Connect the [TEST PORT] on the fixture to the port under test, using the 4" USB cable.
- 7 Apply power to the known good Hi-Speed device.



- 8 Check I have completed these instructions.

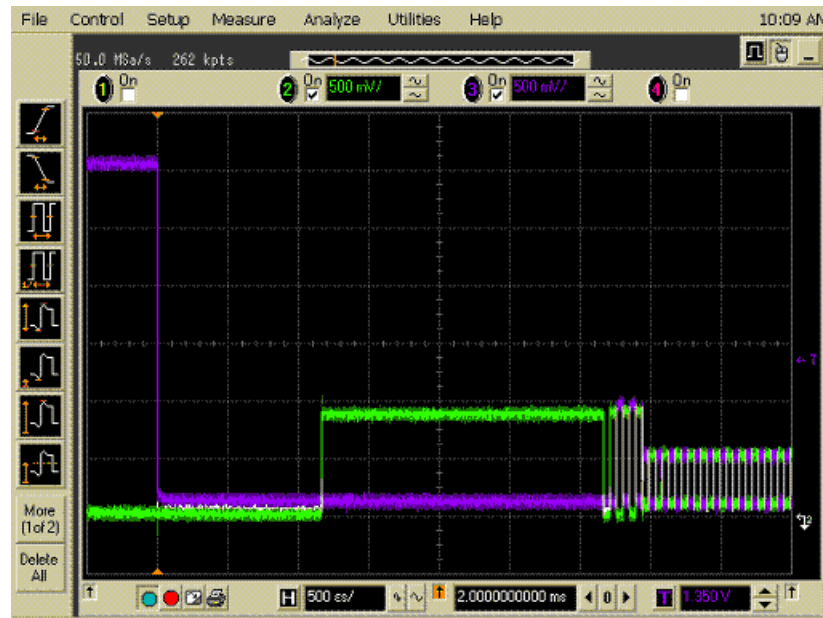
## Running the Tests

- 1 Click **Run Tests**.

## Test Instructions

The USB automated test application will prompt you to perform these steps:

- 1 On the HS Electrical Test Tool software, click [**Enumerate Bus**] once. You should capture the CHIRP handshake as in the below figure.



- 2 Click **OK** to close the Test Instructions dialog.

### EL\_33 CHIRP Timing Response

### EL\_34 CHIRP K Width

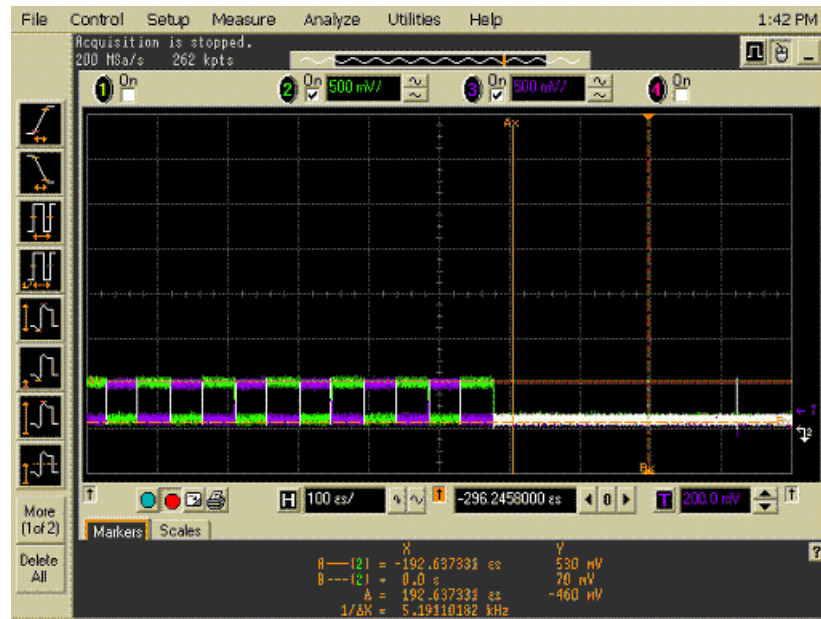
### EL\_34 CHIRP J Width

### EL\_35 S0F Timing Response

The USB automated test application will prompt you to: Unplug the known good device and reattach it.

The USB automated test application will prompt you to perform these steps:

- 1 On the Host Test menu of the HS Electrical Test Tool software, click **[Enumerate Bus]** once. The oscilloscope should capture as in the below figure.



- 2 Click **OK** to close the Test Instructions dialog.

## Viewing Test Results

- 1 When the Testing Complete dialog appears, click **OK**.

The Results tab shows the test results.

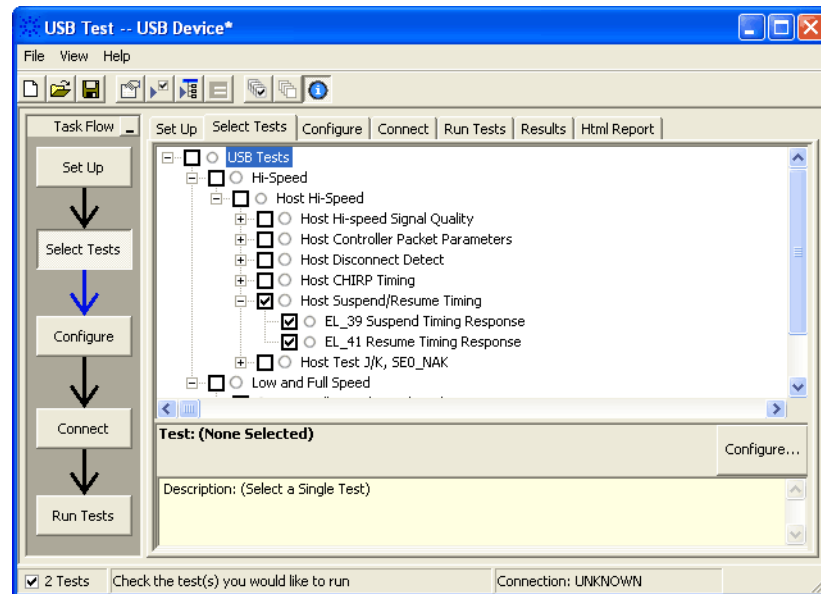
## Host Suspend/Resume Timing

### Equipment Used

**Table 29** Equipment Used in Host Suspend/Resume Timing Tests

Quantity	Item	Description/Model
1	Oscilloscope	Agilent 5485xA Series or DS080000 Series
2	Passive or active probes	Agilent E2697A with 10073C, or 1156A
1	Host test bed computer	Any computer with hi-speed USB ports
1	Host Hi-Speed Signal Quality test fixture and 4" USB cable	Agilent E2645-66502
1	Hi-Speed USB device	Any listed on USB-IF web site
1	5 meter USB 2.0 hi-speed cable	Any listed on USB-IF web site

### Selecting the Tests



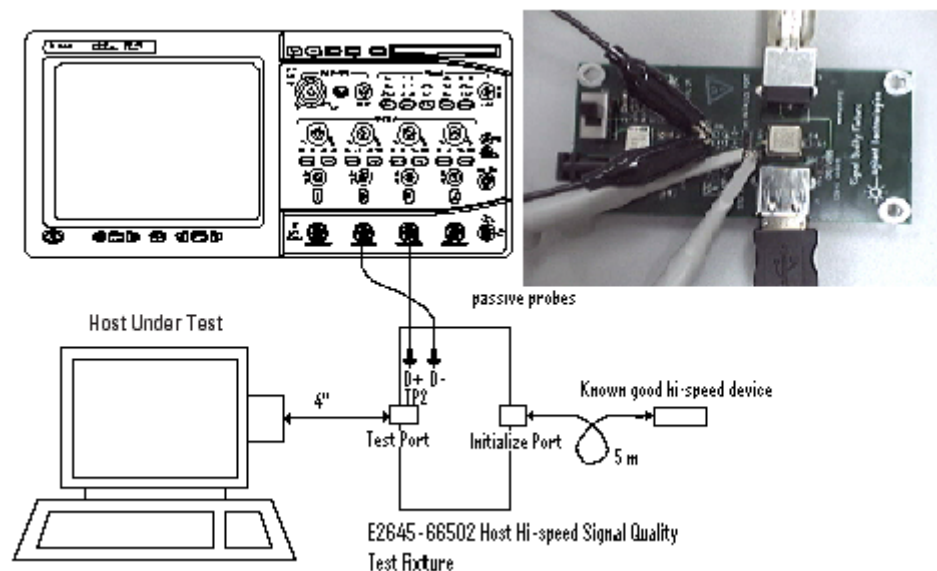


## Configuring the Tests

### Connecting the Equipment

The USB automated test application will prompt you to perform these connection steps:

- 1 Replace the E2645-66506 Disconnect test fixture with the E2645-66502 Host Hi-Speed Signal Quality test fixture. Do not apply 5V to the test fixture.
- 2 Connect the E2697A with 10073C passive probe or the 1156A active probe on Channel 2 to the D- pin at TP2 of the E2645-66502 Host Hi-Speed Signal Quality test fixture.
- 3 Connect the E2697A with 10073C passive probe or the 1156A active probe on Channel 3 to the D+ pin at TP2. D+ on TP2 is the pin closest to the USB connector.
- 4 Connect both probe grounds to leads TP5.
- 5 Connect a known good Hi-Speed device into the [INIT PORT] of the test fixture, using the 5-meter USB cable.
- 6 Connect the [TEST PORT] on the fixture to the port under test, using the 4" USB cable.
- 7 Apply power to the known good Hi-Speed device.



- 8 Check I have completed these instructions.

## Running the Tests

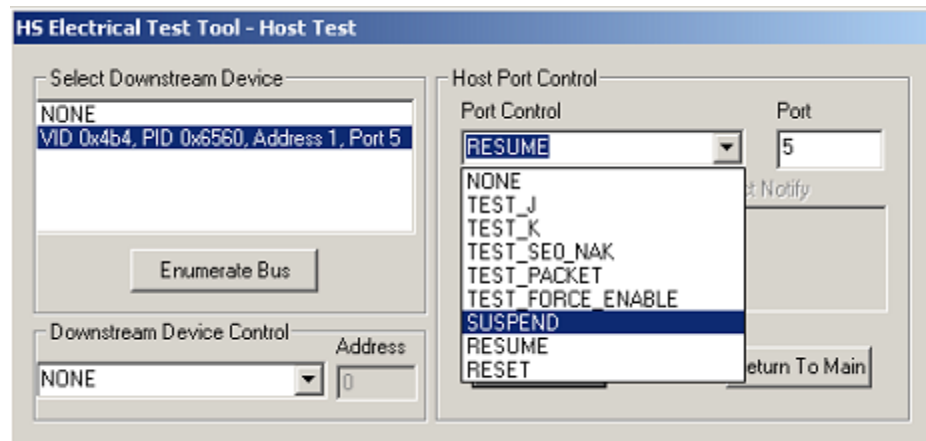
- 1 Click **Run Tests**.

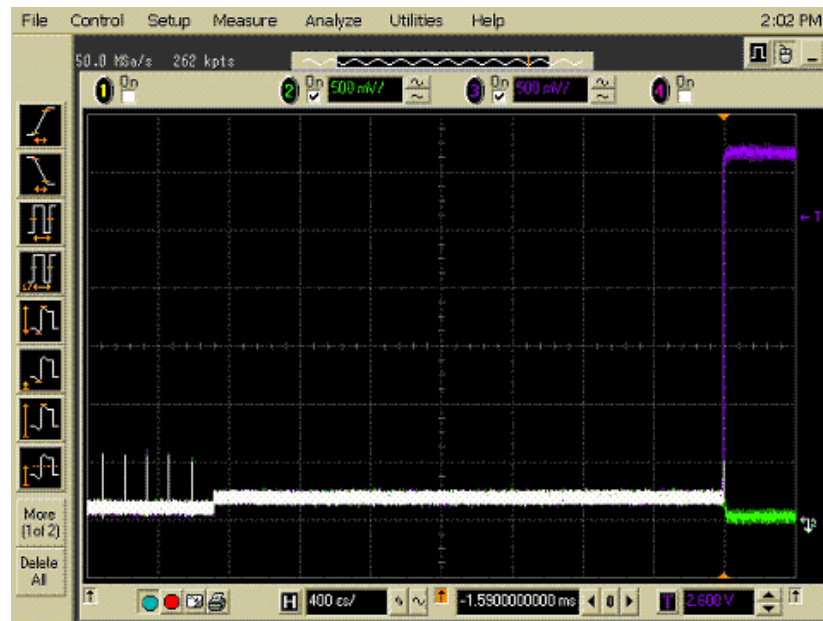
## Test Instructions

### EL\_39 Suspend Timing Response

The USB automated test application will prompt you to perform these steps:

- 1 On the Host Test menu of the HS Electrical Test Tool software, click **[Enumerate Bus]** once.
- 2 Select **SUSPEND** from the Port Control drop down menu.
- 3 Enter the port number. Click **[EXECUTE]** once to place the port into suspend. The captured transition should be as in the figure below.



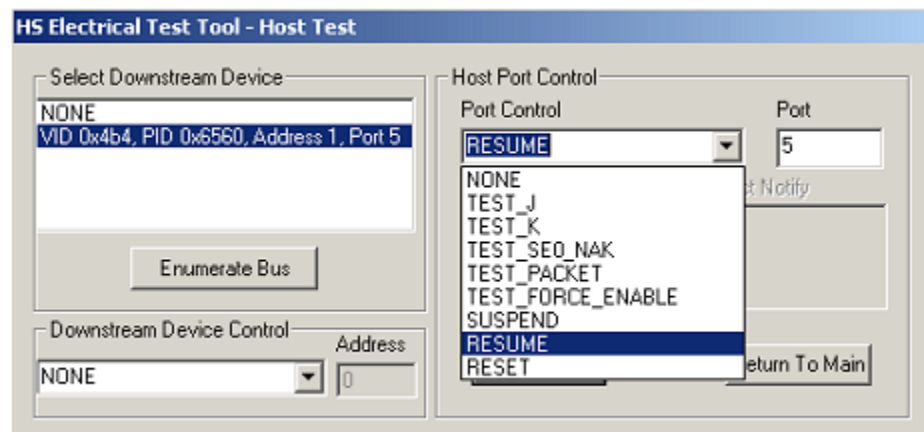


- 4 Click **OK** to close the Test Instructions dialog.

#### EL\_41 Resume Timing Response

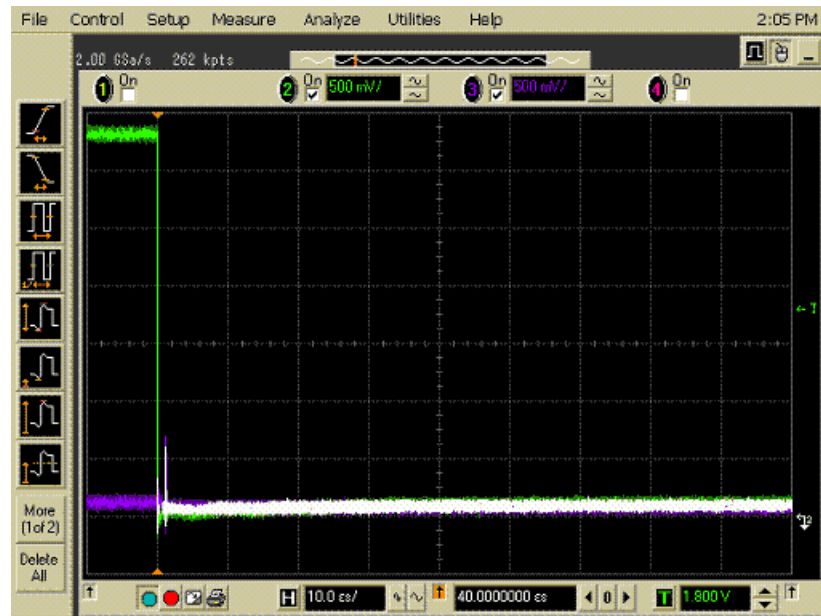
The USB automated test application will prompt you to perform these steps:

- 1 On the Host Test menu of the HS Electrical Test Tool software, select **RESUME** from the Port Control drop down menu.
- 2 Enter the port number. Click **[EXECUTE]** once to resume the port.



The captured transition should be as in the figure below.

## 5 Host Hi-Speed Electrical Tests



- 3 Click **OK** to close the Test Instructions dialog.

### Viewing Test Results

- 1 When the Testing Complete dialog appears, click **OK**.

The Results tab shows the test results.

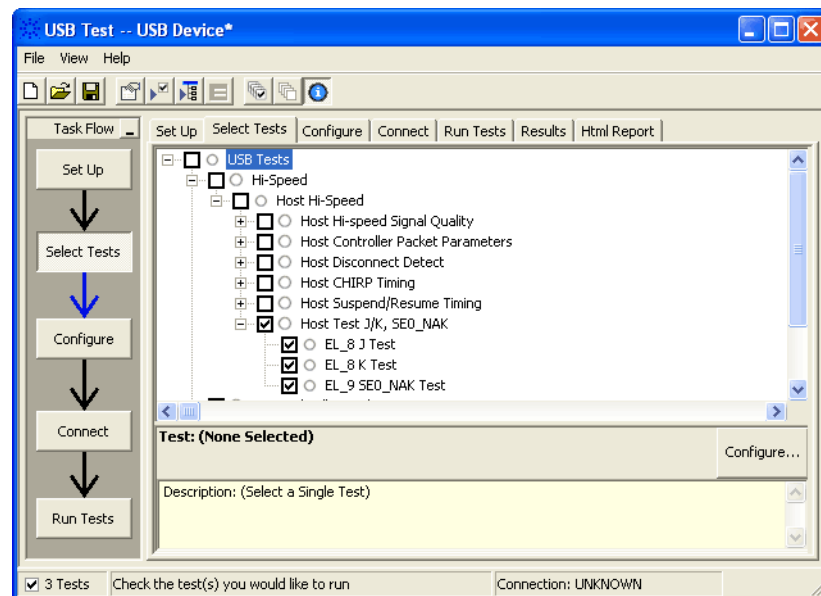
## Host Test J/K, SE0\_NAK

### Equipment Used

**Table 30** Equipment Used in Host Test J/K, SE0\_NAK Tests

Quantity	Item	Description/Model
1	Digital Multimeter (DMM)	Agilent 34401A or equivalent
1	Host test bed computer	Any computer with hi-speed USB ports
1	Host Hi-Speed Signal Quality test fixture and 4" USB cable	Agilent E2645-66502
1	5V power supply	Agilent 0950-2546 or equivalent

### Selecting the Tests

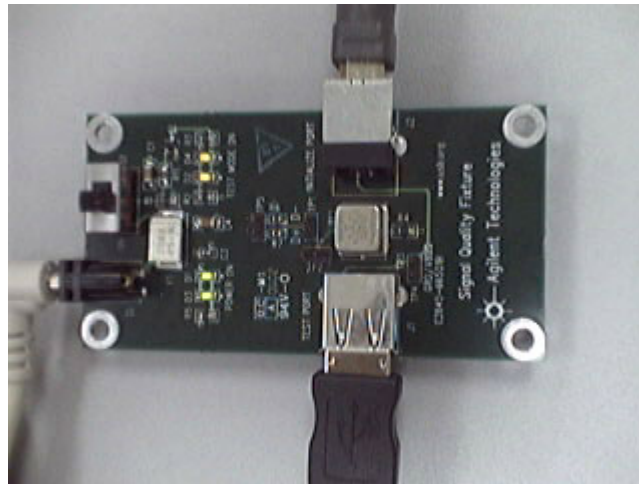


## Configuring the Tests

### Connecting the Equipment

The USB automated test application will prompt you to perform these connection steps:

- 1 Attach the 5V power supply to J5 of the E2645-66502 Host High-Speed Signal Quality test fixture. Verify the green Power LED(D1) is lit. Place the TEST switch (S1) in the Test position and the yellow Test LED(D2) is lit.
- 2 Connect the [TEST PORT] of the test fixture into the port of under test, using the 4" USB cable.



- 3 Check I have completed these instructions.

### Running the Tests

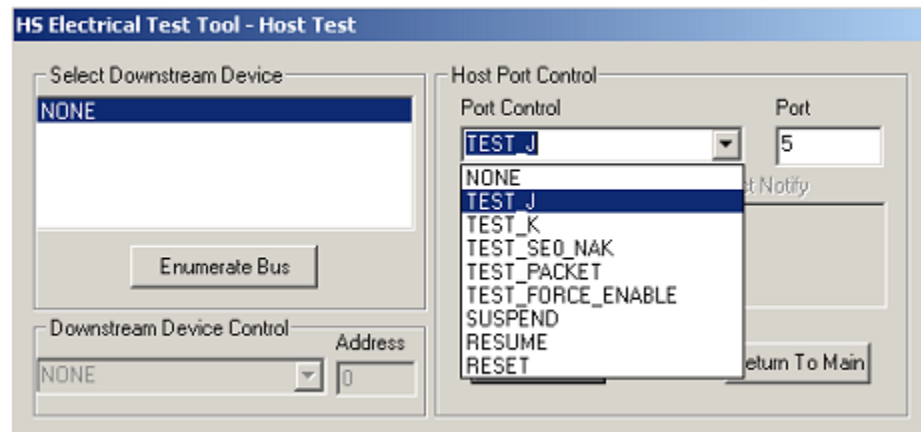
- 1 Click **Run Tests**.

### Test Instructions

#### EL\_8 J Test

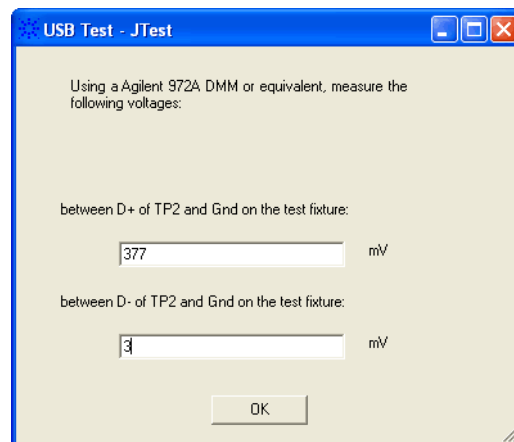
The USB automated test application will prompt you to perform these steps:

- 1 On the Host Test menu of the HS Electrical Test Tool software, select **TEST\_J** from the Port Control drop down menu.
- 2 Enter the port number. Click **[EXECUTE]** once to place the port under test into the TEST\_J test mode.



- 3 Click **OK** to close the Test Instructions dialog.

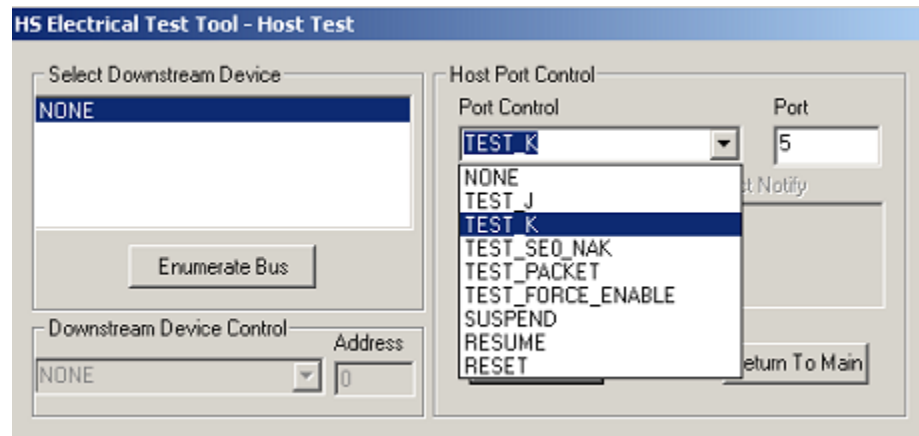
The USB automated test application will prompt you for the following voltage measurements:



### EL\_8 K Test

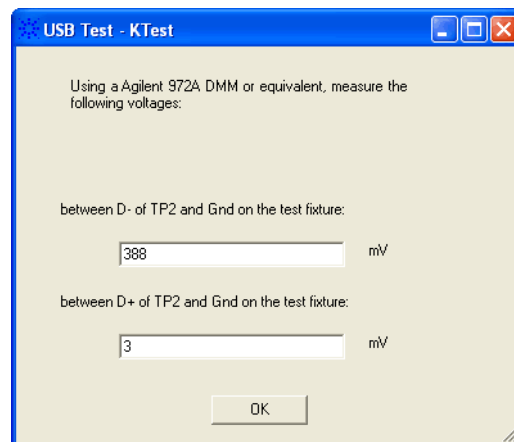
The USB automated test application will prompt you to perform these steps:

- 1 On the Host Test menu of the HS Electrical Test Tool software, select **TEST\_K** from the Port Control drop down menu.
- 2 Enter the port number. Click **[EXECUTE]** once to place the port under test into the TEST\_K test mode.



- 3 Click **OK** to close the Test Instructions dialog.

The USB automated test application will prompt you for the following voltage measurements:

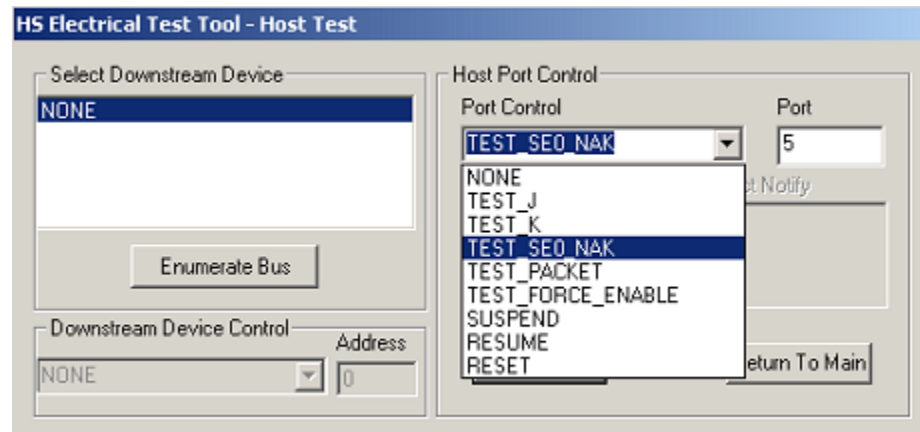


### EL\_9 SE0\_NAK Test

The USB automated test application will prompt you to perform these steps:

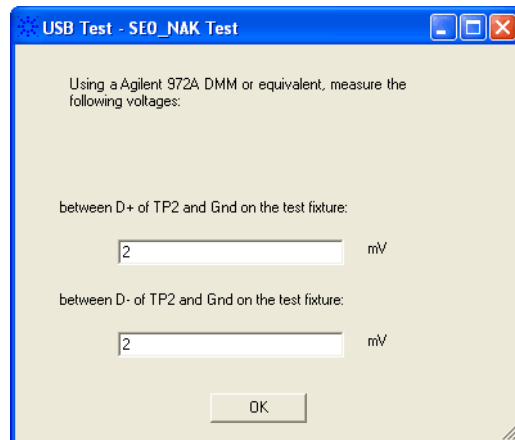
- 1 On the Host Test menu of the HS Electrical Test Tool software, select **TEST\_SE0\_NAK** from the Port Control drop down menu.
- 2 Enter the port number. Click **[EXECUTE]** once to place the port under test into the TEST\_SE0\_NAK test mode.





- 3 Click **OK** to close the Test Instructions dialog.

The USB automated test application will prompt you for the following voltage measurements:



## Viewing Test Results

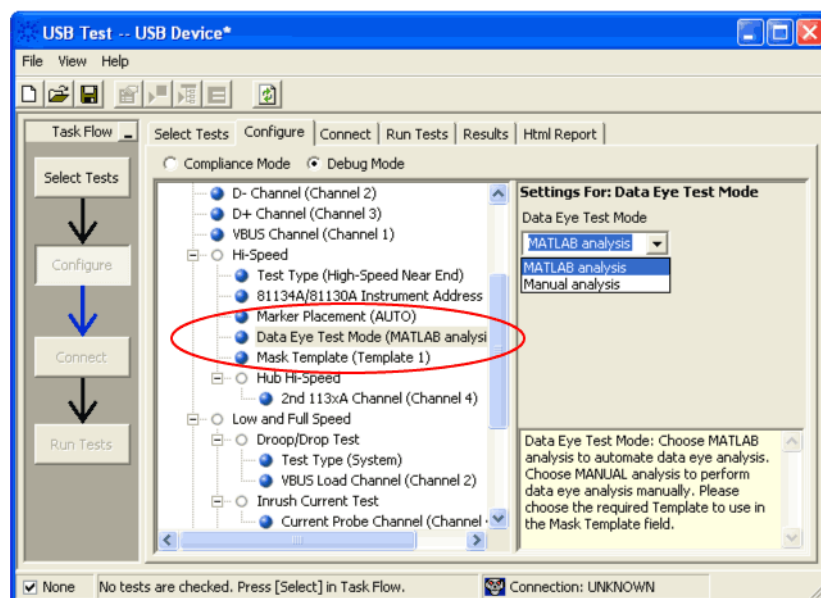
- 1 When the Testing Complete dialog appears, click **OK**.

The Results tab shows the test results.



## 6 Troubleshooting Hi-Speed Test Failures

In the Configure tab's Debug Mode, there are three options that can help you troubleshoot hi-speed test failures:



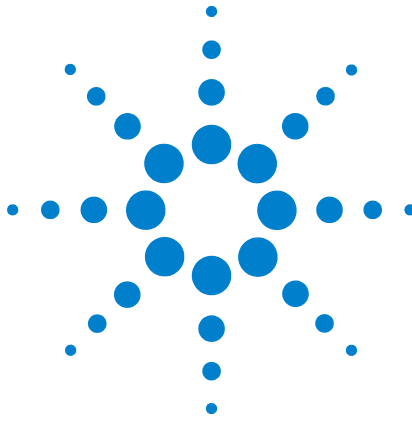
**Figure 3** Debug Mode Options for Hi-Speed Testing

- **Marker Placement** – Lets you manually adjust the markers around the required packet/pattern before proceeding with the test analysis. When “MANUAL” is selected, the automated search for the correct pattern/packet to analyze is turned off.
- **Data Eye Test Mode** – Lets you perform the eye test without using the MATLAB scripts. The oscilloscope will form the eye diagram using the E2688A serial data analysis (SDA) and clock recovery software option.
- **Mask Template** – If you choose to use the SDA software option to perform data eye tests, you need to select the appropriate mask template to use for the eye diagram.

Also useful for debugging problems is the EZJIT analysis software option for the oscilloscope.

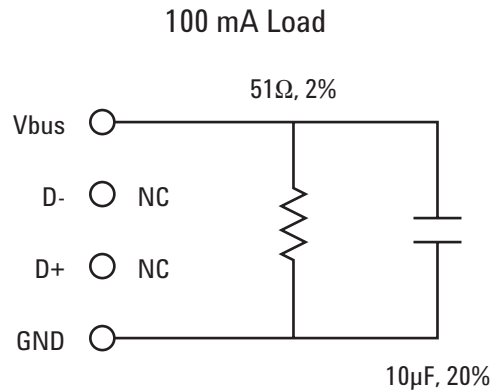




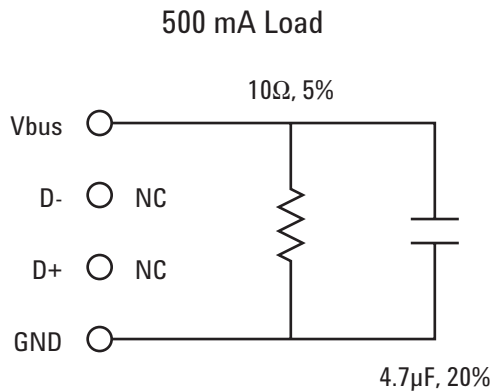


## 7 Low and Full Speed Tests

Droop/Drop Test [167](#)  
Inrush Current Test [174](#)  
Signal Integrity Test [177](#)  
Back-Voltage Test [198](#)



**Figure 4** 100 mA Load Board Schematic



**Figure 5** 500 mA Load Board Schematic





## Droop/Drop Test

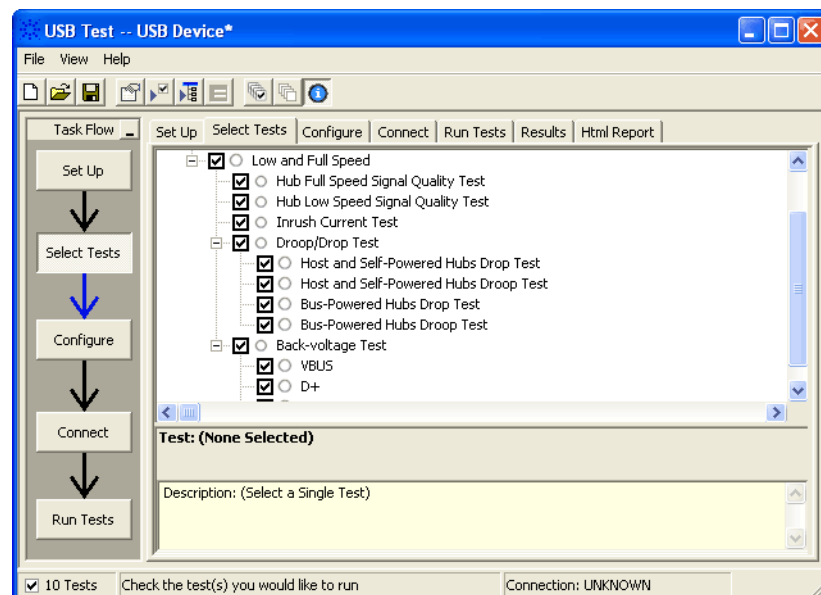
### Host and Self-Powered Hubs

#### Equipment Used

**Table 31** Equipment Used in Host and Self-Powered Hubs Droop/Drop Tests

Quantity	Item	Description/Model
1	Oscilloscope	Agilent 5485xA Series, DS080000 Series, 54831B/D, or 54832B/D
2	Passive or active probes	For 5485x Series and DS080000 Series oscilloscopes: <ul style="list-style-type: none"> <li>• Agilent E2697A with 10073C, or 1156A</li> </ul> For 54831B/D and 54832B/D oscilloscopes: <ul style="list-style-type: none"> <li>• Agilent 1165A</li> </ul>
1	Digital Multimeter (DMM)	Agilent 34401A or equivalent
1	SQiDD board	Agilent E2646A
1	500 mA load board	(see the schematic in <a href="#">Figure 5</a> on page 165)
1	1 meter USB cable	Any listed on USB-IF web site

#### Selecting the Tests

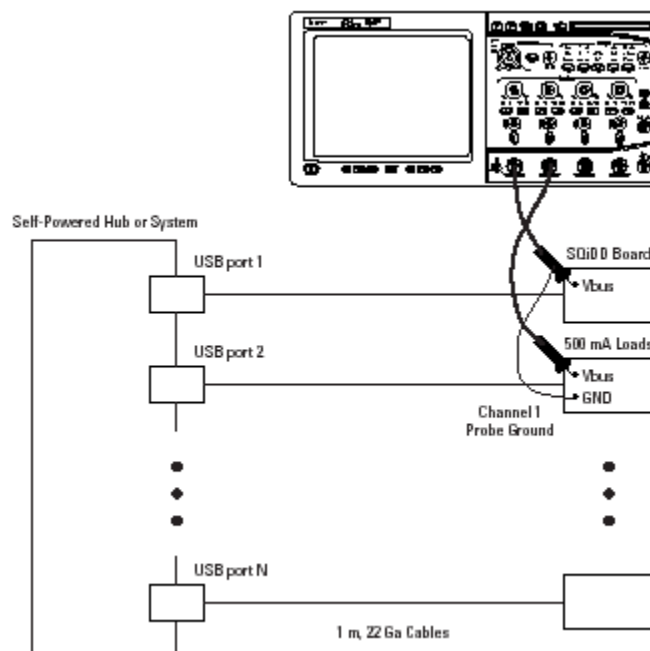


## Configuring the Tests

### Connecting the Equipment

The USB automated test application will prompt you to perform these connection steps:

- 1 For 54831B/D and 54832B/D oscilloscopes, use 1165A passive probes. For the 5485XA or DSO80000 series oscilloscopes, use E2697A high-impedance converter with 10:1 passive probes, or 1156A active probes.
- 2 Connect 500mA load boards to all but the adjacent port on the host or self-powered hub under test. Connect the SQiDD board to the hub/host port under test prior to connecting the load board .
- 3 Attach the passive probes to the oscilloscope's Channel 1 and Channel 2 inputs.
- 4 Connect the Channel 1 probe to Vbus on the SQiDD board with the probe's ground to GND on one of the 500mA load boards. This is the port under test.
- 5 Connect the Channel 2 probe to the Vbus test point on the load board connected adjacent to the USB port to be measured. This provides the oscilloscope trigger.



- 6 Check I have completed these instructions.



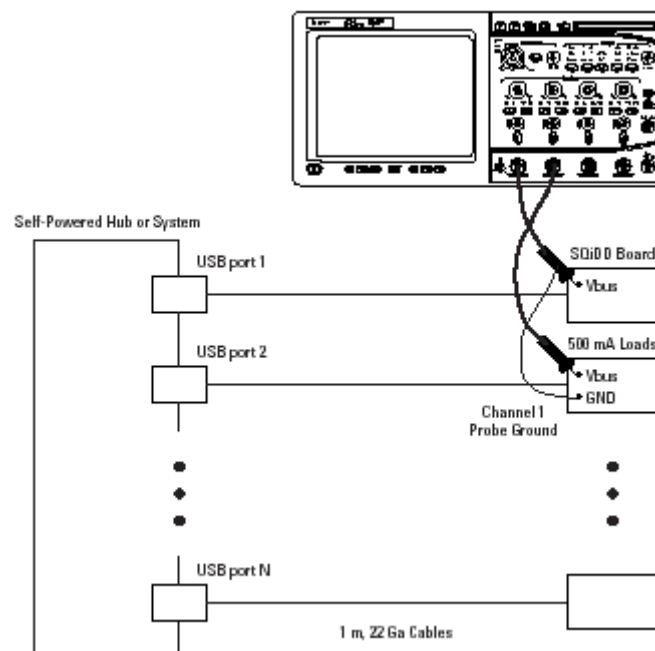
## Running the Tests

- 1 Click **Run Tests**.

### Test Instructions

The USB automated test application will prompt you to perform these steps:

- 1 For 54831B/D and 54832B/D oscilloscopes, use 1165A passive probes. For the 5485XA or DSO80000 series oscilloscopes, use E2697A high-impedance converter with 10:1 passive probes, or 1156A active probes.
- 2 Connect 500 mA load boards to all but the adjacent port on the host or self-powered hub under test. Connect the SQiDD board to the hub/host port under test prior to connecting the load board .
- 3 Attach the passive probes to the oscilloscope's Channel 1 and Channel 2 inputs.
- 4 Connect the Channel 1 probe to Vbus on the SQiDD board with the probe's ground to GND on one of the 500mA load boards. This is the port under test.
- 5 Connect the Channel 2 probe to the Vbus test point on the load board connected adjacent to the USB port to be measured. This provides the oscilloscope trigger.



- 6 Click **OK** to close the Test Instructions dialog.

### Viewing Test Results

- 1 When the Testing Complete dialog appears, click **OK**.

The Results tab shows the test results.

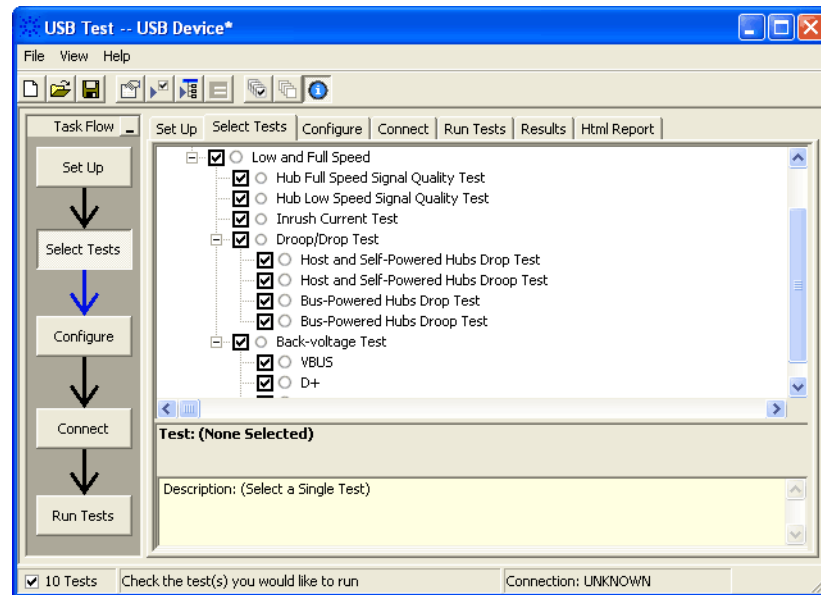
## Bus-Powered Hubs

### Equipment Used

**Table 32** Equipment Used in Bus-Powered Hubs Droop/Drop Tests

Quantity	Item	Description/Model
1	Oscilloscope	Agilent 5485xA Series, DS080000 Series, 54831B/D, or 54832B/D
2	Passive or active probes	For 5485x Series and DS080000 Series oscilloscopes: <ul style="list-style-type: none"> <li>• Agilent E2697A with 10073C, or 1156A</li> </ul> For 54831B/D and 54832B/D oscilloscopes: <ul style="list-style-type: none"> <li>• Agilent 1165A</li> </ul>
1	Digital Multimeter (DMM)	Agilent 34401A or equivalent
1	SQiDD board	Agilent E2646A
1	100 mA load board	(see the schematic in <a href="#">Figure 4</a> on page 165)
1	1 meter USB cable	Any listed on USB-IF web site

## Selecting the Tests

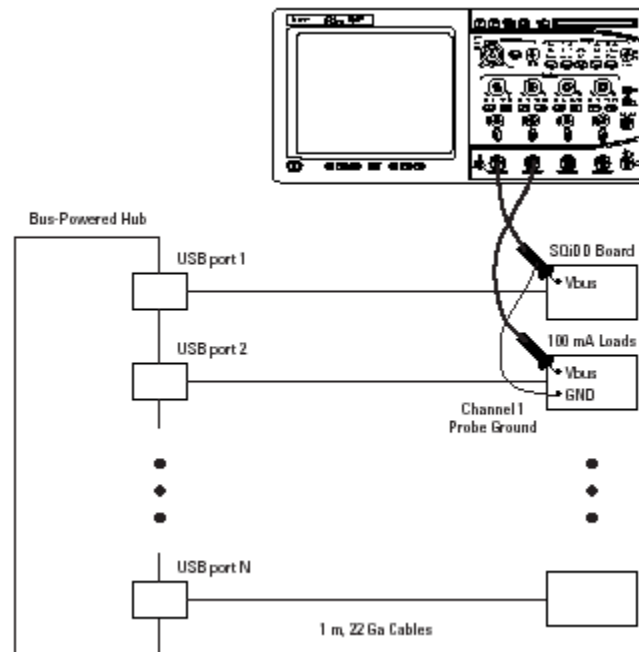


## Configuring the Tests

### Connecting the Equipment

The USB automated test application will prompt you to perform these connection steps:

- 1 For 54831B/D and 54832B/D oscilloscopes, use 1165A passive probes. For the 5485XA or DSO80000 series oscilloscopes, use E2697A high-impedance converter with 10:1 passive probes, or 1156A active probes.
- 2 Connect 100mA load boards to all but the adjacent port on the bus-powered hub under test. Connect the SQiDD board to the hub/host port under test prior to connecting the load board.
- 3 Attach the passive probes to the oscilloscope's Channel 1 and Channel 2 inputs.
- 4 Connect the Channel 1 probe to Vbus on the SQiDD board with the probe's ground to GND on one of the 100mA load boards. This is the port under test.
- 5 Connect the Channel 2 probe to the Vbus test point on the load board connected adjacent to the USB port to be measured. This provides the oscilloscope trigger.



6 Check I have completed these instructions.

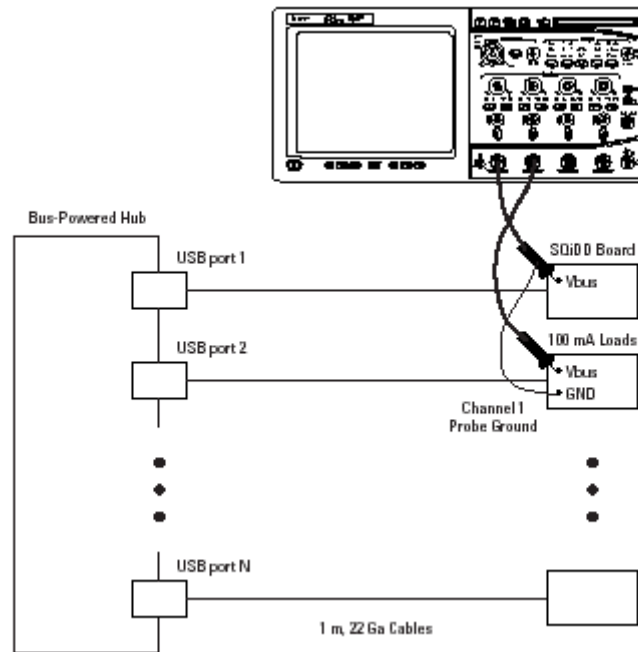
### Running the Tests

1 Click **Run Tests**.

### Test Instructions

The USB automated test application will prompt you to perform these steps:

- 1 For 54831B/D and 54832B/D oscilloscopes, use 1165A passive probes. For the 5485XA or DSO80000 series oscilloscopes, use E2697A high-impedance converter with 10:1 passive probes, or 1156A active probes.
- 2 Connect 100 mA load boards to all but the adjacent port on the bus-powered hub under test. Connect the SQiDD board to the hub/host port under test prior to connecting the load board .
- 3 Attach the passive probes to the oscilloscope's Channel 1 and Channel 2 inputs.
- 4 Connect the Channel 1 probe to Vbus on the SQiDD board with the probe's ground to GND on one of the 100 mA load boards. This is the port under test.
- 5 Connect the Channel 2 probe to the Vbus test point on the load board connected adjacent to the USB port to be measured. This provides the oscilloscope trigger.



- 6 Click **OK** to close the Test Instructions dialog.

### Viewing Test Results

- 1 When the Testing Complete dialog appears, click **OK**.  
The Results tab shows the test results.

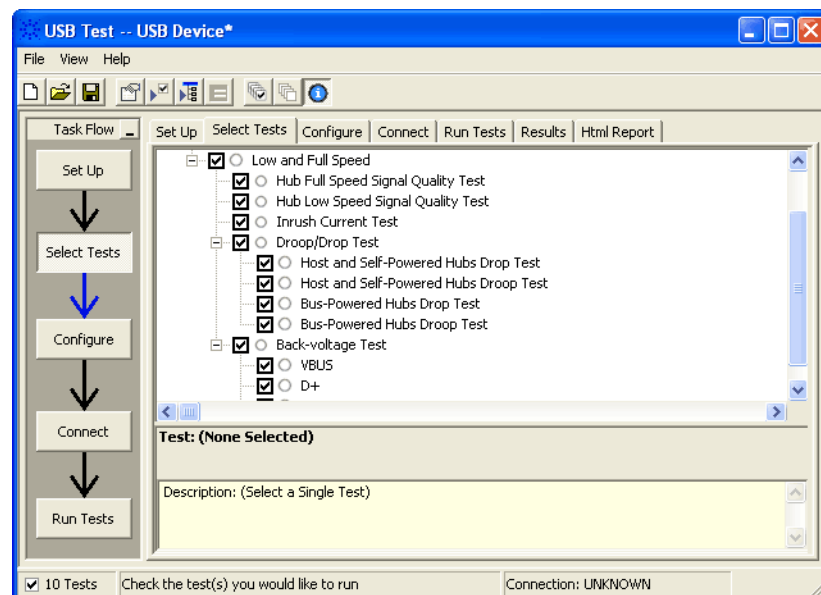
## Inrush Current Test

### Equipment Used

**Table 33** Equipment Used in Inrush Current Test

Quantity	Item	Description/Model
1	Oscilloscope	Agilent 5485xA Series, DS080000 Series, 54831B/D, or 54832B/D
1	Current probe	For 5485x Series and DS080000 Series oscilloscopes: <ul style="list-style-type: none"> <li>Agilent E2697A high impedance converter, N2774A current probe, and N2775A power supply</li> </ul> For 54831B/D and 54832B/D oscilloscopes: <ul style="list-style-type: none"> <li>Agilent 1147A</li> </ul>
1	Digital Multimeter (DMM)	Agilent 34401A or equivalent
1	SQiDD board	Agilent E2646A
1	USB self-powered hub	Any listed on USB-IF web site
1	1 meter USB cable	Any listed on USB-IF web site

### Selecting the Tests



## Configuring the Tests

### Connecting the Equipment

The USB automated test application will prompt you to perform these connection steps:

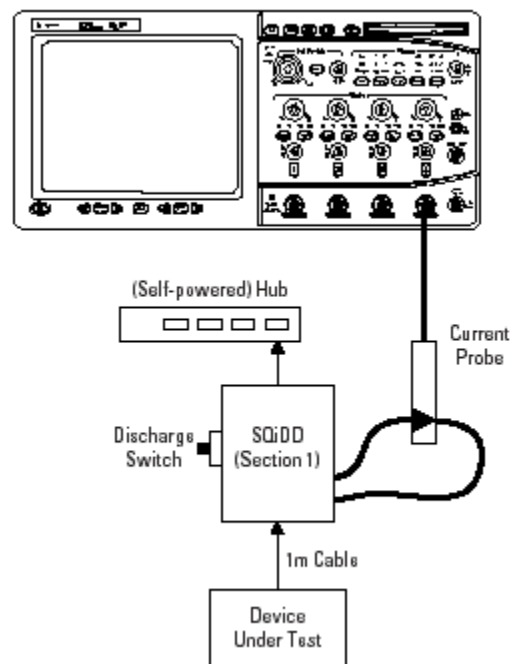
**1** Attach the current probe:

For the 54831B/D or 54832B/D oscilloscope, attach the 1147A current probe to the oscilloscope's Channel 4 input.

For the 54853A, 54854A, 54855A oscilloscope:

- a** Attach the E2697A high-impedance connector to the Channel 4 input.
- b** Attach the N2774A current probe to the E2697A.
- c** Attach the N2775A power supply to the N2774A.
- d** Choose the Setup->Channel 4->Probes->Configure Probing System command and select "Connect N2774A Probe".

**2** Zero the current probe.



**3** Check I have completed these instructions.

## Running the Tests

- 1 Click **Run Tests**.

### Test Instructions, Part 1

The USB automated test application will prompt you to perform these steps:

- 1 Attach the current probe to the current loop on the SQiDD board with the arrow on the probe toward the device under test.
- 2 Attach the device under test to the SQiDD board.
- 3 Place the switch on the SQiDD board to the discharge position (opposite the ON position) .
- 4 Disconnect the device under test from the SQiDD board.
- 5 Place the switch on the SQiDD board to the ON position.
- 6 Click **OK** to close the Test Instructions dialog.

### Test Instructions, Part 2

The USB automated test application will prompt you to perform these steps:

- 1 Re-connect the device under test to the SQiDD board in order to capture the inrush current waveform.
- 2 Click **OK** to close the Test Instructions dialog.

### Viewing Test Results

- 1 When the Testing Complete dialog appears, click **OK**.

The Results tab shows the test results.



## Signal Integrity Test

### Host Downstream Signal Quality Test

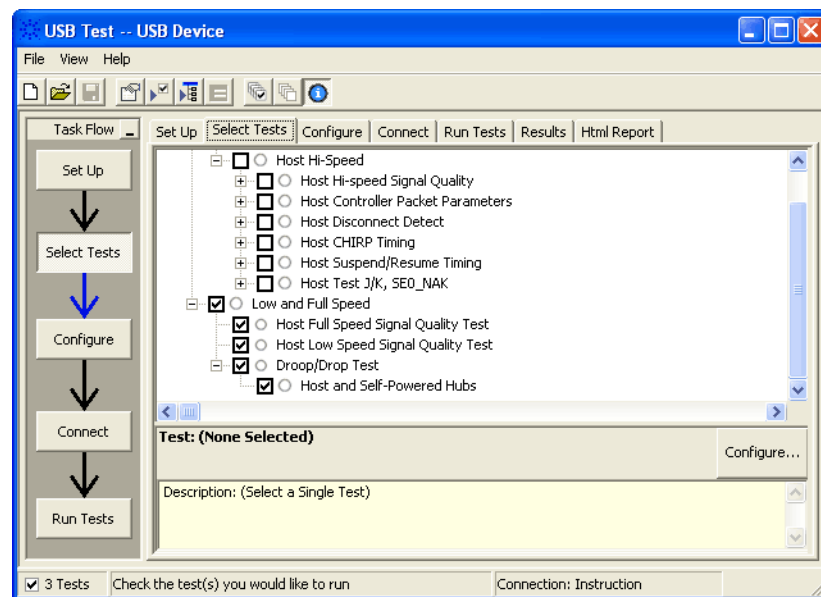
#### Host Low Speed Test

#### Equipment Used

**Table 34** Equipment Used in Host Downstream Low Speed Signal Quality Test

Quantity	Item	Description/Model
1	Oscilloscope	Agilent 5485xA Series, DS080000 Series, 54831B/D, or 54832B/D
2	Passive or active probes	For 5485x Series and DS080000 Series oscilloscopes: <ul style="list-style-type: none"> <li>• Agilent E2697A with 10073C, or 1156A</li> </ul> For 54831B/D and 54832B/D oscilloscopes: <ul style="list-style-type: none"> <li>• Agilent 1165A</li> </ul>
1	Host test bed computer	Any computer with hi-speed USB ports
1	SQiDD board	Agilent E2646A
1	low speed USB device	Logitech mouse, P/N 830311-1000, Model #: M-BB48

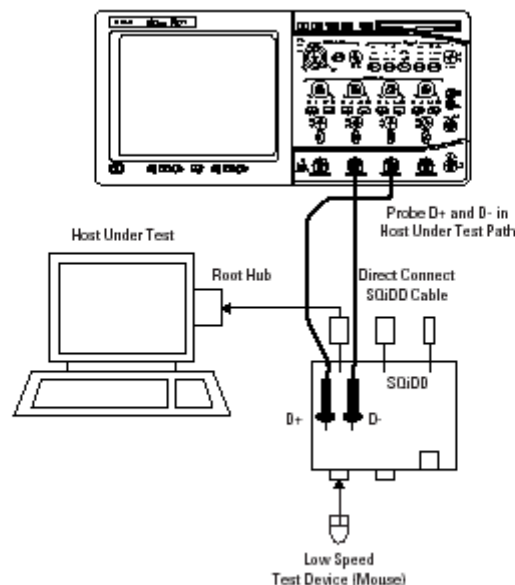
#### Selecting the Tests



**Configuring the Tests** Make sure you set the Test Type configuration option to “Low-Speed Near End” before running the test.

**Connecting the Equipment** The USB automated test application will prompt you to perform these connection steps:

- 1 For 54831B/D and 54832B/D oscilloscopes, use 1165A passive probes. For the 5485XA or DSO80000 series oscilloscopes, use E2697A high-impedance converter with 10:1 passive probes, or 1156A active probes.
- 2 Attach the passive probes to the oscilloscope's Channel 3 and Channel 2 inputs.
- 3 Attach the SQiDD board to the root hub on the host under test.
- 4 Attach a low speed device to the same section of the SQiDD board. If the section has a switch, it should be set to ON.
- 5 Connect the oscilloscope Channel 2 probe to D- probe point on the SQiDD board. Connect the oscilloscope Channel 3 probe to the D+ probe point on the SQiDD board.
- 6 Exit the HS Electrical Test Tool if you have previously launched it.



- 7 Check **I have completed these instructions**.

### Running the Tests

- 1 Click **Run Tests**.

### Viewing Test Results

- 1 When the Testing Complete dialog appears, click **OK**.

The Results tab shows the test results.

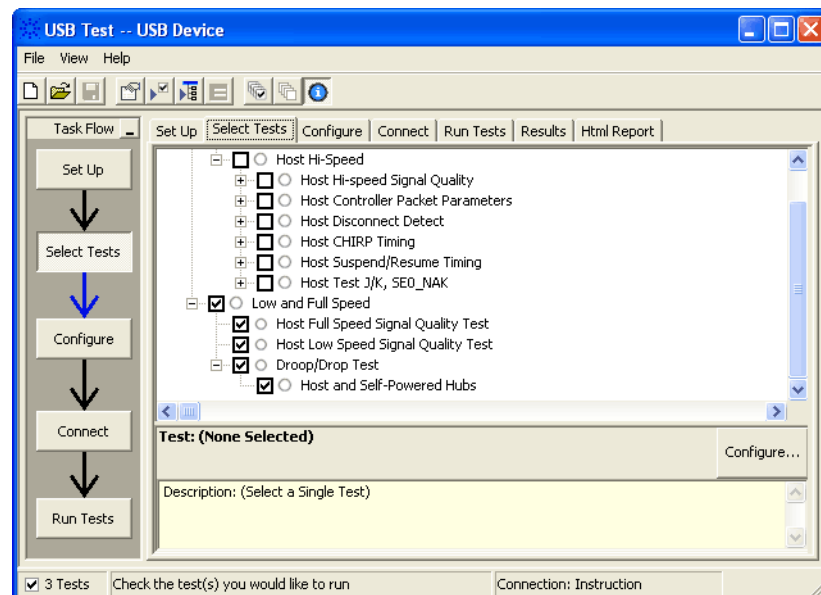
## Host Full Speed Test

### Equipment Used

**Table 35** Equipment Used in Host Downstream Full Speed Signal Quality Test

Quantity	Item	Description/Model
1	Oscilloscope	Agilent 5485xA Series, DS080000 Series, 54831B/D, or 54832B/D
2	Passive or active probes	For 5485x Series and DS080000 Series oscilloscopes: <ul style="list-style-type: none"> <li>• Agilent E2697A with 10073C, or 1156A</li> </ul> For 54831B/D and 54832B/D oscilloscopes: <ul style="list-style-type: none"> <li>• Agilent 1165A</li> </ul>
1	Host test bed computer	Any computer with hi-speed USB ports
1	SQiDD board	Agilent E2646A
1	full speed USB device	Intel Create and Share USB camera, P/N 735147-001, Model #: CS330
5	USB self-powered hubs	Any listed on USB-IF web site
6	5 meter USB cables	Any listed on USB-IF web site

### Selecting the Tests



**Configuring the Tests** Make sure you set the Test Type configuration option to “Full-Speed Far End” before running the test.

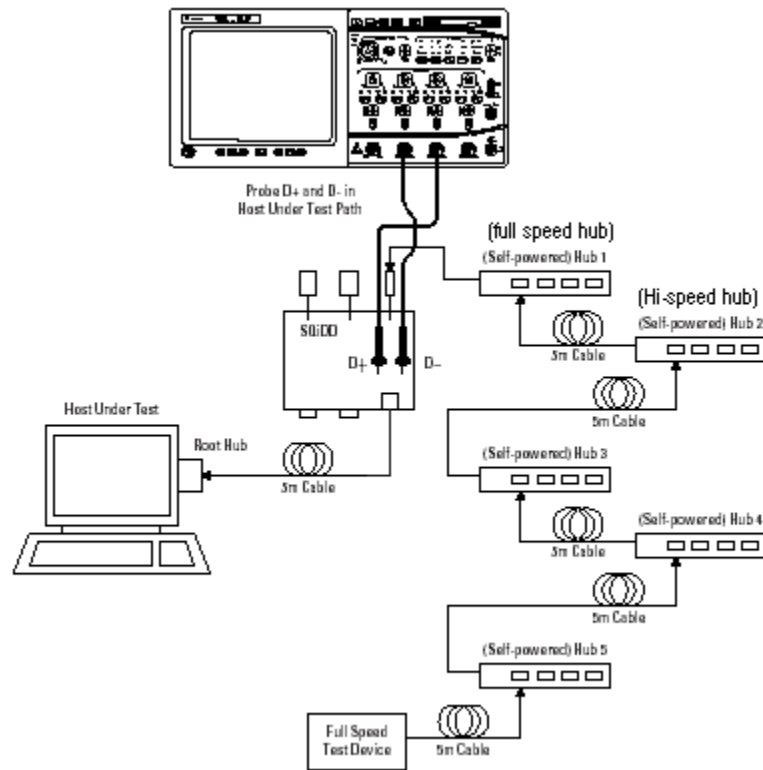
**Connecting the Equipment** The USB automated test application will prompt you to perform these connection steps:

- 1 For 54831B/D and 54832B/D oscilloscopes, use 1165A passive probes. For the 5485XA or DSO80000 series oscilloscopes, use E2697A high-impedance converter with 10:1 passive probes, or 1156A active probes.
- 2 Attach the passive probes to the oscilloscope's Channel 3 and Channel 2 inputs.
- 3 Attach the SQiDD board to the root hub on the host under test.
- 4 Attach 5 self-powered hubs and a full-speed device to the same section of the SQiDD board. If the section has a switch, it should be set to ON. Hub #1 has to be a full-speed hub and hub #2 a Hi-speed hub. The other hubs can be either full speed or hi-speed hubs.

### NOTE

Placing a full speed and/or a high-speed device downstream of a full speed hub forces both to operate in full speed mode.

- 
- 5 Connect the oscilloscope Channel 2 probe to D- probe point of the device under test portion. Connect the oscilloscope Channel 3 probe to the D+ probe point of the device under test portion.
  - 6 Exit the HS Electrical Test Tool is you have previously launched.



## 7 Check I have completed these instructions.

### Running the Tests

- 1 Click **Run Tests**.

### Viewing Test Results

- 1 When the Testing Complete dialog appears, click **OK**.

The Results tab shows the test results.

## Hub Downstream Signal Quality Test

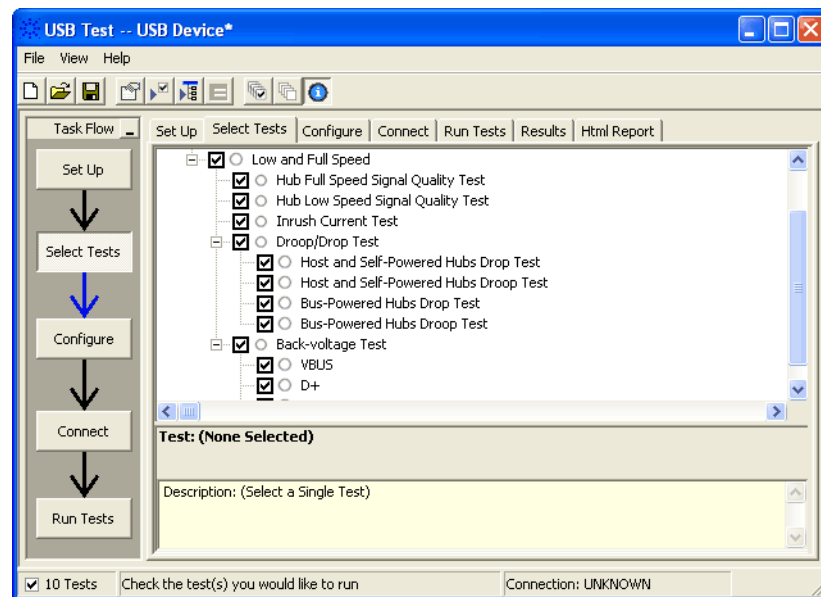
### Hub Low Speed Test

#### Equipment Used

**Table 36** Equipment Used in Hub Downstream Low Speed Signal Quality Test

Quantity	Item	Description/Model
1	Oscilloscope	Agilent 5485xA Series, DSO80000 Series, 54831B/D, or 54832B/D
2	Passive or active probes	For 5485x Series and DSO80000 Series oscilloscopes: <ul style="list-style-type: none"> <li>• Agilent E2697A with 10073C, or 1156A</li> </ul> For 54831B/D and 54832B/D oscilloscopes: <ul style="list-style-type: none"> <li>• Agilent 1165A</li> </ul>
1	Host test bed computer	Any computer with hi-speed USB ports
1	SQiDD board	Agilent E2646A
1	low speed USB device	Logitech mouse, P/N 830311-1000, Model #: M-BB48
5	USB self-powered hubs	Any listed on USB-IF web site
5	5 meter USB cables	Any listed on USB-IF web site

#### Selecting the Tests



**Configuring the Tests** Make sure you set the Test Type configuration option to “Low-Speed Near End” before running the test.

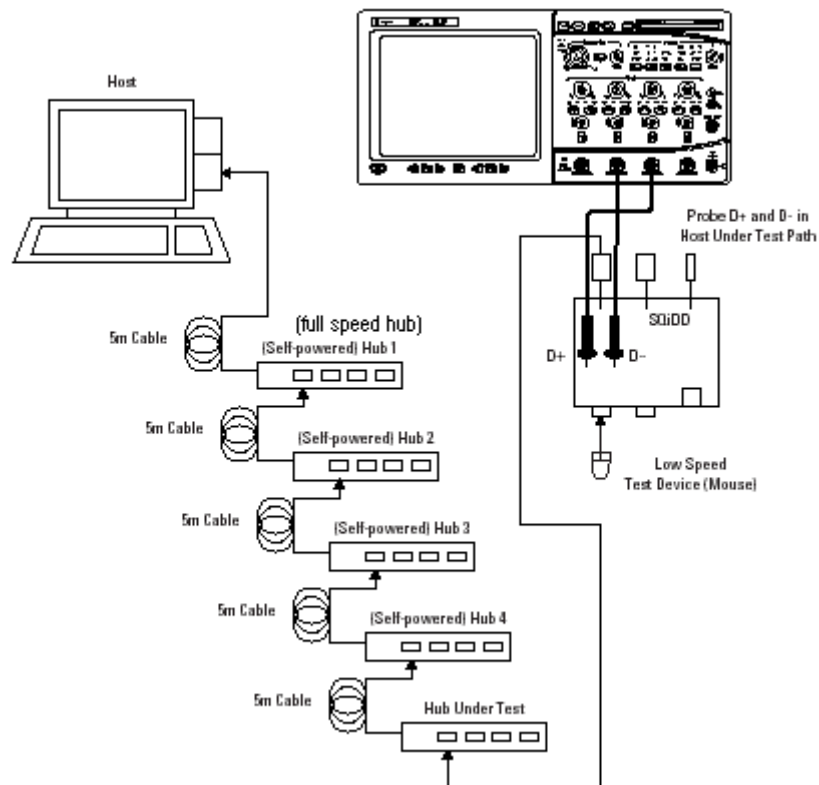
**Connecting the Equipment** The USB automated test application will prompt you to perform these connection steps:

- 1 For 54831B/D and 54832B/D oscilloscopes, use 1165A passive probes. For the 5485XA or DSO80000 series oscilloscopes, use E2697A high-impedance converter with 10:1 passive probes, or 1156A active probes.
- 2 Attach the passive probes to the oscilloscope's Channel 3 and Channel 2 inputs.
- 3 Attach the SQiDD board to the hub under test.
- 4 Attach the upstream port of the hub under test to the end of 4 self-powered hubs and a host system. Hub #1 has to be a full speed hub. The other hubs can be either full speed or hi-speed hubs.

**NOTE**

The best method to capture and analyze low-speed downstream signal quality is to capture both a keep-alive (low speed EOP) if present and a SOF packet. Hubs are required to generate keep-alives when there is full speed traffic and pass them on to low speed devices.

- 5 Attach a low speed device to the same section of the SQiDD board. If the section has a switch, it should be set to ON.
- 6 Connect the oscilloscope Channel 2 probe to D- probe point of the device under test portion. Connect the oscilloscope Channel 3 probe to the D+ probe point of the device under test portion.
- 7 Exit the HS Electrical Test Tool if you have previously launched it.



**8** Check I have completed these instructions.

### Running the Tests

**1** Click **Run Tests**.

### Viewing Test Results

**1** When the Testing Complete dialog appears, click **OK**.

The Results tab shows the test results.



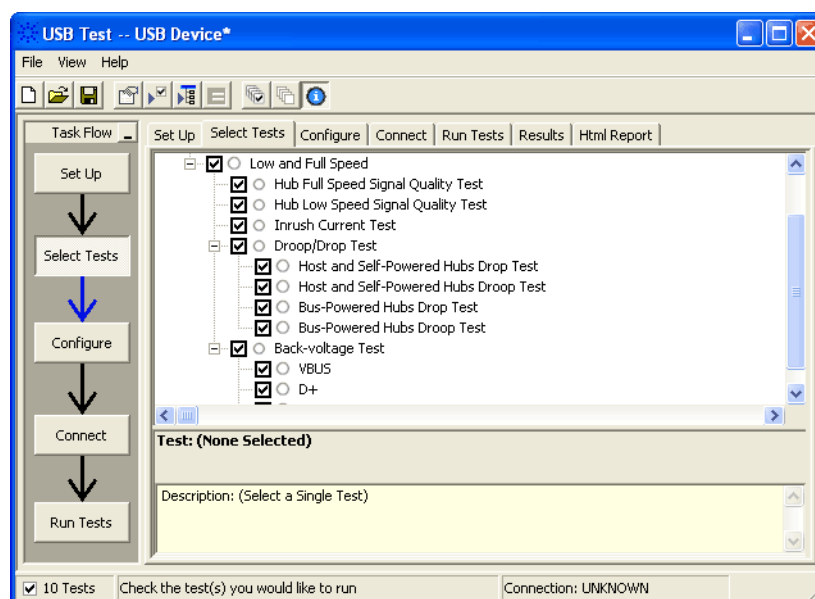
## Hub Full Speed Test

### Equipment Used

**Table 37** Equipment Used in Hub Downstream Full Speed Signal Quality Test

Quantity	Item	Description/Model
1	Oscilloscope	Agilent 5485xA Series, DS080000 Series, 54831B/D, or 54832B/D
2	Passive or active probes	For 5485x Series and DS080000 Series oscilloscopes: <ul style="list-style-type: none"> <li>• Agilent E2697A with 10073C, or 1156A</li> </ul> For 54831B/D and 54832B/D oscilloscopes: <ul style="list-style-type: none"> <li>• Agilent 1165A</li> </ul>
1	Host test bed computer	Any computer with hi-speed USB ports
1	SQiDD board	Agilent E2646A
1	full speed USB device	Intel Create and Share USB camera, P/N 735147-001, Model #: CS330
5	USB self-powered hubs	Any listed on USB-IF web site
6	5 meter USB cables	Any listed on USB-IF web site

### Selecting the Tests



**Configuring the Tests** Make sure you set the Test Type configuration option to “Full-Speed Far End” before running the test.

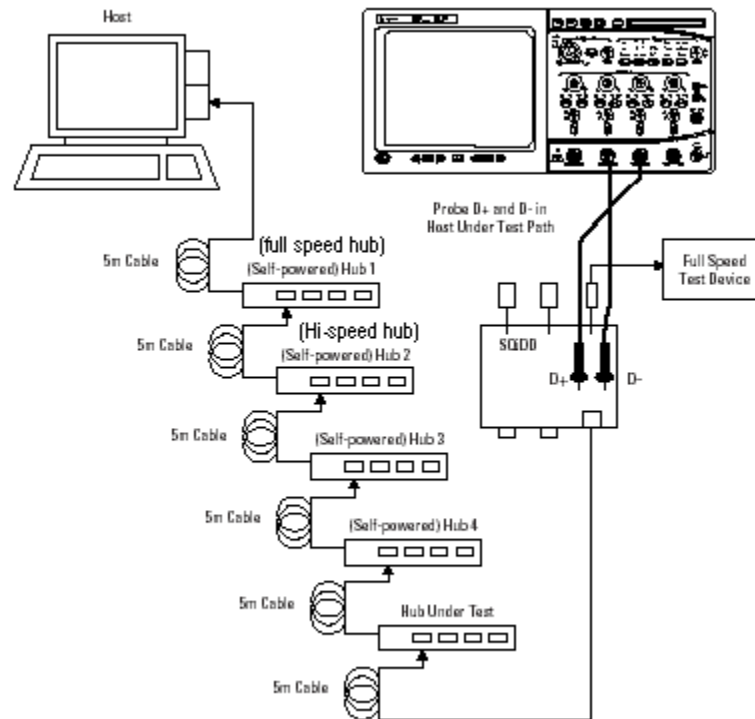
**Connecting the Equipment** The USB automated test application will prompt you to perform these connection steps:

- 1 For 54831B/D and 54832B/D oscilloscopes, use 1165A passive probes. For the 5485XA or DSO80000 series oscilloscopes, use E2697A high-impedance converter with 10:1 passive probes, or 1156A active probes.
- 2 Attach the passive probes to the oscilloscope's Channel 3 and Channel 2 inputs.
- 3 Attach the SQiDD board to the hub under test.
- 4 Attach the upstream port of the hub under test to the end of 4 self-powered hubs and a host system. Hub #1 has to be a full-speed hub and hub #2 a Hi-speed hub. The other hubs can be either full speed or hi-speed hubs.

### NOTE

Placing a full speed and/or a high-speed device downstream of a full speed hub forces both to operate in full speed mode.

- 
- 5 Attach a full speed device to the same section of the SQiDD board. If the section has a switch, it should be set to ON.
  - 6 Connect the oscilloscope Channel 2 probe to D- probe point of the device under test portion. Connect the oscilloscope channel Channel 3 probe to the D+ probe point of the device under test portion.
  - 7 Exit the HS Electrical Test Tool if you have previously launched it.



**8** Check I have completed these instructions.

### Running the Tests

**1** Click **Run Tests**.

### Viewing Test Results

**1** When the Testing Complete dialog appears, click **OK**.

The Results tab shows the test results.

## Upstream Signal Quality Test

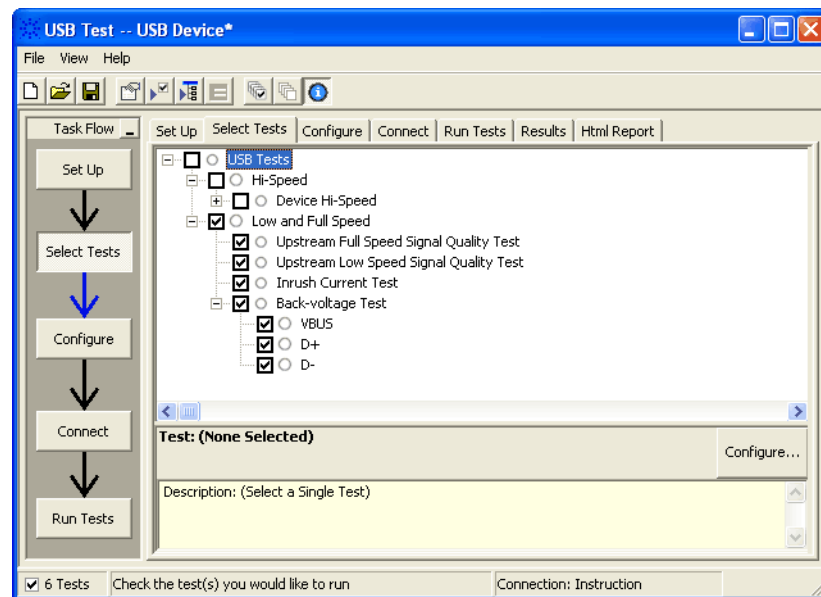
### Upstream Low Speed Test

#### Equipment Used

**Table 38** Equipment Used in Upstream Low Speed Signal Quality Test

Quantity	Item	Description/Model
1	Oscilloscope	Agilent 5485xA Series, DS080000 Series, 54831B/D, or 54832B/D
3	Passive or active probes	For 5485x Series and DS080000 Series oscilloscopes: <ul style="list-style-type: none"> <li>• Agilent E2697A with 10073C, or 1156A</li> </ul> For 54831B/D and 54832B/D oscilloscopes: <ul style="list-style-type: none"> <li>• Agilent 1165A</li> </ul>
1	Host test bed computer	Any computer with hi-speed USB ports
1	SQiDD board	Agilent E2646A
1	low speed USB device	Logitech mouse, P/N 830311-1000, Model #: M-BB48
5	USB self-powered hubs	Any listed on USB-IF web site
6	5 meter USB cables	Any listed on USB-IF web site

#### Selecting the Tests



**Configuring the Tests** Make sure you set the Test Type configuration option to “Low-Speed Far End” before running the test.

**Connecting the Equipment** The USB automated test application will prompt you to perform these connection steps:

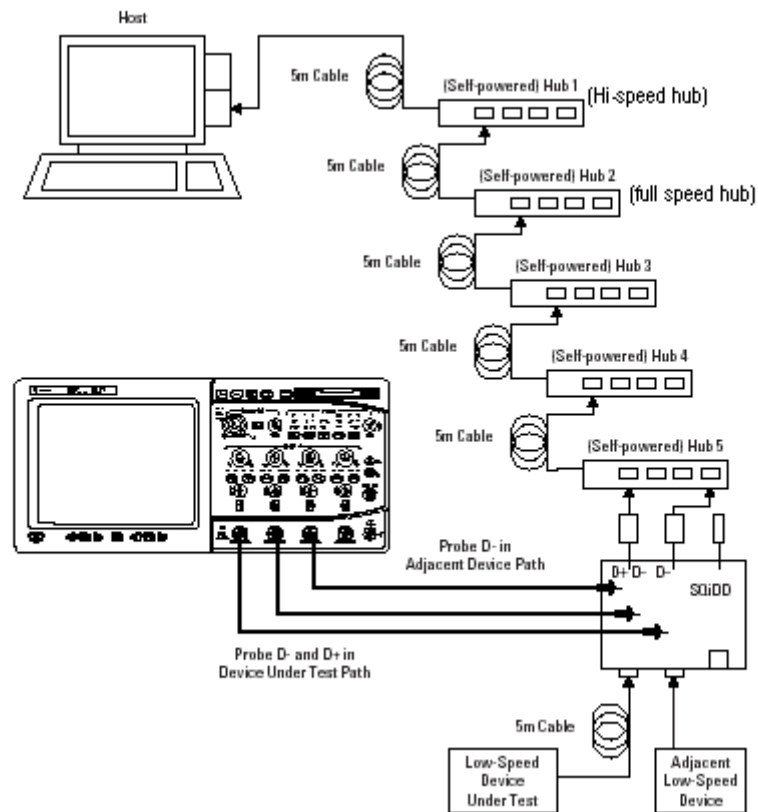
- 1 For 54831B/D and 54832B/D oscilloscopes, use 1165A passive probes. For the 5485XA or DSO80000 series oscilloscopes, use E2697A high-impedance converter with 10:1 passive probes, or 1156A active probes.
- 2 Attach the passive probes to the oscilloscope's Channel 2, Channel 3 and Channel 1 inputs.
- 3 Attach the SQiDD board to two USB ports at the end of 5 self-powered hubs and a host system. Hub #1 has to be a hi-speed hub and hub #2 has to be a full speed hub. The rest of the hubs can be either hi-speed or full speed hubs.

**NOTE**

Placing a full speed and/or a high-speed device downstream of a full speed hub forces both to operate in full speed mode.

- 4 Attach a low speed device under test to the same section of the SQiDD board. If the section has a switch, it should be set to ON.
- 5 Attach another low speed device to the adjacent section of the SQiDD board. This is for triggering purposes.
- 6 Connect the oscilloscope Channel 2 probe to D- probe point of the device under test portion. Connect the oscilloscope Channel 3 probe to the D+ probe point of the device under test portion. Connect the oscilloscope Channel 1 probe to the D- probe point on the adjacent device section of the SQiDD board.

## 7 Low and Full Speed Tests



**7** Check I have completed these instructions.

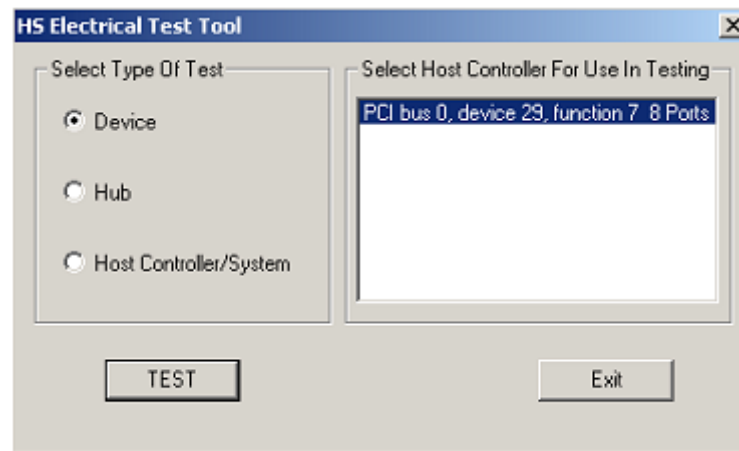
### Running the Tests

**1** Click **Run Tests**.

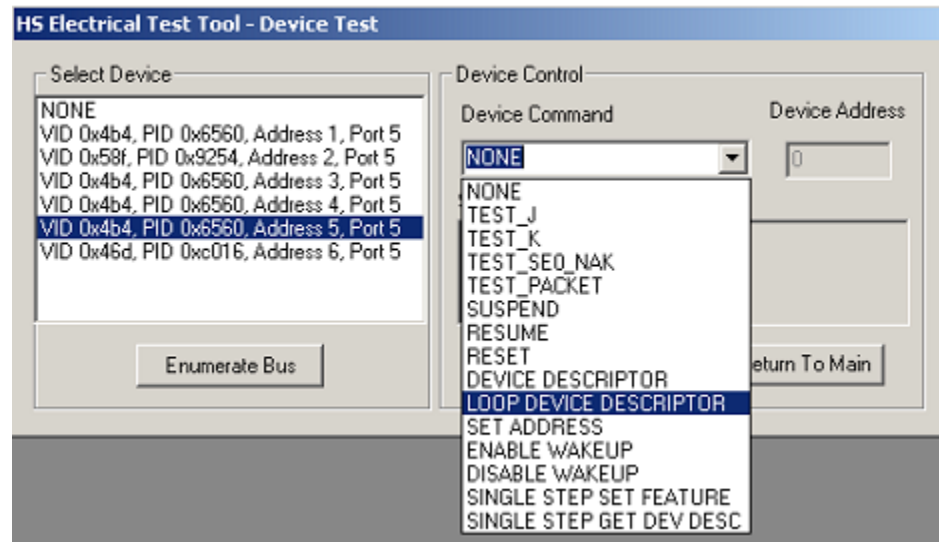
### Test Instructions

The USB automated test application will prompt you to perform these steps:

- 1 Invoke the HS Electrical Test Tool software on the Hi-Speed Electrical Test Bed computer. Select **Device** and click the **[TEST]** button to enter the Device Test menu.



- 2 On the Device Test Menu of the HS Electrical Test Tool software, click **[Enumerate Bus]** once. All devices attached to the host controller should appear in the device enumeration list.
- 3 Highlight the device under test and select **LOOP DEVICE DESCRIPTOR** from the Device Command drop down menu. Click **EXECUTE** once.
- 4 If you do not know which VID/PID belongs to the device under test, unattach the device under test and enumerate the bus once. Then reattach the device under test and enumerate again, this time paying attention to the new device attached.



- 5 Click **OK** to close the Test Instructions dialog.

### Viewing Test Results

- 1 When the Testing Complete dialog appears, click **OK**.

The Results tab shows the test results.



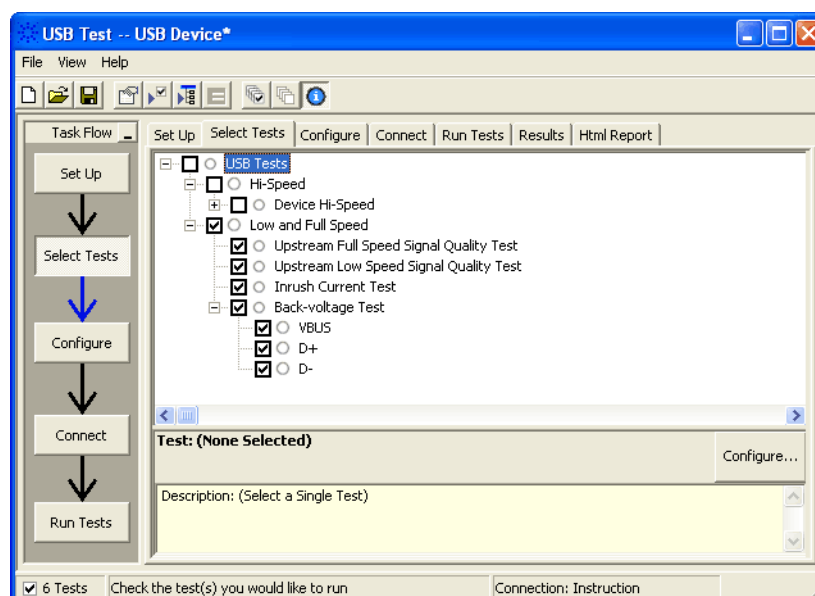
## Upstream Full Speed Test

### Equipment Used

**Table 39** Equipment Used in Upstream Full Speed Signal Quality Test

Quantity	Item	Description/Model
1	Oscilloscope	Agilent 5485xA Series, DS080000 Series, 54831B/D, or 54832B/D
3	Passive or active probes	For 5485x Series and DS080000 Series oscilloscopes: <ul style="list-style-type: none"> <li>• Agilent E2697A with 10073C, or 1156A</li> </ul> For 54831B/D and 54832B/D oscilloscopes: <ul style="list-style-type: none"> <li>• Agilent 1165A</li> </ul>
1	Host test bed computer	Any computer with hi-speed USB ports
1	SQiDD board	Agilent E2646A
1	full speed USB device	Intel Create and Share USB camera, P/N 735147-001, Model #: CS330
5	USB self-powered hubs	Any listed on USB-IF web site
6	5 meter USB cables	Any listed on USB-IF web site

### Selecting the Tests



**Configuring the Tests** Make sure you set the Test Type configuration option to “Full-Speed Far End” before running the test.

**Connecting the Equipment** The USB automated test application will prompt you to perform these connection steps:

- 1 For 54831B/D and 54832B/D oscilloscopes, use 1165A passive probes. For the 5485XA or DSO80000 series oscilloscopes, use E2697A high-impedance converter with 10:1 passive probes, or 1156A active probes.
- 2 Attach the passive probes to the oscilloscope's channel Channel 2, Channel 3 and Channel 1 inputs.
- 3 Attach the SQiDD board to two USB ports at the end of 5 self-powered hubs and a host system. Hub #1 has to be a hi-speed hub and hub #2 has to be a full speed hub. The rest of the hubs can be either hi-speed or full speed hubs.

### NOTE

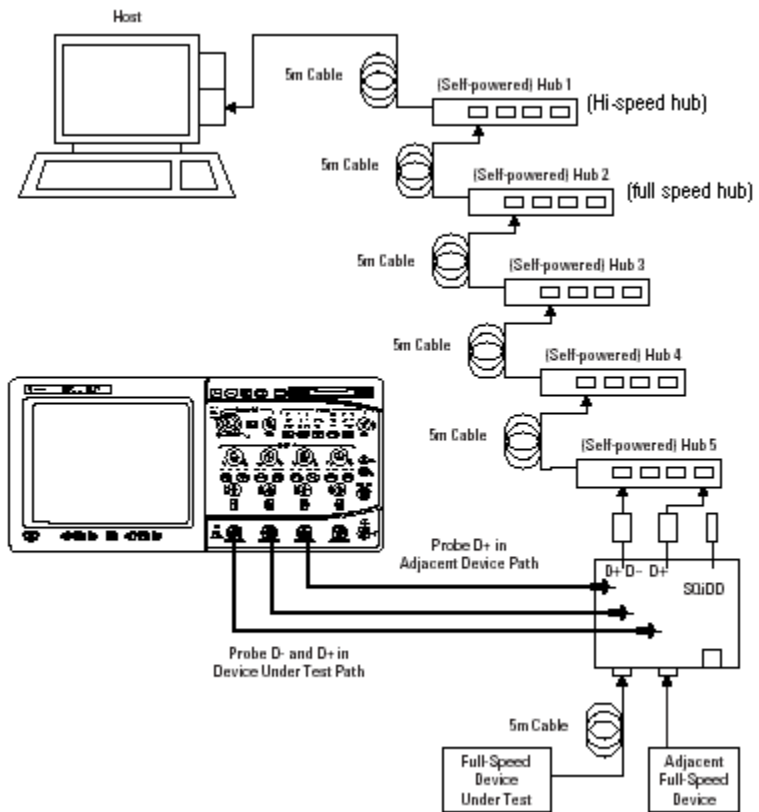
Placing a full speed and/or a high-speed device downstream of a full speed hub forces both to operate in full speed mode.

- 4 Attach a full speed device under test to the same section of the SQiDD board. If the section has a switch, it should be set to ON.
- 5 Attach another full speed device to the adjacent section of the SQiDD board. This is for triggering purposes.

### NOTE

Use a full-speed hub if device under test has embedded hub function. Otherwise the scope will falsely trigger.

- 6 Connect the oscilloscope Channel 2 probe to D- probe point of the device under test portion. Connect the oscilloscope Channel 3 probe to the D+ probe point of the device under test portion. Connect the oscilloscope Channel 1 probe to the D+ probe point on the adjacent device section of the SQiDD board.



7 Check I have completed these instructions.

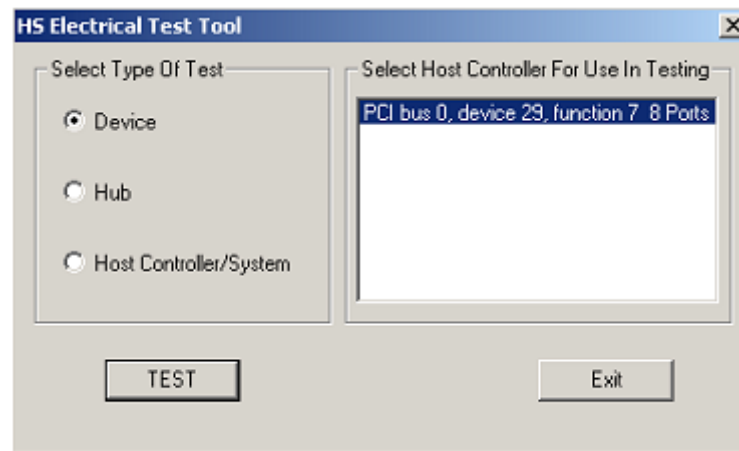
### Running the Tests

1 Click **Run Tests**.

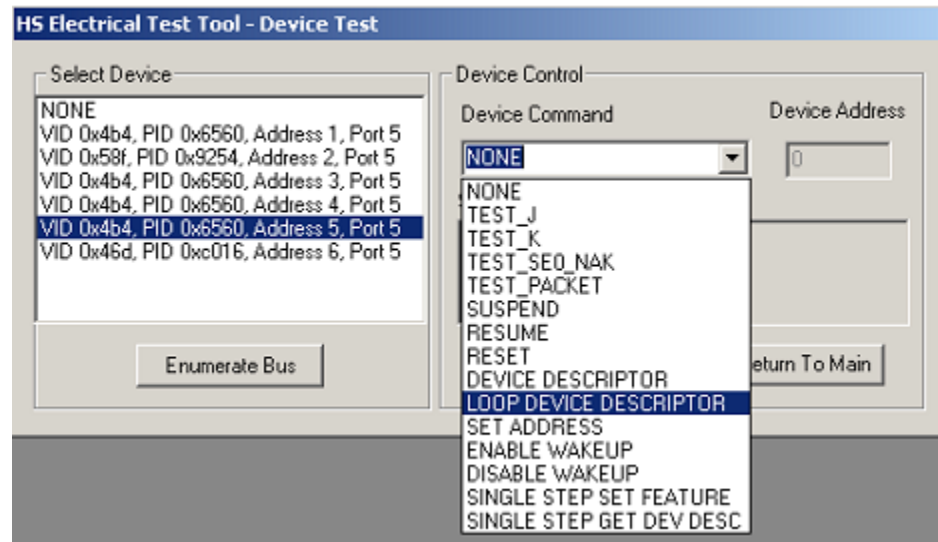
### Test Instructions

The USB automated test application will prompt you to perform these steps:

- 1 Invoke the HS Electrical Test Tool software on the Hi-Speed Electrical Test Bed computer. Select **Device** and click the **[TEST]** button to enter the Device Test menu.



- 2 On the Device Test Menu of the HS Electrical Test Tool software, click **[Enumerate Bus]** once. All devices attached to the host controller should appear in the device enumeration list.
- 3 Highlight the device under test and select **LOOP DEVICE DESCRIPTOR** from the Device Command drop down menu. Click **EXECUTE** once.
- 4 If you do not know which VID/PID belongs to the device under test, unattach the device under test and enumerate the bus once. Then reattach the device under test and enumerate again, this time paying attention to the new device attached.



- 5 Click **OK** to close the Test Instructions dialog.

### Viewing Test Results

- 1 When the Testing Complete dialog appears, click **OK**.

The Results tab shows the test results.

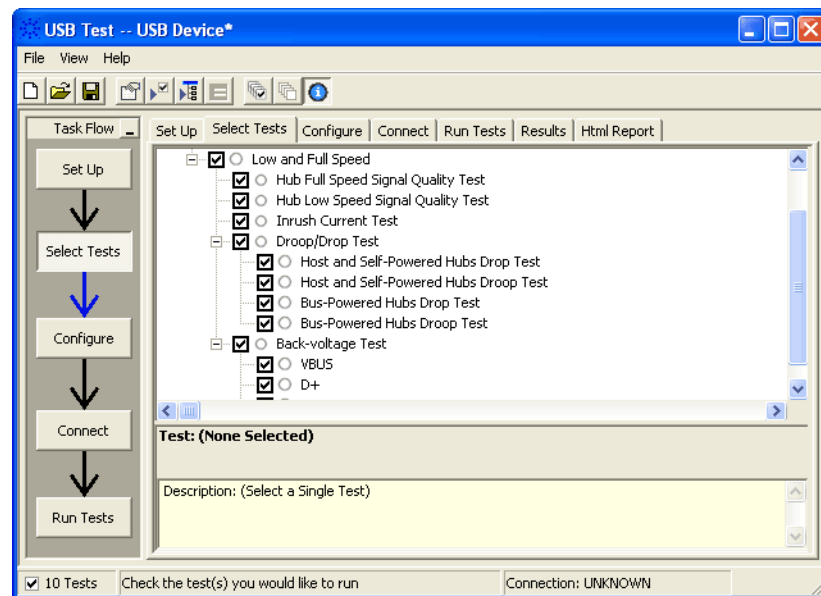
## Back-Voltage Test

### Equipment Used

**Table 40** Equipment Used in Back-Voltage Test

Quantity	Item	Description/Model
1	Digital Multimeter (DMM)	Agilent 34401A or equivalent
1	SQiDD board or back-voltage test fixture	Agilent E2646A
1	1 meter USB cable	Any listed on USB-IF web site

### Selecting the Tests



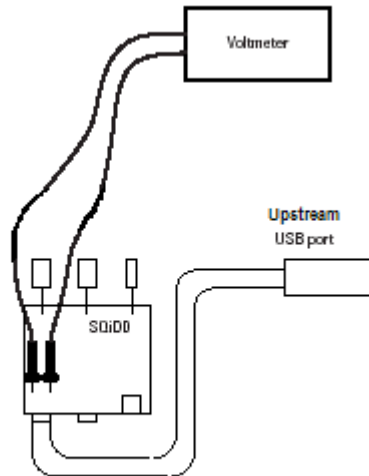
### Configuring the Tests

### Connecting the Equipment

The USB automated test application will prompt you to perform these connection steps:

- 1 Connect power supply to device/hub under test. Plug device/hub under test into a known good host. Verify proper enumeration. Unplug USB cable from

the host. Connect the device/hub upstream port to the SQiDD board using a known good USB cable.



- 2 Check I have completed these instructions.

## Running the Tests

- 1 Click **Run Tests**.

## Test Instructions

### VBUS

The USB automated test application will prompt you to: measure the voltage between Vbus and Gnd on the SQiDD board and record the value.

### D+

The USB automated test application will prompt you to: measure the voltage between D+ and Gnd on the SQiDD board and record the value.

### D-

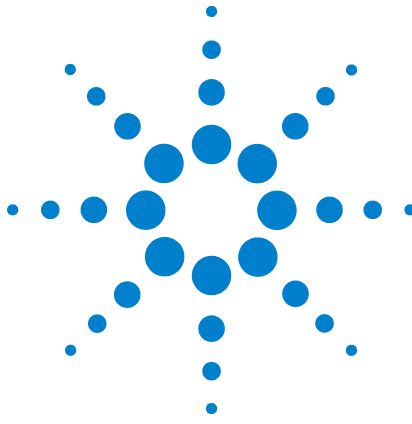
The USB automated test application will prompt you to: measure the voltage between D- and Gnd on the SQiDD board and record the value.

## **Viewing Test Results**

- 1 When the Testing Complete dialog appears, click **OK**.

The Results tab shows the test results.





## 8 On-The-Go Electrical Tests

Equipment Used	202
Selecting the Tests	202
Configuring the Tests	203
Connecting the Equipment	203
Running the Tests	204
Viewing Test Results	204

All of the On-The-Go electrical tests use the same test setup.

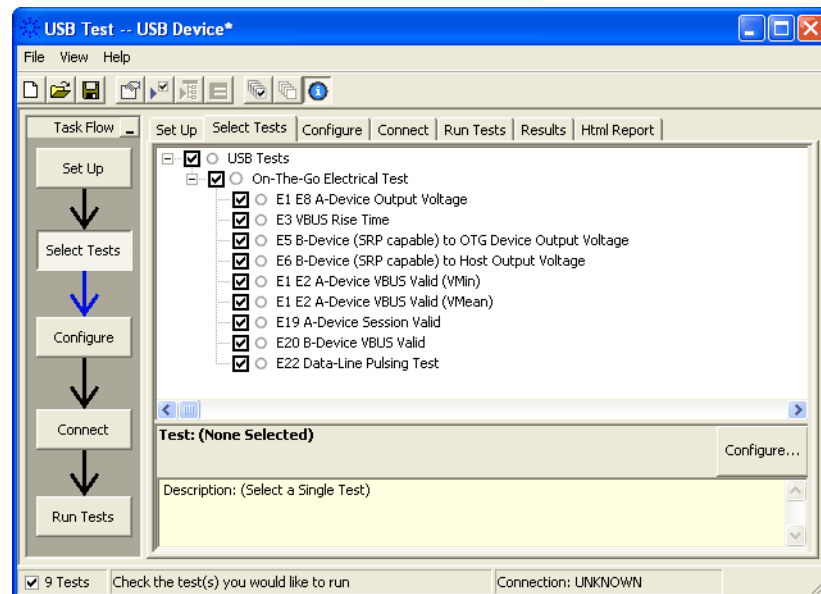


## Equipment Used

**Table 41** Equipment Used in On-The-Go Electrical Tests

Quantity	Item	Description/Model
1	Oscilloscope	Agilent 5485xA Series, DS080000 Series, 54831B/D, or 54832B/D
2	Passive or active probes	For 5485x Series and DS080000 Series oscilloscopes: • Agilent 1156A For 54831B/D and 54832B/D oscilloscopes: • Agilent 1165A
1	Digital Multimeter (DMM)	Agilent 34401A or equivalent
1	USB OTG test fixture	Agilent N5417A
1	Power supply	Agilent E3631A or equivalent
1	USB/GPIB interface	Agilent 82357A
1	GPIB cable	Agilent 10833B

## Selecting the Tests



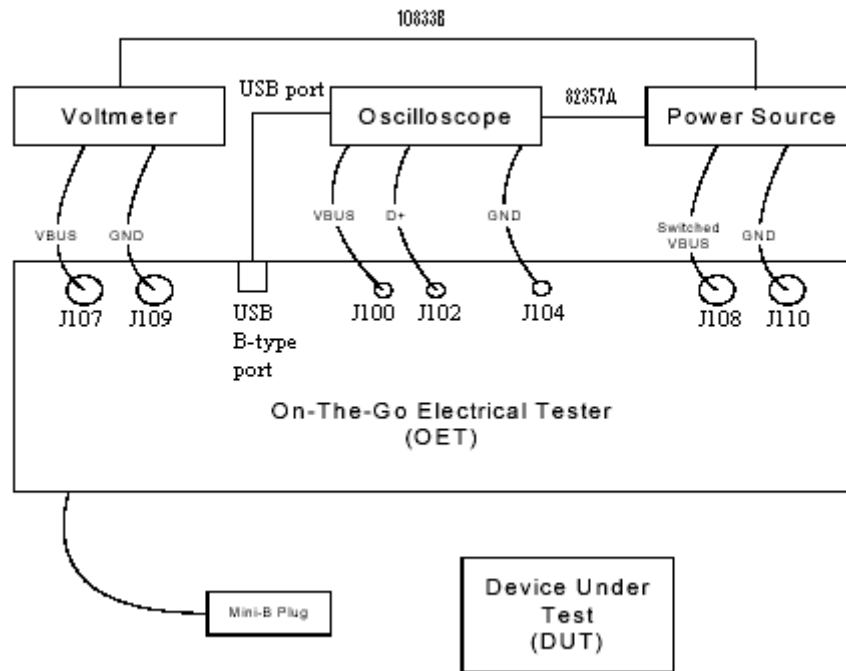
## Configuring the Tests

If the power supply's SICL address is different from the default, make sure you set the 83631A Instrument Address configuration option to the power supply's SICL address.

## Connecting the Equipment

The USB automated test application will prompt you to perform these connection steps:

- 1 Connect the Channel 1 probe of the oscilloscope to the J100, VBUS test point of the OET. Connect the probe's ground to the J104, GND test point nearest to the VBUS test point.
- 2 Connect the Channel 3 probe of the oscilloscope to the J102, D+ test point of the OET. Connect the probe's ground to the J105, GND test point nearest to the D+ test point.
- 3 Connect the black multimeter lead from INPUT LOW to J109, GND terminal, of the OET.
- 4 Connect the red multimeter lead from INPUT HI to J107, VBUS terminal, of the OET.
- 5 Connect the black supply lead from the power supply 6 volt supply negative output to J110, GND terminal, of the OET.
- 6 Connect the red power supply lead from the power supply 6 volt supply positive output to J108, Switched VBUS terminal, of the OET.
- 7 Connect the 34401A digital multi-meter to E3631A power supply using the 10833B GPIB cable.
- 8 Connect the E3631A power supply to the oscilloscope using the 82357A USB/GPIB Interface.
- 9 Connect the OET test fixture to the oscilloscope's USB port .



- 10 Check I have completed these instructions.

## Running the Tests

- 1 Click **Run Tests**.

## Viewing Test Results

- 1 When the Testing Complete dialog appears, click **OK**.  
The Results tab shows the test results.

# Index

## Numerics

100 mA load board schematic, 165  
10073C miniature passive probes, 19  
1156A probes, 19  
500 mA load board schematic, 165  
81134A pulse generator, 89  
81134A/81130A Instrument Address  
configuration option, 57, 89  
82357A GPIB-USB converter, 89  
82357A USB/GPIB interface, 17  
83631A Instrument Address configuration  
option, 203

## C

cables, 18  
calibrate probes, 20  
calibration, 19  
common ground reference, 20  
compensate passive probes, 20  
computer, high-speed electrical test bed, 18  
configure, 22  
connect, 22

## D

Data Eye Test Mode configuration option, 163  
debug mode, 163  
device CHIRP timing, 39  
device hi-speed signal quality test, 27  
device hi-speed tests, 25  
device packet parameters, 32  
device receiver sensitivity, 56  
device suspend/resume/reset timing, 42  
device test J/K, SEO\_NAK, 50  
differential probe, 19  
digital signal generator, 17, 20  
droop/drop test, 167

## E

E2688A serial data analysis (SDA) and clock  
recovery software option, 163  
E2697A adapters, 19  
EHCI driver stack, 18  
electrical test bed computer, 18  
enhanced bandwidth software option, 16, 25,  
63, 131  
entitlement certificate, 14  
equipment required, 16  
equipment, setting up, 19

## G

ground reference, common, 20

## H

high-speed electrical test bed computer, 18  
High-Speed Electrical Test Tool Kit software, 18  
host CHIRP timing, 148  
host controller packet parameters, 137  
host disconnect detect, 144  
host downstream signal quality test, 177  
host hi-speed electrical tests, 131  
host hi-speed signal quality, 133  
host suspend/resume timing, 152  
host test J/K, SEO\_NAK, 157  
HTML report, 22  
hub CHIRP timing - upstream facing port, 108  
hub disconnect detect, 77  
hub downstream signal quality test, 182  
hub hi-speed signal quality test - downstream  
facing ports, 69  
hub hi-speed signal quality test - upstream  
facing ports, 65  
hub hi-speed tests, 63  
hub jitter test - downstream facing ports, 73  
hub packet parameters - upstream facing  
port, 81  
hub receiver sensitivity - upstream facing  
port, 88  
hub repeater test - downstream facing port, 97  
hub repeater test - upstream facing port, 102  
hub suspend/resume/reset timing - upstream  
facing port, 111  
hub test J/K, SEO\_NAK - downstream facing  
port, 124  
hub test J/K, SEO\_NAK - upstream facing  
port, 119

## I

identify test environment, 21  
in this book, 4  
inrush current test, 174  
installing the license key, 14  
installing the software, 13

## L

license code, 14  
license key, installing, 14  
load board, 17

## M

Marker Placement configuration option, 163  
Mask Template configuration option, 163  
MATLAB scripts, 163  
memory upgrade option, 16, 25, 63, 131  
monitor, optional, 19  
multimeter, 16

## N

N5416A USB 2.0 Compliance Test Option, 3,  
16  
noise reduction software option, 16, 25, 63,  
131

## O

On-The-Go electrical tests, 201  
optional computer monitor, 19  
oscilloscope required, 16  
oscilloscope, software, and accessories, 16

## P

passive probes, compensating, 20  
power supply's SICL address, 203  
probes, calibrating, 20  
pulse generator's SICL address, 57, 89  
pulse/pattern generator, 17

## R

report, 22  
required equipment and software, 16  
results, 22  
run tests, 22  
running tests, 23

## S

select tests, 22  
SICL address, power supply, 203  
SICL address, pulse generator, 57, 89  
software, installing, 13  
SQiDD board, 17  
starting the USB automated test application, 21

## T

test bed computer, high-speed electrical, 18

## Index

test fixtures, USB electrical, [17](#)  
Test Type configuration option, [177](#), [179](#), [182](#),  
[185](#), [188](#), [193](#)  
tests, running, [23](#)  
troubleshooting hi-speed test failures, [163](#)

## U

upstream signal quality test, [188](#)  
USB automated testing—at a glance, [3](#)  
USB electrical test fixtures, [17](#)  
USB Implementers Forum web site, [4](#)  
USBHSET software, [18](#)

## W

web site, USB Implementers Forum, [4](#)



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